



Radiation Lot Acceptance Testing (RLAT) of the RH6200MW Low Noise Rail-to-Rail Input and Output Op Amp for Linear Technology

Customer: Linear Technology, PO# 7128F

RAD Job Number: 10-494

Part Type Tested: RH6200MW Low Noise Rail-to-Rail Input and Output Op Amp.

Traceability Information/Lot Number/ Date Code: Lot Number: WD004518.3, Wafer Number: 9. See photograph of unit under test in Appendix A.

Quantity of Units: 12 units received, 5 units for biased irradiation, 5 units for unbiased irradiation and 2 units for control. Serial numbers 61-65 were biased during irradiation, serial numbers 66-70 were unbiased during irradiation and serial numbers 71 and 72 were used as control. See Appendix B for the radiation bias connection table.

Radiation and Electrical Test Increments: 50rad(Si)/s ionizing radiation with electrical test increments: pre-irradiation, 10krad(Si), 20krad(Si), 50krad(Si), 100krad(Si) and 200krad(Si).

Pre-Irradiation Burn-In: Burn-In performed by linear Technology prior to receipt by RAD.

Overtest and Post-Irradiation Anneal: No overtest. No anneal.

Radiation Test Standard: MIL-STD 883 and/or MIL-STD-750 TM1019 (latest revision), Condition A.

Test Hardware and Software: LTS2020 Automated Tester, Entity ID TS03, Calibration Date: 04-28-10, Calibration Due 04-28-11. LTS2100 Family Board, Entity ID FB01. LTS0600 Test Fixture, Entity ID TF03. Test Program: RH6200.SRC

Facility and Radiation Source: Radiation Assured Devices' Longmire Laboratories, Colorado Springs, CO. Gamma rays provided by JLSA 81-24 Co60 source. Dosimetry performed by CaF₂ TLDs traceable to NIST. RAD's dosimetry has been audited by DSCC and RAD has been awarded Laboratory Suitability for MIL-STD-750 and MIL-STD-883 TM 1019.

Irradiation and Test Temperature: Room temperature controlled to 24°C ± 6°C per MIL-STD-883 and MIL-STD-750.

RLAT Result: PASSED. The units showed no significant degradation with total dose. All parameters remained within their datasheet specifications to the maximum dose level tested of 200krad(Si)



1.0. Overview and Background

It is well known that total dose ionizing radiation can cause parametric degradation and ultimately functional failure in electronic devices. The damage occurs via electron-hole pair production, transport and trapping in the dielectric and interface regions. In discrete devices the bulk of the damage is frequently manifested as a reduction in the gain and/or breakdown voltage of the device. The damage will usually anneal with time following the end of the radiation exposure. Due to this annealing, and to ensure a worst-case test condition MIL-STD-883 TM1019.8 calls out a dose rate of 50 to 300rad(Si)/s as Condition A and further specifies that the time from the end of an incremental radiation exposure and electrical testing shall be 1-hour or less and the total time from the end of one incremental irradiation to the beginning of the next incremental radiation step should be 2-hours or less. The work described in this report was performed to meet MIL-STD-883 TM1019.8 Condition A.

2.0. Radiation Test Apparatus

The total ionizing dose testing described in this final report was performed using the facilities at Radiation Assured Devices' Longmire Laboratories in Colorado Springs, CO. The high dose rate total ionizing dose (TID) source is a JLSA 81-24 irradiator modified to provide a panoramic exposure. The Co-60 rods are held in the base of the irradiator heavily shielded by lead. During the radiation exposures the rod is raised by an electronic timer/controller and the exposure is performed in air. The dose rate for this irradiator in this configuration ranges from <1rad(Si)/s to a maximum of approximately 120rad(Si)/s, determined by the distance from the source. For high-dose rate experiments the bias boards are placed in a radial fashion equidistant from the raised Co-60 rods with the distance adjusted to provide the required dose rate. The irradiator calibration is maintained by Radiation Assured Devices Longmire Laboratories using air ionization chamber (AIC) equipment calibrated with traceability to the National Institute of Standards and Technology (NIST). Figure 2.1 shows a photograph of the JLSA 81-24 Co-60 irradiator at RAD's Longmire Laboratory facility.

RAD is currently certified by the Defense Supply Center Columbus (DSCC) for Laboratory Suitability under MIL STD 750 and MIL-STD-883. Additional details regarding Radiation Assured Devices dosimetry for TM1019 Condition A testing are available in RAD's report to DSCC entitled: "Dose Rate Mapping of the J.L. Shepherd and Associates Model 81 Irradiator Installed by Radiation Assured Devices".



Figure 2.1. Radiation Assured Devices' high dose rate Co-60 irradiator. The dose rate is obtained by positioning the device-under-test at a fixed distance from the gamma cell. The dose rate for this irradiator varies from approximately 120rad(Si)/s close to the rods down to 1rad(Si)/s at a distance of approximately 2-feet.



3.0. Radiation Test Conditions

The RH6200 Low Noise Rail-to-Rail Input and Output Op Amp described in this final report was irradiated using a split 5V supply and with all pins tied to ground, that is biased and unbiased. See the TID Bias Table in Appendix B for the full bias circuits. In our opinion, this bias circuit satisfies the requirements of MIL-STD-883H TM1019.8 Section 3.9.3 Bias and Loading Conditions which states "The bias applied to the test devices shall be selected to produce the greatest radiation induced damage or the worst-case damage for the intended application, if known. While maximum voltage is often worst case some bipolar linear device parameters (e.g. input bias current or maximum output load current) exhibit more degradation with 0 V bias."

The devices were irradiated to a maximum total ionizing dose level of 200krad(Si) with incremental readings at 10krad(Si), 20krad(Si), 50krad(Si) and 100krad(Si). Electrical testing occurred within one hour following the end of each irradiation segment. For intermediate irradiations, the parts were tested and returned to total dose exposure within two hours from the end of the previous radiation increment.

The TID bias board was positioned in the Co-60 cell to provide the required minimum of 50rad(Si)/s and was located inside a lead-aluminum enclosure. The lead-aluminum enclosure is required under MIL-STD-883H TM1019.8 Section 3.4 that reads as follows: "Lead/Aluminum (Pb/Al) container. Test specimens shall be enclosed in a Pb/Al container to minimize dose enhancement effects caused by low-energy, scattered radiation. A minimum of 1.5 mm Pb, surrounding an inner shield of at least 0.7 mm Al, is required. This Pb/Al container produces an approximate charged particle equilibrium for Si and for TLDs such as CaF₂. The radiation field intensity shall be measured inside the Pb/Al container (1) initially, (2) when the source is changed, or (3) when the orientation or configuration of the source, container, or test-fixture is changed. This measurement shall be performed by placing a dosimeter (e.g., a TLD) in the device-irradiation container at the approximate test-device position. If it can be demonstrated that low energy scattered radiation is small enough that it will not cause dosimetry errors due to dose enhancement, the Pb/Al container may be omitted."

The final dose rate within the high dose rate lead-aluminum enclosure was determined using calibration calculations based on air ionization chamber (AIC) dosimetry performed just prior to beginning the total dose irradiations. The final dose rate for this work was 52.81rad(Si)/s with a precision of $\pm 5\%$.



4.0. Tested Parameters

During the radiation lot acceptance testing the following pre- and post-irradiation electrical parameters were measured:

1. Positive Supply Current
2. Negative Supply Current
3. Disabled Supply Current
4. SHDN Pin Current
5. CMRR
6. PSRR
7. Large Signal Voltage Gain
8. Output Voltage Swing High
9. Output Voltage Swing Low
10. Positive Short-Circuit Current
11. Negative Short-Circuit Current
12. Input Offset Voltage
13. Input Offset Current
14. + Input Bias Current
15. – Input Bias Current

Appendix C details the measured parameters, test conditions, pre-irradiation specification and measurement resolution for each of the measurements.

The parametric data was obtained as "read and record" and all the raw data plus an attributes summary are contained in this report as well as in a separate Excel file. The attributes data contains the average, standard deviation and the average with the KTL values applied. The KTL value used in this work is 2.742 per MIL-HDBK-814 using one sided tolerance limits of 90/90 and a 5-piece sample size. The 90/90 KTL values were selected to match the statistical levels specified in the MIL-PRF-38535 sampling plan for the qualification of a radiation hardness assured (RHA) component. Note that the following criteria must be met for a device to pass the total ionizing dose test: following the radiation exposure each of the 5 pieces irradiated under electrical bias shall pass the specification value. The units irradiated without electrical bias and the KTL statistics are included in this report for reference only. If any of the 5 pieces irradiated under electrical bias exceed the datasheet specifications, then the lot could be logged as a failure.



5.0. Total Ionizing Dose Test Results

Based on this criterion the RH6200 Low Noise Rail-to-Rail Input and Output Op Amp (from the lot date code identified on the first page of this test report) showed no significant degradation and PASSED the total ionizing dose test to the maximum tested dose level of 200krad(Si) with all parameters remaining within their datasheet specifications.

Figures 5.1 through 5.49 show plots of all the measured parameters versus total ionizing dose while Tables 5.1 - 5.49 show the corresponding raw data for each of these parameters. In the data plots the solid diamonds are the average of the measured data points for the sample irradiated under electrical bias while the shaded diamonds are the average of the measured data points for the units irradiated with all pins tied to ground. The black lines (solid or dashed) are the average of the data points after application of the KTL statistics on the sample irradiated in the biased condition while the shaded lines (solid or dashed) are the average of the data points after application of the KTL statistics on the sample irradiated in the unbiased condition. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.

The control units, as expected, show no significant changes to any of the parameters. Therefore we can conclude that the electrical testing remained in control throughout the duration of the tests and the observed degradation was due to the radiation exposure. Appendix D lists the figures used in this section to facilitate the location of a particular parameter.

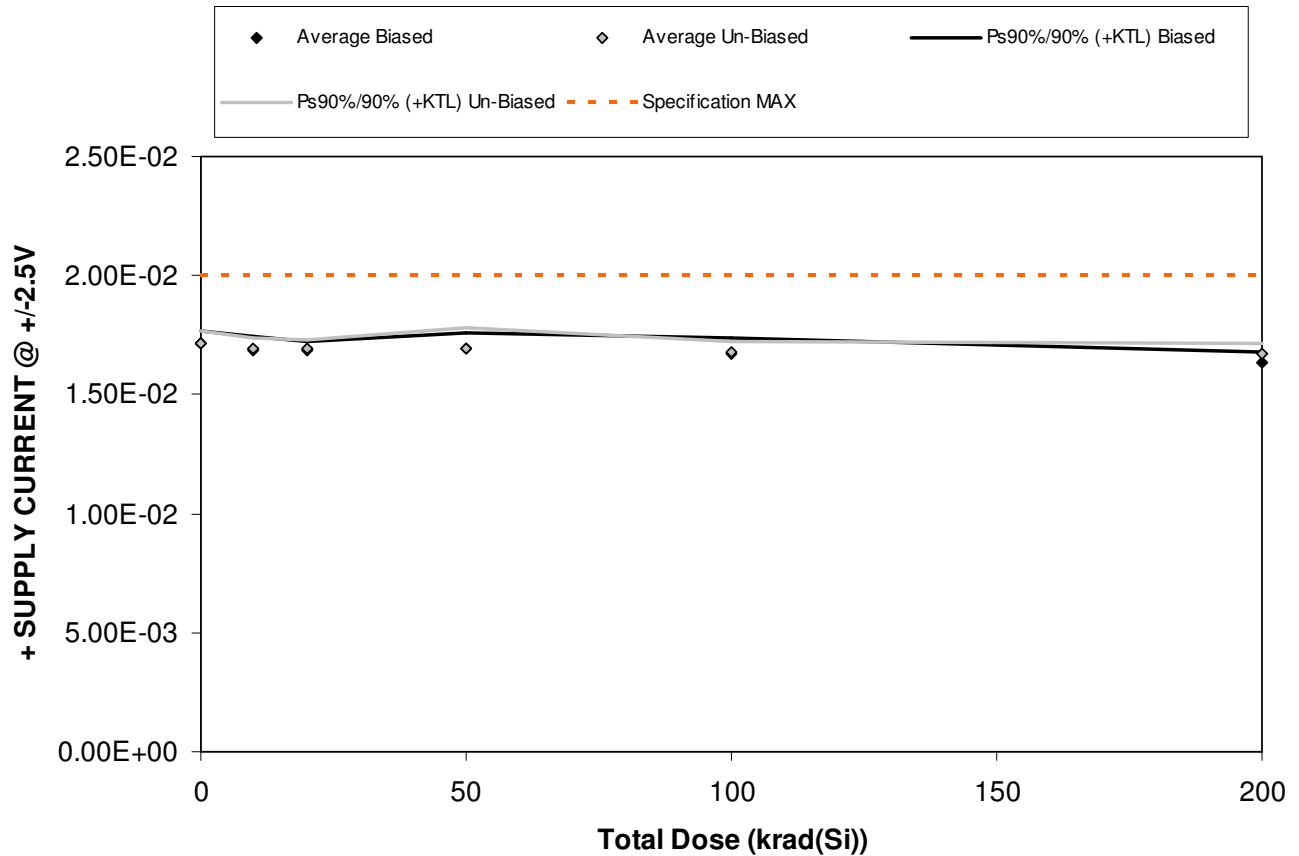


Figure 5.1. Plot of + SUPPLY CURRENT @ +/-2.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.1. Raw data for + SUPPLY CURRENT @ +/-2.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

+ SUPPLY CURRENT @ +/-2.5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.71E-02	1.71E-02	1.70E-02	1.72E-02	1.71E-02	1.66E-02
62	1.74E-02	1.70E-02	1.70E-02	1.71E-02	1.68E-02	1.64E-02
63	1.73E-02	1.68E-02	1.68E-02	1.69E-02	1.67E-02	1.64E-02
64	1.72E-02	1.69E-02	1.69E-02	1.69E-02	1.67E-02	1.63E-02
65	1.69E-02	1.66E-02	1.67E-02	1.66E-02	1.64E-02	1.61E-02
66	1.71E-02	1.69E-02	1.69E-02	1.68E-02	1.68E-02	1.68E-02
67	1.70E-02	1.68E-02	1.68E-02	1.67E-02	1.67E-02	1.66E-02
68	1.73E-02	1.71E-02	1.71E-02	1.75E-02	1.70E-02	1.69E-02
69	1.74E-02	1.71E-02	1.70E-02	1.70E-02	1.70E-02	1.69E-02
70	1.70E-02	1.68E-02	1.68E-02	1.68E-02	1.67E-02	1.66E-02
71	1.71E-02	1.68E-02	1.67E-02	1.68E-02	1.68E-02	1.68E-02
72	1.73E-02	1.70E-02	1.70E-02	1.69E-02	1.70E-02	1.71E-02
Biased Statistics						
Average Biased	1.72E-02	1.69E-02	1.69E-02	1.69E-02	1.67E-02	1.64E-02
Std Dev Biased	1.86E-04	2.02E-04	1.34E-04	2.53E-04	2.43E-04	1.70E-04
Ps90%/90% (+KTL) Biased	1.77E-02	1.74E-02	1.72E-02	1.76E-02	1.74E-02	1.68E-02
Ps90%/90% (-KTL) Biased	1.67E-02	1.63E-02	1.65E-02	1.62E-02	1.61E-02	1.59E-02
Un-Biased Statistics						
Average Un-Biased	1.72E-02	1.69E-02	1.69E-02	1.70E-02	1.68E-02	1.67E-02
Std Dev Un-Biased	1.77E-04	1.54E-04	1.43E-04	3.13E-04	1.37E-04	1.53E-04
Ps90%/90% (+KTL) Un-Biased	1.77E-02	1.73E-02	1.73E-02	1.78E-02	1.72E-02	1.72E-02
Ps90%/90% (-KTL) Un-Biased	1.67E-02	1.65E-02	1.65E-02	1.61E-02	1.64E-02	1.63E-02
Specification MAX	2.00E-02	2.00E-02	2.00E-02	2.00E-02	2.00E-02	2.00E-02
Status	PASS	PASS	PASS	PASS	PASS	PASS

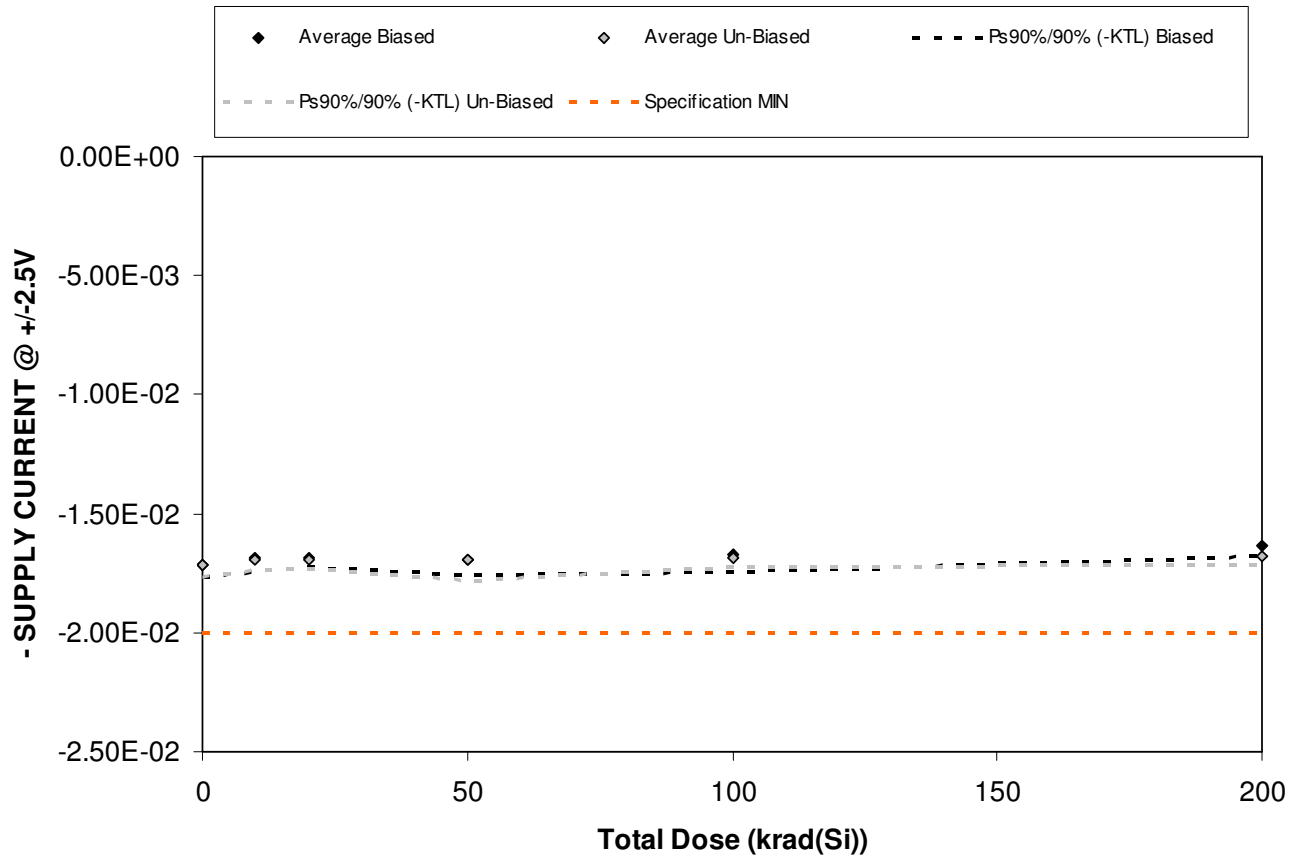


Figure 5.2. Plot of - SUPPLY CURRENT @ +/-2.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.2. Raw data for - SUPPLY CURRENT @ +/-2.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

- SUPPLY CURRENT @ +/-2.5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	-1.71E-02	-1.71E-02	-1.70E-02	-1.72E-02	-1.71E-02	-1.65E-02
62	-1.74E-02	-1.70E-02	-1.70E-02	-1.71E-02	-1.68E-02	-1.64E-02
63	-1.73E-02	-1.68E-02	-1.68E-02	-1.69E-02	-1.67E-02	-1.64E-02
64	-1.72E-02	-1.69E-02	-1.69E-02	-1.69E-02	-1.67E-02	-1.63E-02
65	-1.69E-02	-1.66E-02	-1.67E-02	-1.66E-02	-1.64E-02	-1.61E-02
66	-1.71E-02	-1.69E-02	-1.69E-02	-1.68E-02	-1.68E-02	-1.68E-02
67	-1.70E-02	-1.68E-02	-1.68E-02	-1.67E-02	-1.67E-02	-1.66E-02
68	-1.73E-02	-1.71E-02	-1.71E-02	-1.75E-02	-1.70E-02	-1.69E-02
69	-1.74E-02	-1.71E-02	-1.70E-02	-1.70E-02	-1.70E-02	-1.69E-02
70	-1.70E-02	-1.68E-02	-1.68E-02	-1.68E-02	-1.67E-02	-1.66E-02
71	-1.71E-02	-1.68E-02	-1.68E-02	-1.68E-02	-1.68E-02	-1.68E-02
72	-1.73E-02	-1.70E-02	-1.70E-02	-1.69E-02	-1.70E-02	-1.71E-02
Biased Statistics						
Average Biased	-1.72E-02	-1.69E-02	-1.69E-02	-1.69E-02	-1.67E-02	-1.64E-02
Std Dev Biased	1.86E-04	2.02E-04	1.34E-04	2.52E-04	2.46E-04	1.68E-04
Ps90%/90% (+KTL) Biased	-1.67E-02	-1.63E-02	-1.65E-02	-1.62E-02	-1.61E-02	-1.59E-02
Ps90%/90% (-KTL) Biased	-1.77E-02	-1.74E-02	-1.73E-02	-1.76E-02	-1.74E-02	-1.68E-02
Un-Biased Statistics						
Average Un-Biased	-1.72E-02	-1.69E-02	-1.69E-02	-1.70E-02	-1.68E-02	-1.68E-02
Std Dev Un-Biased	1.81E-04	1.55E-04	1.47E-04	3.08E-04	1.37E-04	1.56E-04
Ps90%/90% (+KTL) Un-Biased	-1.67E-02	-1.65E-02	-1.65E-02	-1.61E-02	-1.65E-02	-1.63E-02
Ps90%/90% (-KTL) Un-Biased	-1.77E-02	-1.74E-02	-1.73E-02	-1.78E-02	-1.72E-02	-1.72E-02
Specification MIN	-2.00E-02	-2.00E-02	-2.00E-02	-2.00E-02	-2.00E-02	-2.00E-02
Status	PASS	PASS	PASS	PASS	PASS	PASS

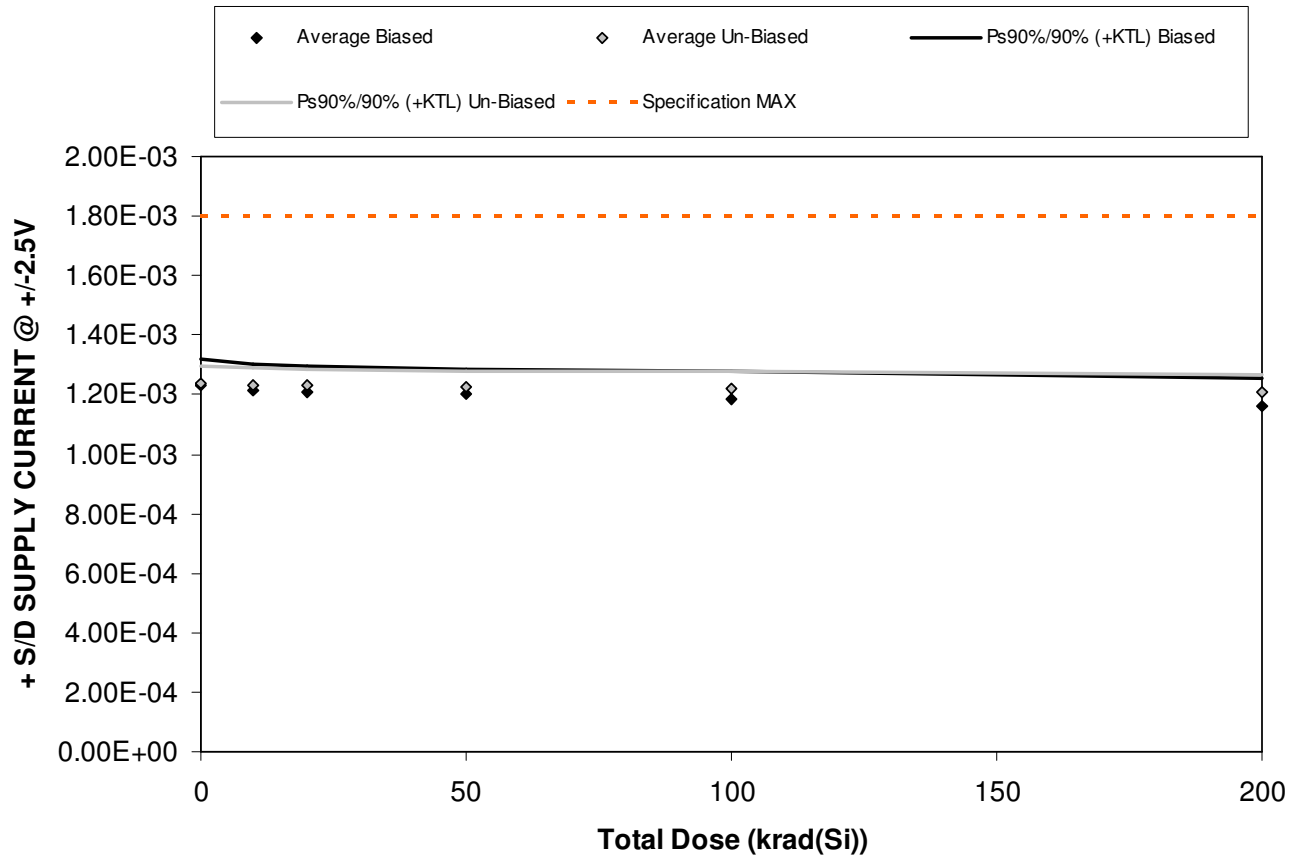


Figure 5.3. Plot of + S/D SUPPLY CURRENT @ +/-2.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.3. Raw data for + S/D SUPPLY CURRENT @ +/-2.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

+ S/D SUPPLY CURRENT @ +/-2.5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.22E-03	1.20E-03	1.19E-03	1.19E-03	1.17E-03	1.15E-03
62	1.24E-03	1.21E-03	1.21E-03	1.21E-03	1.19E-03	1.16E-03
63	1.23E-03	1.21E-03	1.20E-03	1.20E-03	1.18E-03	1.16E-03
64	1.29E-03	1.26E-03	1.26E-03	1.25E-03	1.24E-03	1.22E-03
65	1.20E-03	1.17E-03	1.17E-03	1.16E-03	1.15E-03	1.12E-03
66	1.27E-03	1.26E-03	1.26E-03	1.25E-03	1.25E-03	1.24E-03
67	1.23E-03	1.22E-03	1.22E-03	1.21E-03	1.21E-03	1.20E-03
68	1.22E-03	1.22E-03	1.21E-03	1.22E-03	1.20E-03	1.19E-03
69	1.25E-03	1.24E-03	1.24E-03	1.23E-03	1.23E-03	1.22E-03
70	1.22E-03	1.21E-03	1.21E-03	1.21E-03	1.20E-03	1.19E-03
71	1.22E-03	1.21E-03	1.21E-03	1.21E-03	1.21E-03	1.21E-03
72	1.24E-03	1.24E-03	1.24E-03	1.24E-03	1.24E-03	1.24E-03
Biased Statistics						
Average Biased	1.23E-03	1.21E-03	1.21E-03	1.20E-03	1.19E-03	1.16E-03
Std Dev Biased	3.20E-05	3.20E-05	3.24E-05	3.16E-05	3.26E-05	3.34E-05
Ps90%/90% (+KTL) Biased	1.32E-03	1.30E-03	1.29E-03	1.29E-03	1.28E-03	1.25E-03
Ps90%/90% (-KTL) Biased	1.15E-03	1.12E-03	1.12E-03	1.11E-03	1.10E-03	1.07E-03
Un-Biased Statistics						
Average Un-Biased	1.24E-03	1.23E-03	1.23E-03	1.23E-03	1.22E-03	1.21E-03
Std Dev Un-Biased	2.03E-05	2.10E-05	2.05E-05	1.89E-05	2.16E-05	2.27E-05
Ps90%/90% (+KTL) Un-Biased	1.29E-03	1.29E-03	1.29E-03	1.28E-03	1.28E-03	1.27E-03
Ps90%/90% (-KTL) Un-Biased	1.18E-03	1.17E-03	1.17E-03	1.17E-03	1.16E-03	1.15E-03
Specification MAX	1.80E-03	1.80E-03	1.80E-03	1.80E-03	1.80E-03	1.80E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS

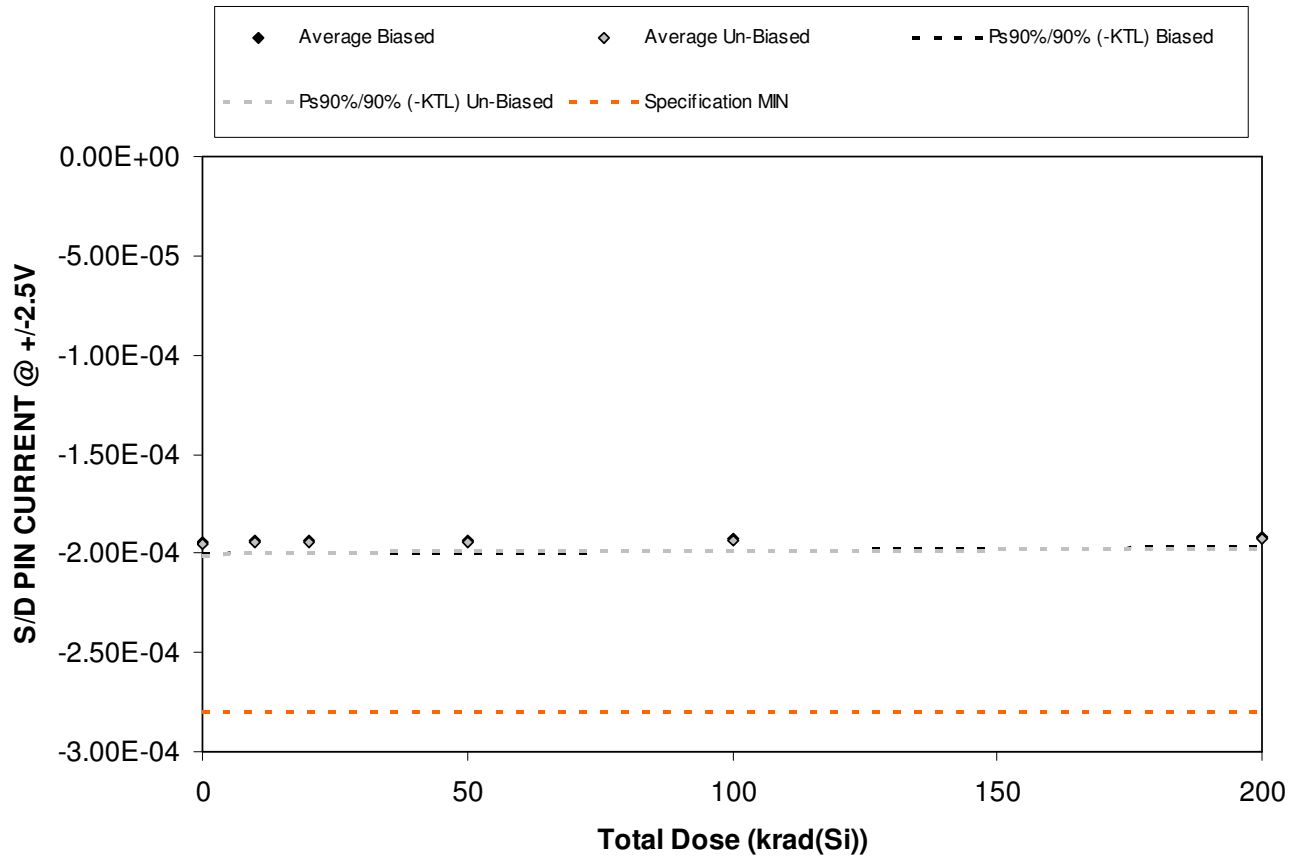


Figure 5.4. Plot of S/D PIN CURRENT @ +/-2.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.4. Raw data for S/D PIN CURRENT @ +/-2.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

S/D PIN CURRENT @ +/-2.5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	-1.93E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.91E-04
62	-1.98E-04	-1.97E-04	-1.97E-04	-1.97E-04	-1.96E-04	-1.95E-04
63	-1.94E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.92E-04	-1.91E-04
64	-1.95E-04	-1.94E-04	-1.94E-04	-1.94E-04	-1.93E-04	-1.92E-04
65	-1.92E-04	-1.92E-04	-1.92E-04	-1.91E-04	-1.91E-04	-1.90E-04
66	-1.94E-04	-1.94E-04	-1.94E-04	-1.93E-04	-1.93E-04	-1.92E-04
67	-1.95E-04	-1.95E-04	-1.94E-04	-1.94E-04	-1.94E-04	-1.93E-04
68	-1.94E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.92E-04	-1.91E-04
69	-1.99E-04	-1.98E-04	-1.98E-04	-1.97E-04	-1.97E-04	-1.96E-04
70	-1.94E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.92E-04	-1.92E-04
71	-1.93E-04	-1.92E-04	-1.92E-04	-1.92E-04	-1.92E-04	-1.92E-04
72	-1.97E-04	-1.97E-04	-1.97E-04	-1.97E-04	-1.97E-04	-1.97E-04
Biased Statistics						
Average Biased	-1.95E-04	-1.94E-04	-1.94E-04	-1.94E-04	-1.93E-04	-1.92E-04
Std Dev Biased	2.15E-06	2.04E-06	2.04E-06	2.15E-06	1.97E-06	1.91E-06
Ps90%/90% (+KTL) Biased	-1.89E-04	-1.88E-04	-1.88E-04	-1.88E-04	-1.88E-04	-1.87E-04
Ps90%/90% (-KTL) Biased	-2.01E-04	-1.99E-04	-1.99E-04	-2.00E-04	-1.98E-04	-1.97E-04
Un-Biased Statistics						
Average Un-Biased	-1.95E-04	-1.95E-04	-1.94E-04	-1.94E-04	-1.93E-04	-1.93E-04
Std Dev Un-Biased	2.16E-06	2.03E-06	2.04E-06	1.83E-06	2.02E-06	2.04E-06
Ps90%/90% (+KTL) Un-Biased	-1.89E-04	-1.89E-04	-1.89E-04	-1.89E-04	-1.88E-04	-1.87E-04
Ps90%/90% (-KTL) Un-Biased	-2.01E-04	-2.00E-04	-2.00E-04	-1.99E-04	-1.99E-04	-1.98E-04
Specification MIN	-2.80E-04	-2.80E-04	-2.80E-04	-2.80E-04	-2.80E-04	-2.80E-04
Status	PASS	PASS	PASS	PASS	PASS	PASS

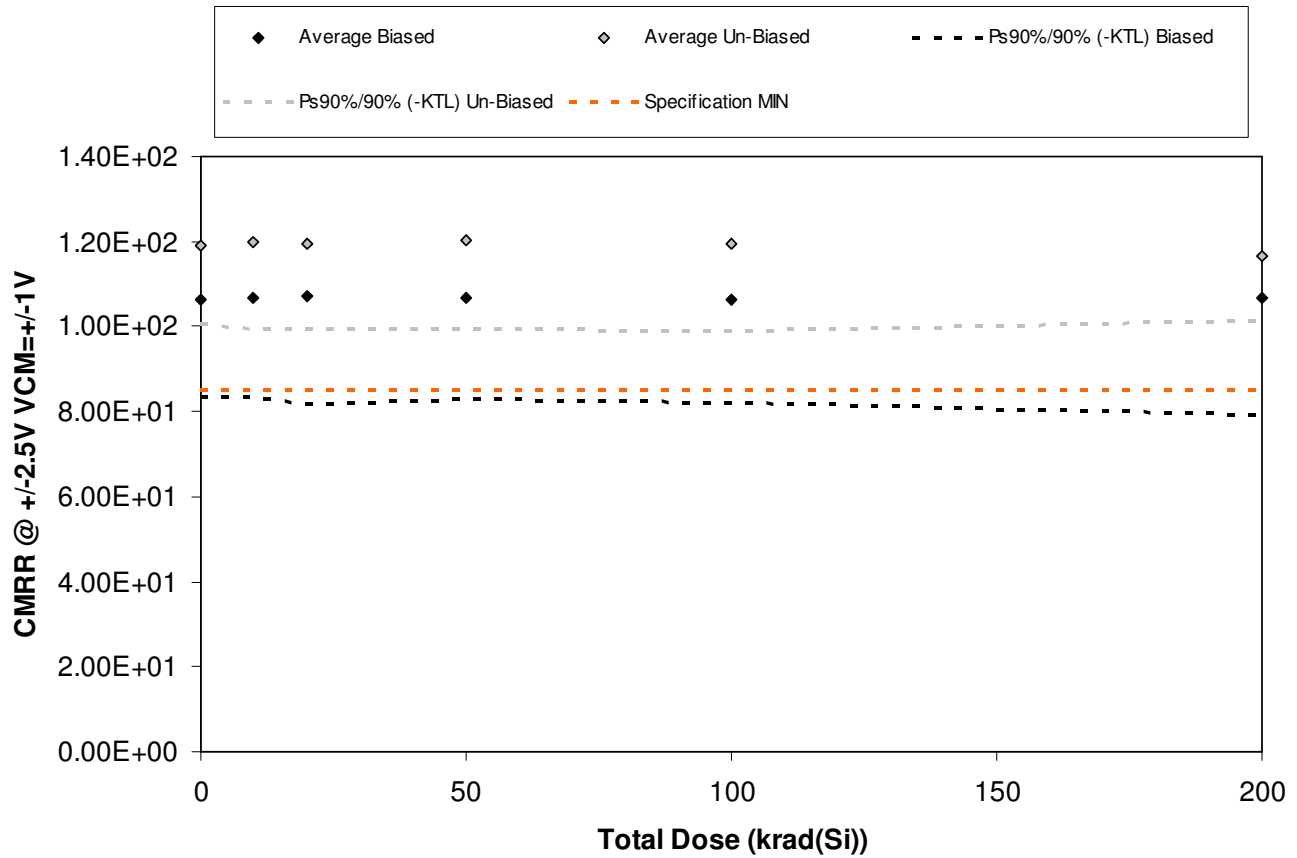


Figure 5.5. Plot of CMRR @ +/-2.5V VCM=+/-1V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.5. Raw data for CMRR @ +/-2.5V VCM=+/-1V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

CMRR @ +/-2.5V VCM=+/-1V Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	1.06E+02	1.06E+02	1.06E+02	1.06E+02	1.06E+02	1.06E+02
62	1.06E+02	1.06E+02	1.06E+02	1.06E+02	1.05E+02	1.05E+02
63	9.91E+01	9.94E+01	9.94E+01	9.92E+01	9.92E+01	9.89E+01
64	1.20E+02	1.21E+02	1.23E+02	1.21E+02	1.22E+02	1.24E+02
65	1.01E+02	1.01E+02	1.01E+02	1.01E+02	1.01E+02	1.01E+02
66	1.24E+02	1.27E+02	1.27E+02	1.26E+02	1.27E+02	1.21E+02
67	1.16E+02	1.15E+02	1.16E+02	1.16E+02	1.14E+02	1.14E+02
68	1.23E+02	1.23E+02	1.22E+02	1.25E+02	1.23E+02	1.20E+02
69	1.08E+02	1.09E+02	1.09E+02	1.09E+02	1.09E+02	1.08E+02
70	1.23E+02	1.24E+02	1.23E+02	1.25E+02	1.23E+02	1.21E+02
71	1.02E+02	1.02E+02	1.02E+02	1.02E+02	1.02E+02	1.02E+02
72	1.15E+02	1.15E+02	1.15E+02	1.16E+02	1.15E+02	1.15E+02
Biased Statistics						
Average Biased	1.06E+02	1.07E+02	1.07E+02	1.07E+02	1.07E+02	1.07E+02
Std Dev Biased	8.35E+00	8.45E+00	9.18E+00	8.59E+00	8.89E+00	1.02E+01
Ps90%/90% (+KTL) Biased	1.29E+02	1.30E+02	1.32E+02	1.30E+02	1.31E+02	1.35E+02
Ps90%/90% (-KTL) Biased	8.35E+01	8.35E+01	8.18E+01	8.30E+01	8.21E+01	7.91E+01
Un-Biased Statistics						
Average Un-Biased	1.19E+02	1.20E+02	1.19E+02	1.20E+02	1.19E+02	1.17E+02
Std Dev Un-Biased	6.64E+00	7.38E+00	7.27E+00	7.61E+00	7.43E+00	5.53E+00
Ps90%/90% (+KTL) Un-Biased	1.37E+02	1.40E+02	1.39E+02	1.41E+02	1.40E+02	1.32E+02
Ps90%/90% (-KTL) Un-Biased	1.01E+02	9.94E+01	9.95E+01	9.92E+01	9.89E+01	1.02E+02
Specification MIN	8.50E+01	8.50E+01	8.50E+01	8.50E+01	8.50E+01	8.50E+01
Status	PASS	PASS	PASS	PASS	PASS	PASS

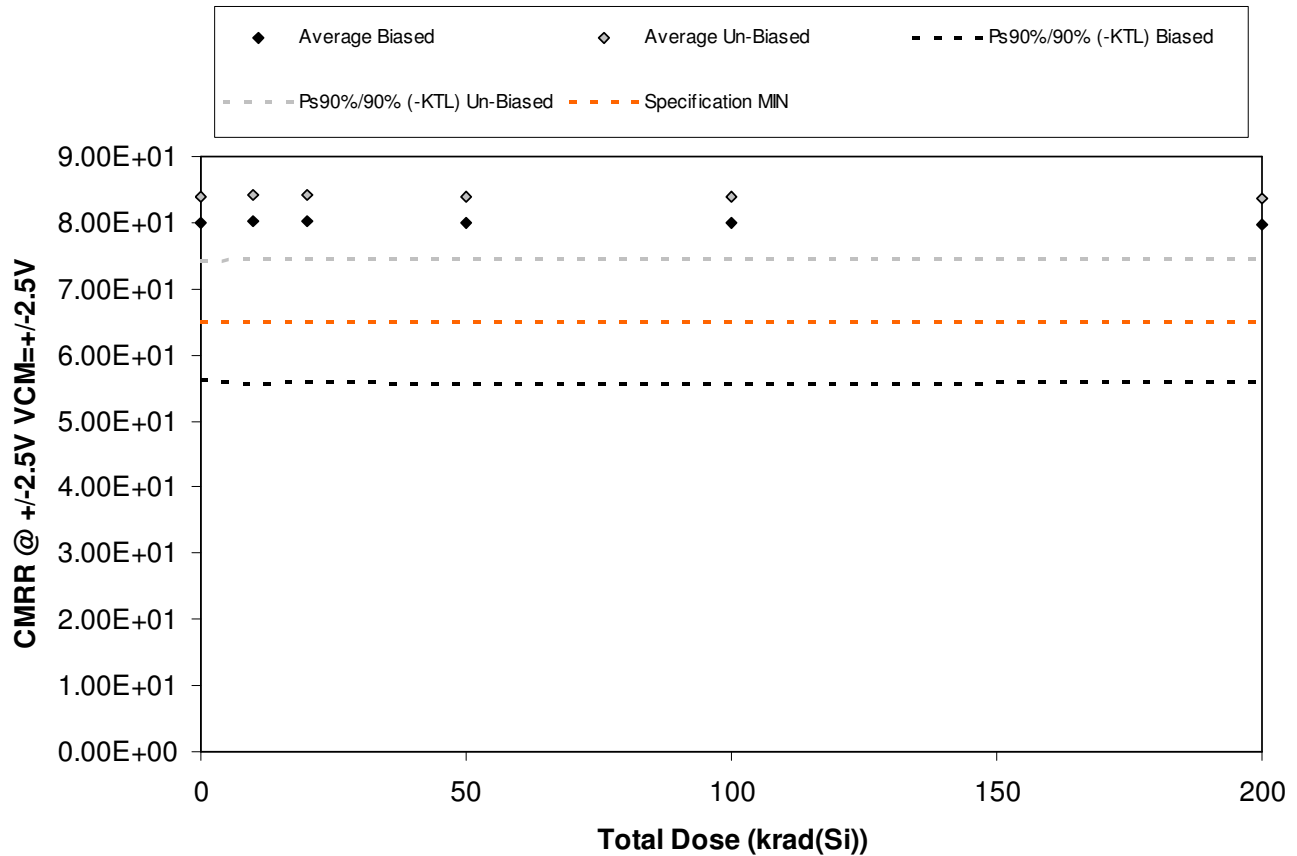


Figure 5.6. Plot of CMRR @ +/-2.5V VCM=+/-2.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.6. Raw data for CMRR @ +/-2.5V VCM=+/-2.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

CMRR @ +/-2.5V VCM=+/-2.5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	7.67E+01	7.66E+01	7.67E+01	7.65E+01	7.64E+01	7.65E+01
62	7.83E+01	7.84E+01	7.84E+01	7.82E+01	7.82E+01	7.80E+01
63	7.38E+01	7.40E+01	7.39E+01	7.39E+01	7.38E+01	7.37E+01
64	9.52E+01	9.59E+01	9.57E+01	9.56E+01	9.56E+01	9.50E+01
65	7.59E+01	7.59E+01	7.59E+01	7.59E+01	7.59E+01	7.58E+01
66	7.80E+01	7.81E+01	7.81E+01	7.81E+01	7.80E+01	7.79E+01
67	8.39E+01	8.42E+01	8.41E+01	8.40E+01	8.38E+01	8.35E+01
68	8.73E+01	8.75E+01	8.74E+01	8.69E+01	8.71E+01	8.65E+01
69	8.50E+01	8.53E+01	8.53E+01	8.52E+01	8.50E+01	8.47E+01
70	8.55E+01	8.57E+01	8.57E+01	8.56E+01	8.56E+01	8.53E+01
71	7.79E+01	7.81E+01	7.81E+01	7.80E+01	7.80E+01	7.80E+01
72	8.62E+01	8.67E+01	8.67E+01	8.67E+01	8.67E+01	8.65E+01
Biased Statistics						
Average Biased	8.00E+01	8.02E+01	8.01E+01	8.00E+01	8.00E+01	7.98E+01
Std Dev Biased	8.67E+00	8.93E+00	8.86E+00	8.85E+00	8.87E+00	8.65E+00
Ps90%/90% (+KTL) Biased	1.04E+02	1.05E+02	1.04E+02	1.04E+02	1.04E+02	1.04E+02
Ps90%/90% (-KTL) Biased	5.62E+01	5.57E+01	5.58E+01	5.58E+01	5.57E+01	5.61E+01
Un-Biased Statistics						
Average Un-Biased	8.39E+01	8.42E+01	8.41E+01	8.40E+01	8.39E+01	8.36E+01
Std Dev Un-Biased	3.55E+00	3.57E+00	3.58E+00	3.45E+00	3.50E+00	3.37E+00
Ps90%/90% (+KTL) Un-Biased	9.37E+01	9.39E+01	9.39E+01	9.34E+01	9.35E+01	9.28E+01
Ps90%/90% (-KTL) Un-Biased	7.42E+01	7.44E+01	7.43E+01	7.45E+01	7.43E+01	7.43E+01
Specification MIN	6.50E+01	6.50E+01	6.50E+01	6.50E+01	6.50E+01	6.50E+01
Status	PASS	PASS	PASS	PASS	PASS	PASS

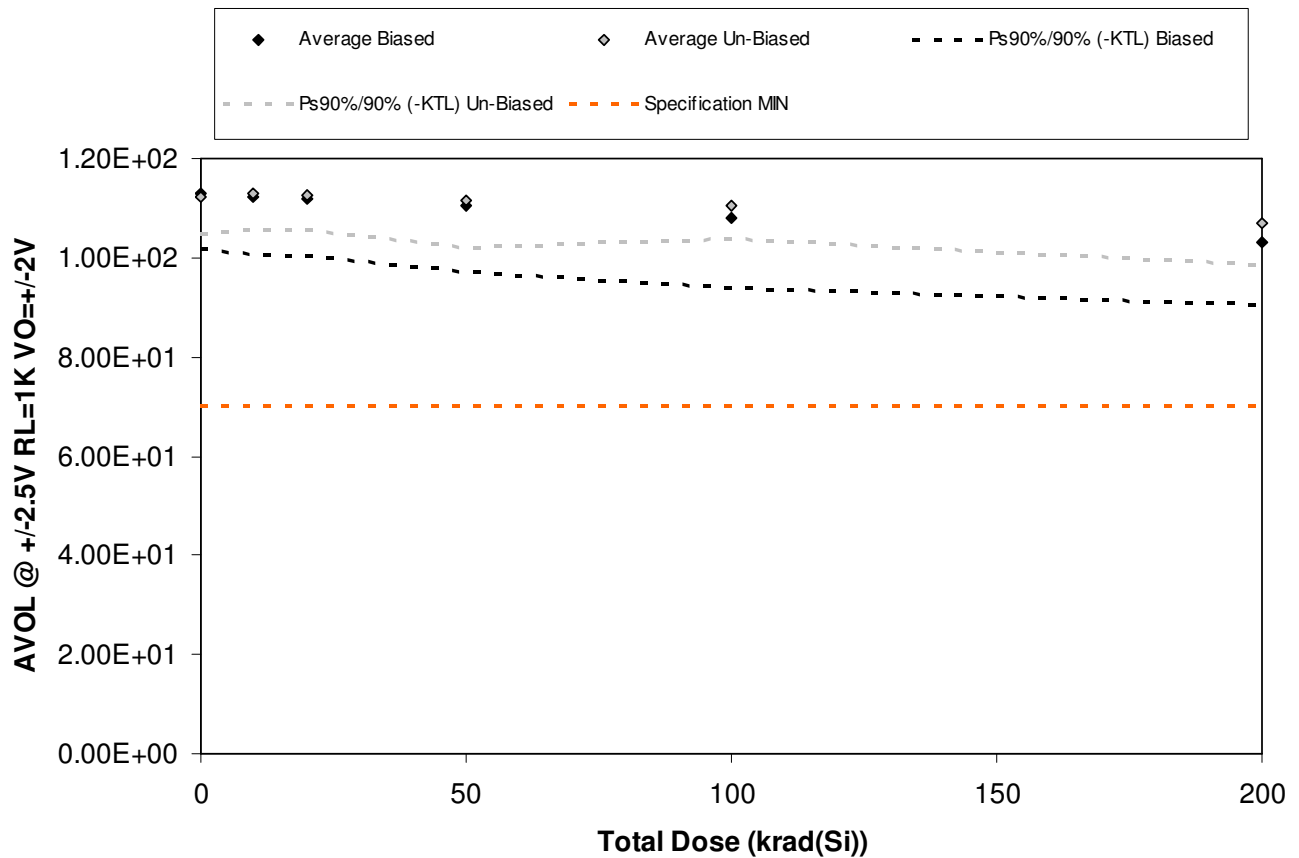


Figure 5.7. Plot of AVOL @ +/-2.5V RL=1K VO=+/-2V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.7. Raw data for AVOL @ +/-2.5V RL=1K VO=+/-2V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

AVOL @ +/-2.5V RL=1K VO=+/-2V Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	1.11E+02	1.10E+02	1.10E+02	1.07E+02	1.05E+02	1.01E+02
62	1.13E+02	1.13E+02	1.13E+02	1.10E+02	1.07E+02	1.02E+02
63	1.20E+02	1.19E+02	1.19E+02	1.18E+02	1.16E+02	1.11E+02
64	1.12E+02	1.13E+02	1.12E+02	1.11E+02	1.08E+02	1.03E+02
65	1.09E+02	1.08E+02	1.07E+02	1.06E+02	1.03E+02	9.88E+01
66	1.17E+02	1.17E+02	1.17E+02	1.17E+02	1.14E+02	1.12E+02
67	1.13E+02	1.13E+02	1.13E+02	1.13E+02	1.11E+02	1.07E+02
68	1.11E+02	1.13E+02	1.11E+02	1.09E+02	1.09E+02	1.06E+02
69	1.12E+02	1.13E+02	1.13E+02	1.11E+02	1.10E+02	1.07E+02
70	1.09E+02	1.10E+02	1.09E+02	1.08E+02	1.08E+02	1.04E+02
71	1.18E+02	1.20E+02	1.21E+02	1.21E+02	1.21E+02	1.20E+02
72	1.13E+02	1.14E+02	1.15E+02	1.14E+02	1.15E+02	1.14E+02
Biased Statistics						
Average Biased	1.13E+02	1.12E+02	1.12E+02	1.10E+02	1.08E+02	1.03E+02
Std Dev Biased	4.08E+00	4.31E+00	4.32E+00	4.81E+00	5.13E+00	4.56E+00
Ps90%/90% (+KTL) Biased	1.24E+02	1.24E+02	1.24E+02	1.24E+02	1.22E+02	1.16E+02
Ps90%/90% (-KTL) Biased	1.02E+02	1.01E+02	1.00E+02	9.72E+01	9.38E+01	9.05E+01
Un-Biased Statistics						
Average Un-Biased	1.12E+02	1.13E+02	1.13E+02	1.11E+02	1.10E+02	1.07E+02
Std Dev Un-Biased	2.67E+00	2.70E+00	2.64E+00	3.44E+00	2.40E+00	3.13E+00
Ps90%/90% (+KTL) Un-Biased	1.20E+02	1.20E+02	1.20E+02	1.21E+02	1.17E+02	1.16E+02
Ps90%/90% (-KTL) Un-Biased	1.05E+02	1.06E+02	1.05E+02	1.02E+02	1.04E+02	9.85E+01
Specification MIN	7.00E+01	7.00E+01	7.00E+01	7.00E+01	7.00E+01	7.00E+01
Status	PASS	PASS	PASS	PASS	PASS	PASS

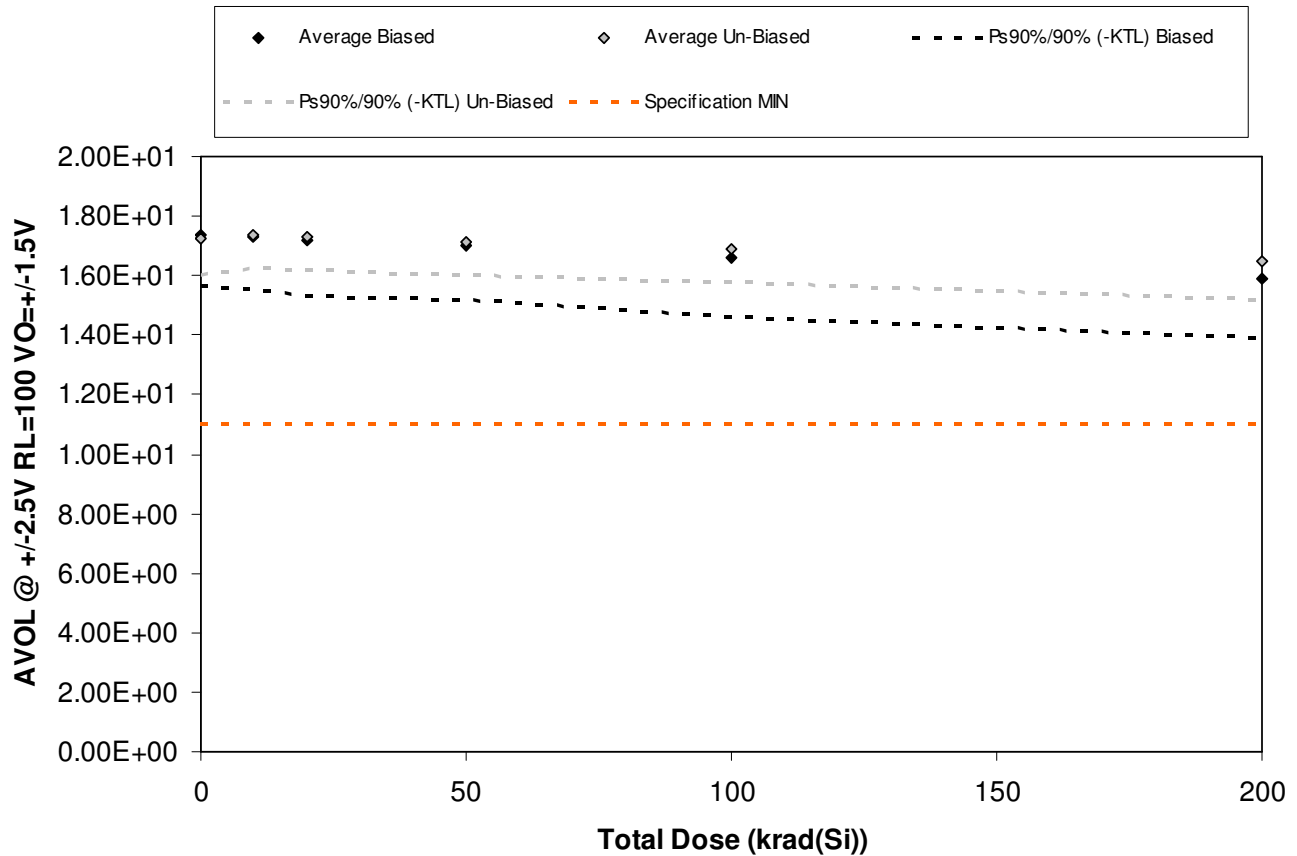


Figure 5.8. Plot of AVOL @ +/-2.5V RL=100 VO=+-1.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.8. Raw data for AVOL @ +/-2.5V RL=100 VO=+/-1.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

AVOL @ +/-2.5V RL=100 VO=+/-1.5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.71E+01	1.69E+01	1.69E+01	1.66E+01	1.62E+01	1.56E+01
62	1.73E+01	1.73E+01	1.72E+01	1.69E+01	1.64E+01	1.56E+01
63	1.83E+01	1.83E+01	1.83E+01	1.81E+01	1.78E+01	1.71E+01
64	1.74E+01	1.73E+01	1.72E+01	1.71E+01	1.67E+01	1.59E+01
65	1.66E+01	1.66E+01	1.64E+01	1.64E+01	1.59E+01	1.52E+01
66	1.79E+01	1.80E+01	1.79E+01	1.78E+01	1.76E+01	1.72E+01
67	1.73E+01	1.74E+01	1.74E+01	1.72E+01	1.69E+01	1.65E+01
68	1.71E+01	1.72E+01	1.72E+01	1.69E+01	1.68E+01	1.64E+01
69	1.71E+01	1.73E+01	1.72E+01	1.71E+01	1.68E+01	1.62E+01
70	1.67E+01	1.69E+01	1.68E+01	1.67E+01	1.65E+01	1.60E+01
71	1.82E+01	1.83E+01	1.84E+01	1.84E+01	1.84E+01	1.83E+01
72	1.74E+01	1.75E+01	1.75E+01	1.76E+01	1.75E+01	1.75E+01
Biased Statistics						
Average Biased	1.73E+01	1.73E+01	1.72E+01	1.70E+01	1.66E+01	1.59E+01
Std Dev Biased	6.19E-01	6.42E-01	6.96E-01	6.61E-01	7.31E-01	7.26E-01
Ps90%/90% (+KTL) Biased	1.90E+01	1.90E+01	1.91E+01	1.88E+01	1.86E+01	1.79E+01
Ps90%/90% (-KTL) Biased	1.56E+01	1.55E+01	1.53E+01	1.52E+01	1.46E+01	1.39E+01
Un-Biased Statistics						
Average Un-Biased	1.72E+01	1.74E+01	1.73E+01	1.71E+01	1.69E+01	1.65E+01
Std Dev Un-Biased	4.38E-01	4.04E-01	4.00E-01	4.16E-01	4.09E-01	4.56E-01
Ps90%/90% (+KTL) Un-Biased	1.84E+01	1.85E+01	1.84E+01	1.83E+01	1.80E+01	1.77E+01
Ps90%/90% (-KTL) Un-Biased	1.60E+01	1.63E+01	1.62E+01	1.60E+01	1.58E+01	1.52E+01
Specification MIN	1.10E+01	1.10E+01	1.10E+01	1.10E+01	1.10E+01	1.10E+01
Status	PASS	PASS	PASS	PASS	PASS	PASS

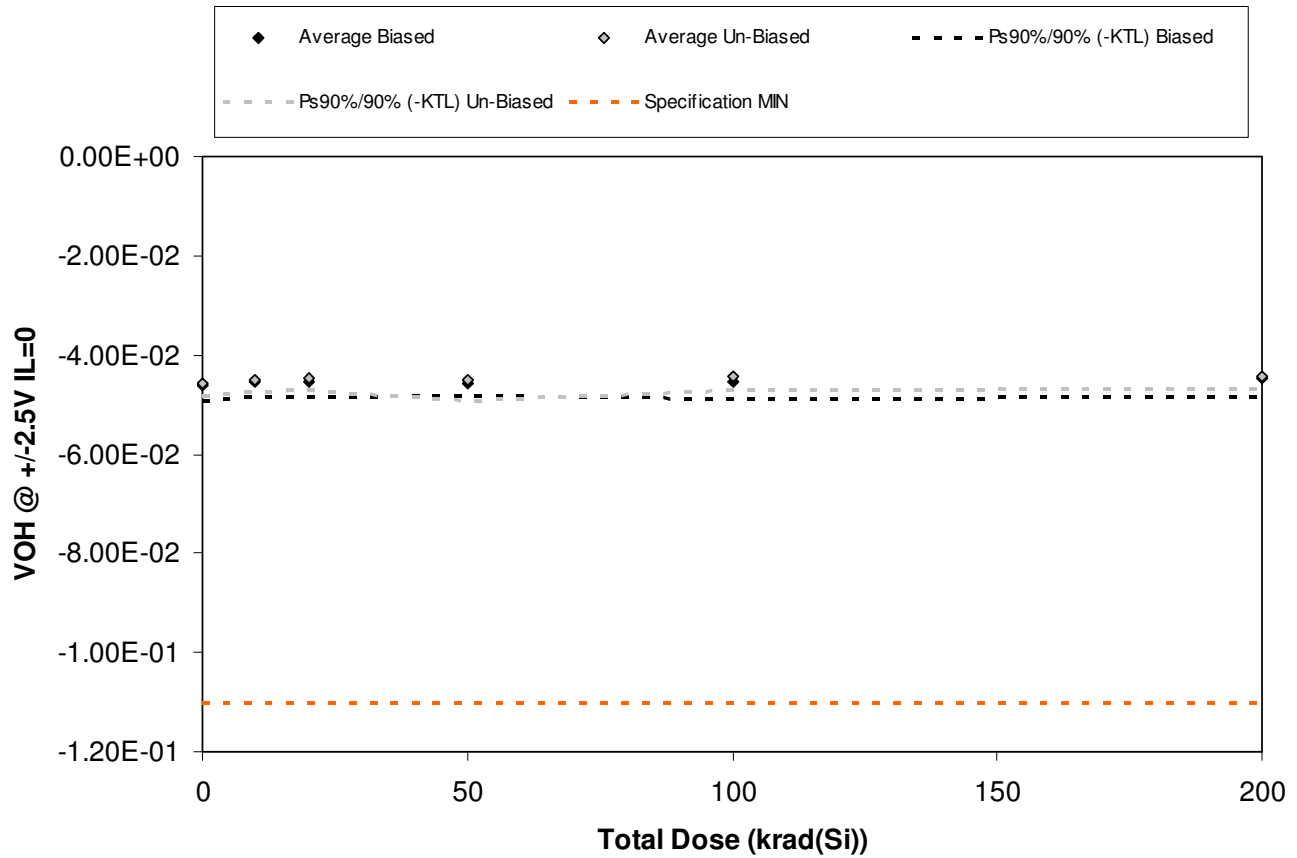


Figure 5.9. Plot of VOH @ +/-2.5V IL=0 versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.9. Raw data for VOH @ +/-2.5V IL=0 versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOH @ +/-2.5V IL=0		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	-4.58E-02	-4.62E-02	-4.57E-02	-4.67E-02	-4.66E-02	-4.54E-02
	62	-4.43E-02	-4.34E-02	-4.34E-02	-4.40E-02	-4.32E-02	-4.23E-02
	63	-4.70E-02	-4.58E-02	-4.60E-02	-4.59E-02	-4.58E-02	-4.53E-02
	64	-4.67E-02	-4.55E-02	-4.59E-02	-4.55E-02	-4.52E-02	-4.49E-02
	65	-4.67E-02	-4.59E-02	-4.61E-02	-4.59E-02	-4.56E-02	-4.56E-02
	66	-4.61E-02	-4.54E-02	-4.53E-02	-4.51E-02	-4.51E-02	-4.51E-02
	67	-4.50E-02	-4.41E-02	-4.41E-02	-4.37E-02	-4.34E-02	-4.36E-02
	68	-4.69E-02	-4.60E-02	-4.57E-02	-4.73E-02	-4.54E-02	-4.52E-02
	69	-4.50E-02	-4.37E-02	-4.36E-02	-4.32E-02	-4.33E-02	-4.31E-02
	70	-4.63E-02	-4.54E-02	-4.51E-02	-4.51E-02	-4.50E-02	-4.47E-02
	71	-4.71E-02	-4.60E-02	-4.59E-02	-4.61E-02	-4.59E-02	-4.62E-02
	72	-4.57E-02	-4.44E-02	-4.45E-02	-4.44E-02	-4.45E-02	-4.50E-02
Biased Statistics							
	Average Biased	-4.61E-02	-4.54E-02	-4.54E-02	-4.56E-02	-4.53E-02	-4.47E-02
	Std Dev Biased	1.09E-03	1.14E-03	1.15E-03	9.98E-04	1.28E-03	1.36E-03
	Ps90%/90% (+KTL) Biased	-4.31E-02	-4.22E-02	-4.23E-02	-4.29E-02	-4.18E-02	-4.10E-02
	Ps90%/90% (-KTL) Biased	-4.91E-02	-4.85E-02	-4.86E-02	-4.83E-02	-4.88E-02	-4.84E-02
Un-Biased Statistics							
	Average Un-Biased	-4.59E-02	-4.49E-02	-4.48E-02	-4.49E-02	-4.44E-02	-4.43E-02
	Std Dev Un-Biased	8.22E-04	9.73E-04	8.64E-04	1.58E-03	9.80E-04	9.41E-04
	Ps90%/90% (+KTL) Un-Biased	-4.36E-02	-4.23E-02	-4.24E-02	-4.05E-02	-4.18E-02	-4.17E-02
	Ps90%/90% (-KTL) Un-Biased	-4.81E-02	-4.76E-02	-4.71E-02	-4.92E-02	-4.71E-02	-4.69E-02
	Specification MIN	-1.10E-01	-1.10E-01	-1.10E-01	-1.10E-01	-1.10E-01	-1.10E-01
	Status	PASS	PASS	PASS	PASS	PASS	PASS

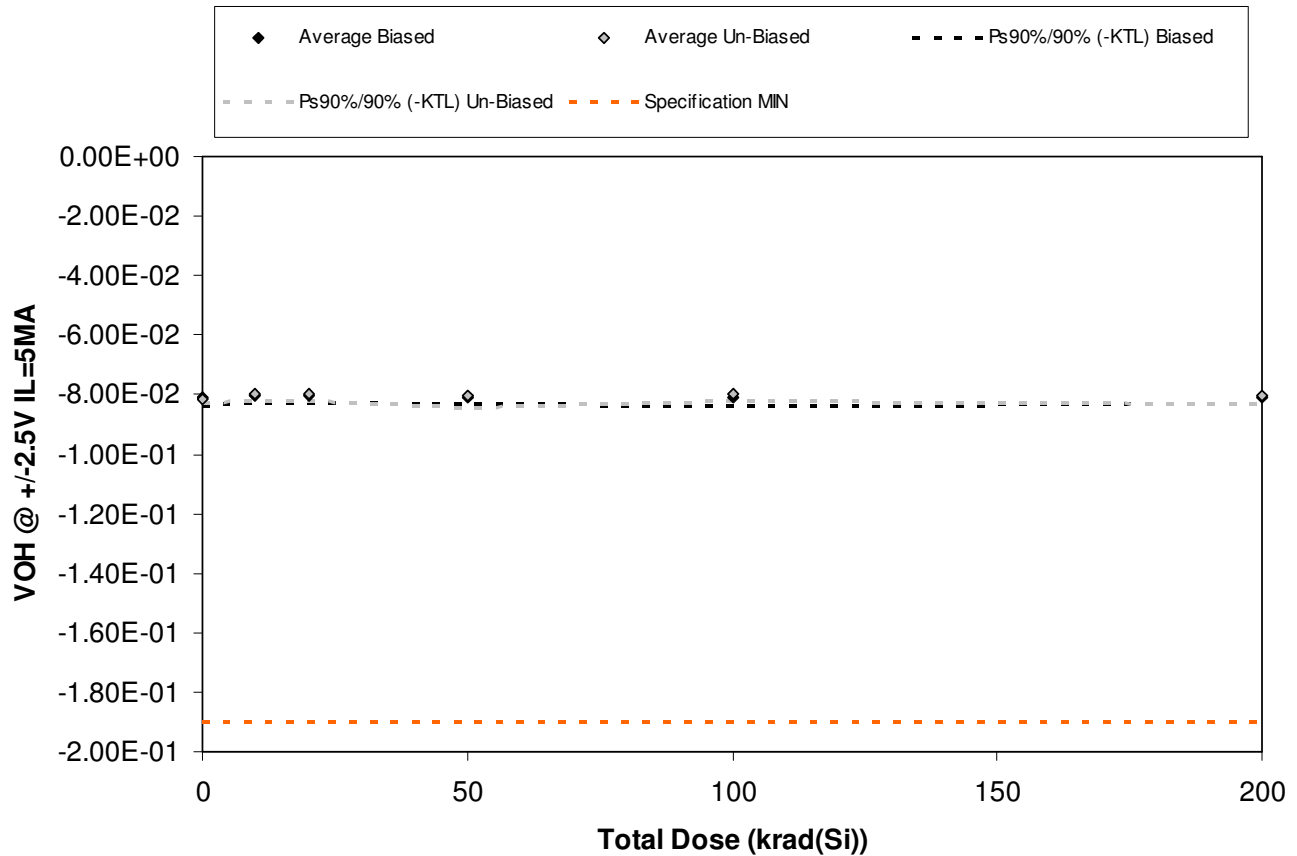


Figure 5.10. Plot of VOH @ +/-2.5V IL=5MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.10. Raw data for VOH @ +/-2.5V IL=5MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOH @ +/-2.5V IL=5MA Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	-8.04E-02	-8.10E-02	-8.06E-02	-8.22E-02	-8.25E-02	-8.18E-02
62	-8.02E-02	-7.92E-02	-7.93E-02	-8.02E-02	-8.00E-02	-8.01E-02
63	-8.23E-02	-8.06E-02	-8.11E-02	-8.12E-02	-8.10E-02	-8.12E-02
64	-8.13E-02	-8.01E-02	-8.08E-02	-8.08E-02	-8.05E-02	-8.09E-02
65	-8.19E-02	-8.11E-02	-8.13E-02	-8.12E-02	-8.15E-02	-8.17E-02
66	-8.21E-02	-8.09E-02	-8.10E-02	-8.12E-02	-8.10E-02	-8.17E-02
67	-8.04E-02	-7.88E-02	-7.92E-02	-7.89E-02	-7.90E-02	-7.91E-02
68	-8.16E-02	-8.06E-02	-8.07E-02	-8.27E-02	-8.02E-02	-8.08E-02
69	-8.12E-02	-7.96E-02	-7.95E-02	-7.95E-02	-7.96E-02	-8.00E-02
70	-8.10E-02	-8.01E-02	-7.98E-02	-8.00E-02	-7.96E-02	-7.99E-02
71	-8.21E-02	-8.10E-02	-8.07E-02	-8.09E-02	-8.07E-02	-8.14E-02
72	-8.09E-02	-7.93E-02	-7.94E-02	-7.87E-02	-7.91E-02	-7.99E-02
Biased Statistics						
Average Biased	-8.12E-02	-8.04E-02	-8.06E-02	-8.11E-02	-8.11E-02	-8.11E-02
Std Dev Biased	9.04E-04	7.81E-04	7.99E-04	7.27E-04	9.65E-04	6.90E-04
Ps90%/90% (+KTL) Biased	-7.87E-02	-7.82E-02	-7.84E-02	-7.91E-02	-7.85E-02	-7.92E-02
Ps90%/90% (-KTL) Biased	-8.37E-02	-8.25E-02	-8.28E-02	-8.31E-02	-8.38E-02	-8.30E-02
Un-Biased Statistics						
Average Un-Biased	-8.12E-02	-8.00E-02	-8.00E-02	-8.05E-02	-7.99E-02	-8.03E-02
Std Dev Un-Biased	6.29E-04	8.34E-04	7.38E-04	1.51E-03	7.60E-04	9.94E-04
Ps90%/90% (+KTL) Un-Biased	-7.95E-02	-7.77E-02	-7.80E-02	-7.63E-02	-7.78E-02	-7.76E-02
Ps90%/90% (-KTL) Un-Biased	-8.30E-02	-8.23E-02	-8.21E-02	-8.46E-02	-8.20E-02	-8.30E-02
Specification MIN	-1.90E-01	-1.90E-01	-1.90E-01	-1.90E-01	-1.90E-01	-1.90E-01
Status	PASS	PASS	PASS	PASS	PASS	PASS

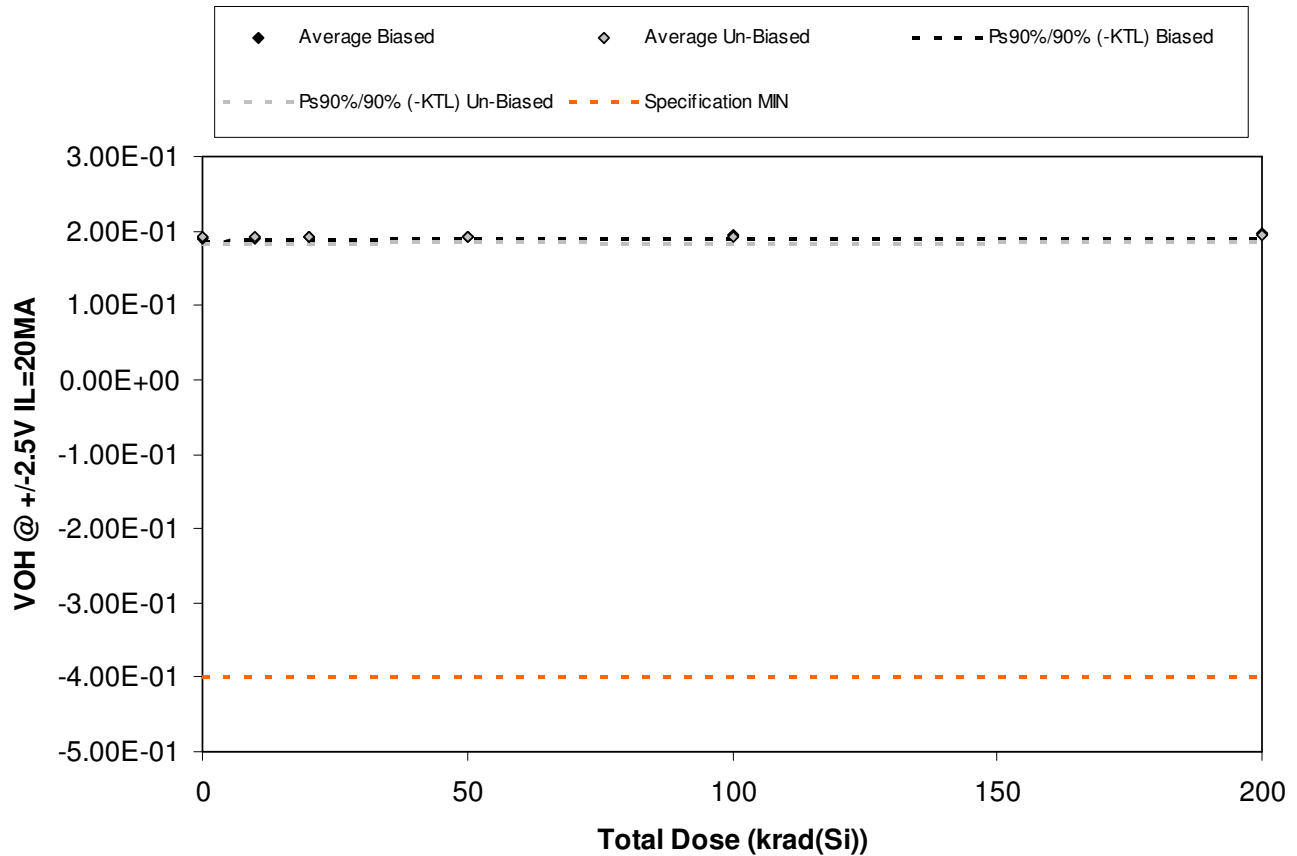


Figure 5.11. Plot of VOH @ +/-2.5V IL=20MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.11. Raw data for VOH @ +/-2.5V IL=20MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOH @ +/-2.5V IL=20MA	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.89E-01	1.90E-01	1.90E-01	1.93E-01	1.95E-01	1.97E-01
62	1.92E-01	1.92E-01	1.93E-01	1.95E-01	1.97E-01	2.00E-01
63	1.91E-01	1.90E-01	1.91E-01	1.92E-01	1.93E-01	1.94E-01
64	1.89E-01	1.89E-01	1.90E-01	1.91E-01	1.92E-01	1.95E-01
65	1.92E-01	1.91E-01	1.92E-01	1.93E-01	1.94E-01	1.96E-01
66	1.95E-01	1.94E-01	1.95E-01	1.95E-01	1.96E-01	1.98E-01
67	1.89E-01	1.88E-01	1.88E-01	1.89E-01	1.90E-01	1.91E-01
68	1.90E-01	1.90E-01	1.90E-01	1.93E-01	1.90E-01	1.92E-01
69	1.96E-01	1.94E-01	1.94E-01	1.95E-01	1.95E-01	1.97E-01
70	1.90E-01	1.89E-01	1.89E-01	1.90E-01	1.90E-01	1.91E-01
71	1.92E-01	1.91E-01	1.91E-01	1.90E-01	1.91E-01	1.91E-01
72	1.90E-01	1.88E-01	1.87E-01	1.87E-01	1.88E-01	1.89E-01
Biased Statistics						
Average Biased	1.91E-01	1.91E-01	1.91E-01	1.93E-01	1.94E-01	1.97E-01
Std Dev Biased	1.63E-03	1.31E-03	1.18E-03	1.52E-03	1.93E-03	2.21E-03
Ps90%/90% (+KTL) Biased	1.95E-01	1.94E-01	1.95E-01	1.97E-01	1.99E-01	2.03E-01
Ps90%/90% (-KTL) Biased	1.86E-01	1.87E-01	1.88E-01	1.89E-01	1.89E-01	1.90E-01
Un-Biased Statistics						
Average Un-Biased	1.92E-01	1.91E-01	1.91E-01	1.92E-01	1.92E-01	1.94E-01
Std Dev Un-Biased	3.23E-03	2.86E-03	2.98E-03	2.91E-03	3.17E-03	3.49E-03
Ps90%/90% (+KTL) Un-Biased	2.01E-01	1.99E-01	1.99E-01	2.00E-01	2.01E-01	2.03E-01
Ps90%/90% (-KTL) Un-Biased	1.83E-01	1.83E-01	1.83E-01	1.84E-01	1.84E-01	1.84E-01
Specification MIN	-4.00E-01	-4.00E-01	-4.00E-01	-4.00E-01	-4.00E-01	-4.00E-01
Status	PASS	PASS	PASS	PASS	PASS	PASS

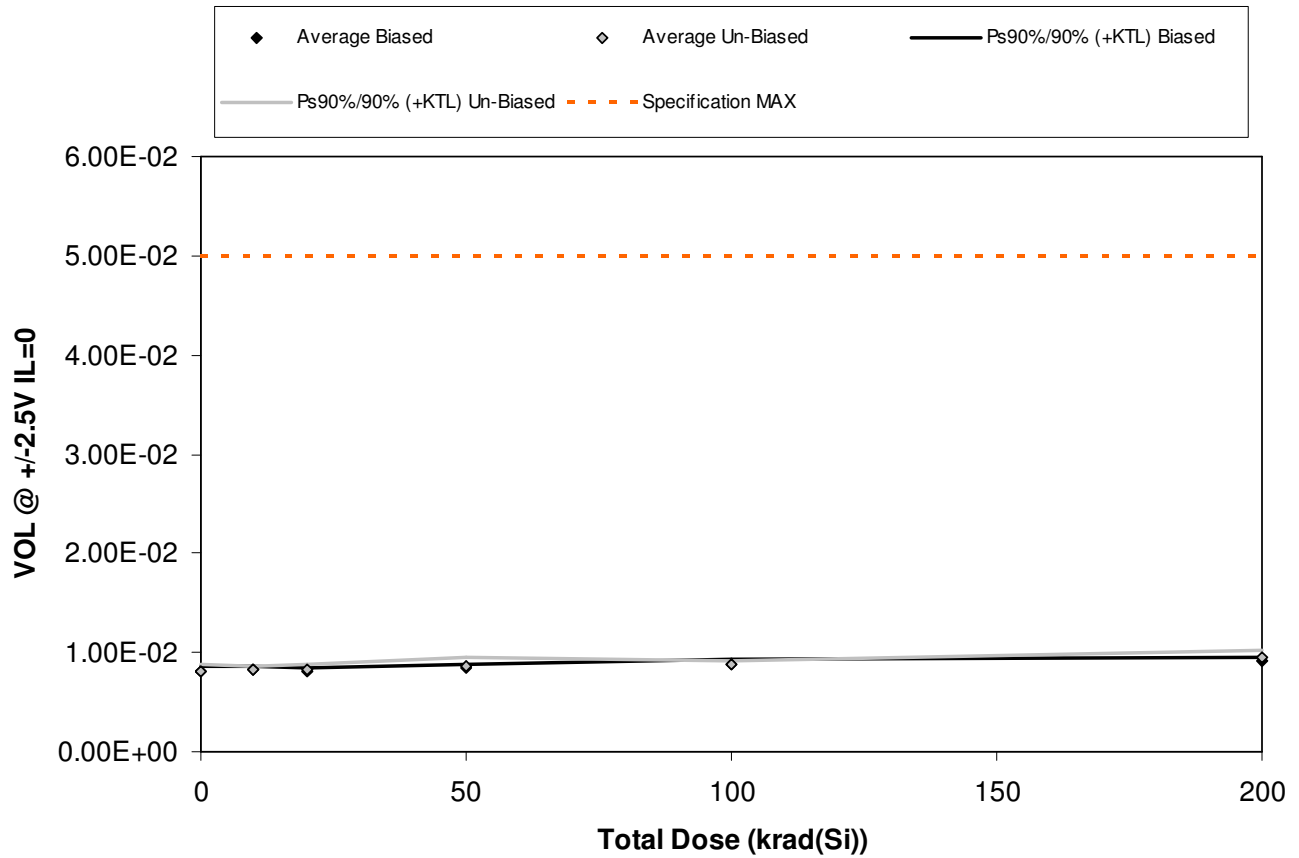


Figure 5.12. Plot of VOL @ +/-2.5V IL=0 versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.12. Raw data for VOL @ +/-2.5V IL=0 versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOL @ +/-2.5V IL=0		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	7.95E-03	8.29E-03	8.27E-03	8.57E-03	9.16E-03	9.36E-03
	62	8.13E-03	8.14E-03	8.06E-03	8.24E-03	8.75E-03	9.29E-03
	63	8.46E-03	8.34E-03	8.21E-03	8.55E-03	8.62E-03	9.17E-03
	64	8.11E-03	8.34E-03	8.07E-03	8.44E-03	8.60E-03	8.98E-03
	65	7.99E-03	7.95E-03	8.13E-03	8.27E-03	8.59E-03	9.09E-03
	66	8.04E-03	8.23E-03	8.35E-03	8.62E-03	8.77E-03	9.73E-03
	67	8.02E-03	8.32E-03	7.97E-03	8.41E-03	9.03E-03	9.53E-03
	68	8.36E-03	8.13E-03	8.47E-03	9.15E-03	8.85E-03	9.53E-03
	69	8.11E-03	8.30E-03	8.35E-03	8.51E-03	8.92E-03	9.53E-03
	70	7.55E-03	8.00E-03	8.16E-03	8.43E-03	8.71E-03	9.08E-03
	71	8.38E-03	8.18E-03	8.01E-03	8.06E-03	8.23E-03	8.17E-03
	72	8.20E-03	8.03E-03	8.04E-03	7.99E-03	7.91E-03	8.22E-03
Biased Statistics							
Average Biased		8.13E-03	8.21E-03	8.15E-03	8.41E-03	8.74E-03	9.18E-03
Std Dev Biased		2.00E-04	1.71E-04	9.17E-05	1.55E-04	2.42E-04	1.50E-04
Ps90%/90% (+KTL) Biased		8.67E-03	8.68E-03	8.40E-03	8.84E-03	9.41E-03	9.59E-03
Ps90%/90% (-KTL) Biased		7.58E-03	7.75E-03	7.90E-03	7.99E-03	8.08E-03	8.77E-03
Un-Biased Statistics							
Average Un-Biased		8.02E-03	8.19E-03	8.26E-03	8.62E-03	8.86E-03	9.48E-03
Std Dev Un-Biased		2.94E-04	1.29E-04	1.95E-04	3.05E-04	1.26E-04	2.40E-04
Ps90%/90% (+KTL) Un-Biased		8.82E-03	8.55E-03	8.79E-03	9.46E-03	9.20E-03	1.01E-02
Ps90%/90% (-KTL) Un-Biased		7.21E-03	7.84E-03	7.72E-03	7.79E-03	8.51E-03	8.82E-03
Specification MAX		5.00E-02	5.00E-02	5.00E-02	5.00E-02	5.00E-02	5.00E-02
Status		PASS	PASS	PASS	PASS	PASS	PASS

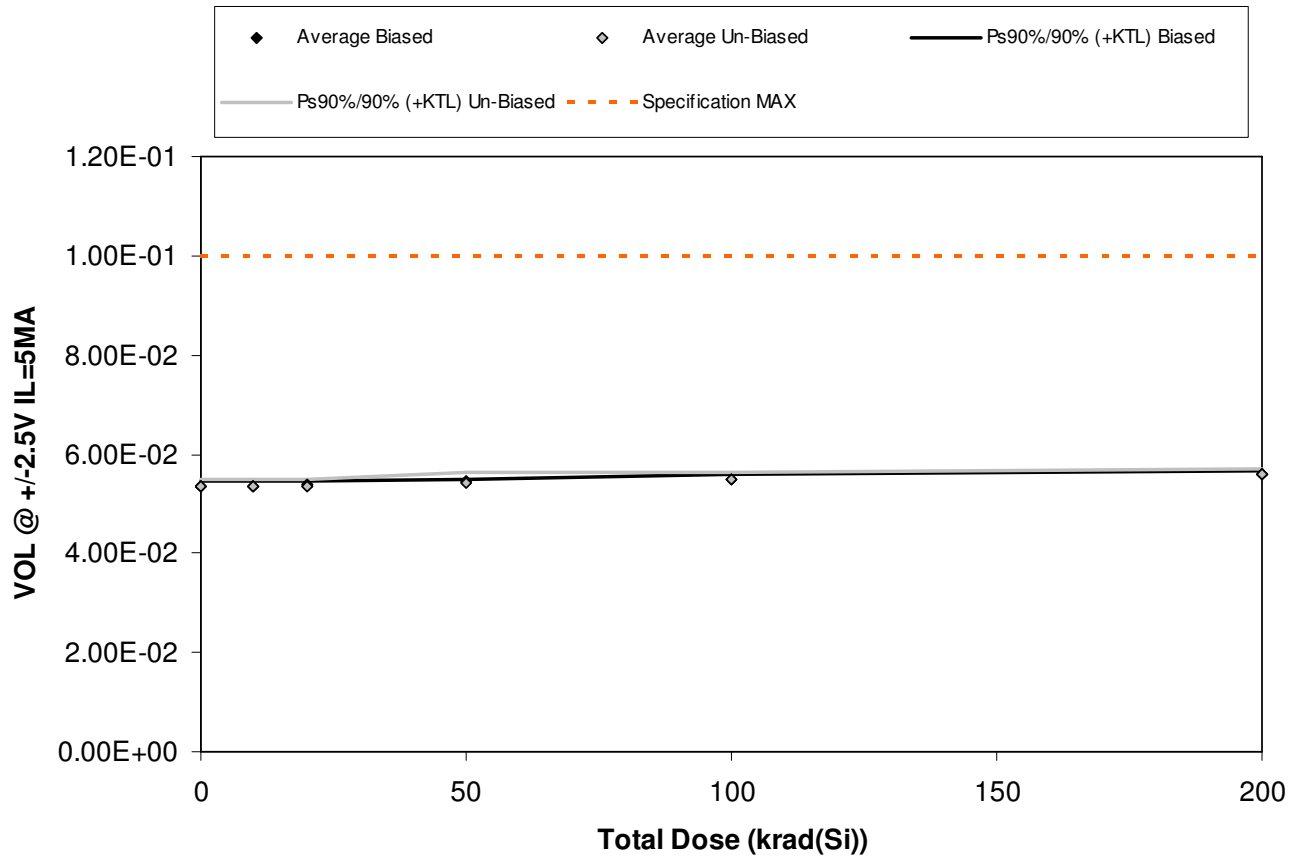


Figure 5.13. Plot of VOL @ +/-2.5V IL=5MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.13. Raw data for VOL @ +/-2.5V IL=5MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOL @ +/-2.5V IL=5MA		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	5.34E-02	5.35E-02	5.37E-02	5.44E-02	5.55E-02	5.63E-02
	62	5.31E-02	5.30E-02	5.32E-02	5.43E-02	5.48E-02	5.59E-02
	63	5.42E-02	5.39E-02	5.39E-02	5.44E-02	5.48E-02	5.58E-02
	64	5.35E-02	5.37E-02	5.41E-02	5.43E-02	5.50E-02	5.61E-02
	65	5.37E-02	5.37E-02	5.40E-02	5.46E-02	5.51E-02	5.58E-02
	66	5.27E-02	5.27E-02	5.30E-02	5.33E-02	5.43E-02	5.54E-02
	67	5.39E-02	5.40E-02	5.44E-02	5.49E-02	5.55E-02	5.65E-02
	68	5.37E-02	5.38E-02	5.38E-02	5.49E-02	5.54E-02	5.60E-02
	69	5.31E-02	5.31E-02	5.31E-02	5.34E-02	5.44E-02	5.55E-02
	70	5.35E-02	5.32E-02	5.34E-02	5.40E-02	5.45E-02	5.55E-02
	71	5.37E-02	5.32E-02	5.32E-02	5.35E-02	5.34E-02	5.33E-02
	72	5.38E-02	5.34E-02	5.33E-02	5.32E-02	5.33E-02	5.38E-02
Biased Statistics							
	Average Biased	5.36E-02	5.36E-02	5.38E-02	5.44E-02	5.50E-02	5.60E-02
	Std Dev Biased	4.06E-04	3.11E-04	3.42E-04	1.43E-04	3.07E-04	2.28E-04
	Ps90%/90% (+KTL) Biased	5.47E-02	5.44E-02	5.47E-02	5.48E-02	5.59E-02	5.66E-02
	Ps90%/90% (-KTL) Biased	5.25E-02	5.27E-02	5.28E-02	5.40E-02	5.42E-02	5.54E-02
Un-Biased Statistics							
	Average Un-Biased	5.34E-02	5.33E-02	5.35E-02	5.41E-02	5.48E-02	5.58E-02
	Std Dev Un-Biased	5.08E-04	5.19E-04	5.43E-04	7.82E-04	5.94E-04	4.52E-04
	Ps90%/90% (+KTL) Un-Biased	5.48E-02	5.48E-02	5.50E-02	5.62E-02	5.64E-02	5.70E-02
	Ps90%/90% (-KTL) Un-Biased	5.20E-02	5.19E-02	5.21E-02	5.19E-02	5.32E-02	5.45E-02
	Specification MAX	1.00E-01	1.00E-01	1.00E-01	1.00E-01	1.00E-01	1.00E-01
	Status	PASS	PASS	PASS	PASS	PASS	PASS

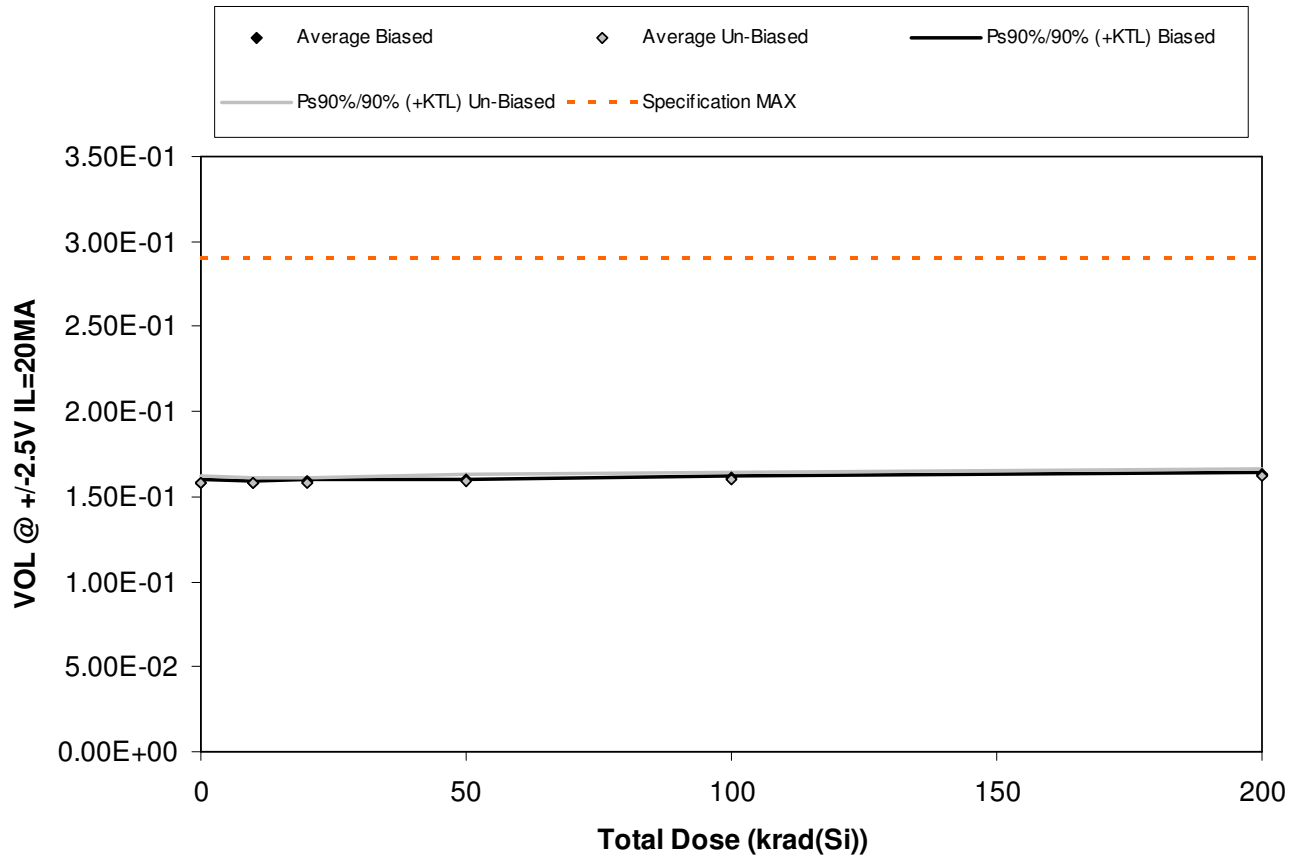


Figure 5.14. Plot of VOL @ +/-2.5V IL=20MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.14. Raw data for VOL @ +/-2.5V IL=20MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOL @ +/-2.5V IL=20MA Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	1.57E-01	1.58E-01	1.58E-01	1.60E-01	1.62E-01	1.64E-01
62	1.58E-01	1.58E-01	1.59E-01	1.60E-01	1.62E-01	1.64E-01
63	1.59E-01	1.59E-01	1.59E-01	1.60E-01	1.61E-01	1.63E-01
64	1.58E-01	1.58E-01	1.59E-01	1.60E-01	1.61E-01	1.63E-01
65	1.59E-01	1.58E-01	1.59E-01	1.60E-01	1.61E-01	1.63E-01
66	1.56E-01	1.57E-01	1.57E-01	1.58E-01	1.59E-01	1.61E-01
67	1.60E-01	1.60E-01	1.60E-01	1.61E-01	1.63E-01	1.64E-01
68	1.58E-01	1.58E-01	1.58E-01	1.61E-01	1.61E-01	1.62E-01
69	1.58E-01	1.58E-01	1.58E-01	1.59E-01	1.60E-01	1.63E-01
70	1.58E-01	1.58E-01	1.58E-01	1.59E-01	1.60E-01	1.61E-01
71	1.58E-01	1.57E-01	1.57E-01	1.57E-01	1.57E-01	1.58E-01
72	1.60E-01	1.59E-01	1.58E-01	1.58E-01	1.59E-01	1.59E-01
Biased Statistics						
Average Biased	1.58E-01	1.58E-01	1.59E-01	1.60E-01	1.61E-01	1.63E-01
Std Dev Biased	7.56E-04	2.51E-04	4.06E-04	2.12E-04	5.08E-04	4.95E-04
Ps90%/90% (+KTL) Biased	1.60E-01	1.59E-01	1.60E-01	1.61E-01	1.63E-01	1.65E-01
Ps90%/90% (-KTL) Biased	1.56E-01	1.58E-01	1.58E-01	1.59E-01	1.60E-01	1.62E-01
Un-Biased Statistics						
Average Un-Biased	1.58E-01	1.58E-01	1.58E-01	1.60E-01	1.60E-01	1.62E-01
Std Dev Un-Biased	1.40E-03	1.15E-03	1.21E-03	1.43E-03	1.39E-03	1.29E-03
Ps90%/90% (+KTL) Un-Biased	1.62E-01	1.61E-01	1.62E-01	1.63E-01	1.64E-01	1.66E-01
Ps90%/90% (-KTL) Un-Biased	1.54E-01	1.55E-01	1.55E-01	1.56E-01	1.57E-01	1.59E-01
Specification MAX	2.90E-01	2.90E-01	2.90E-01	2.90E-01	2.90E-01	2.90E-01
Status	PASS	PASS	PASS	PASS	PASS	PASS

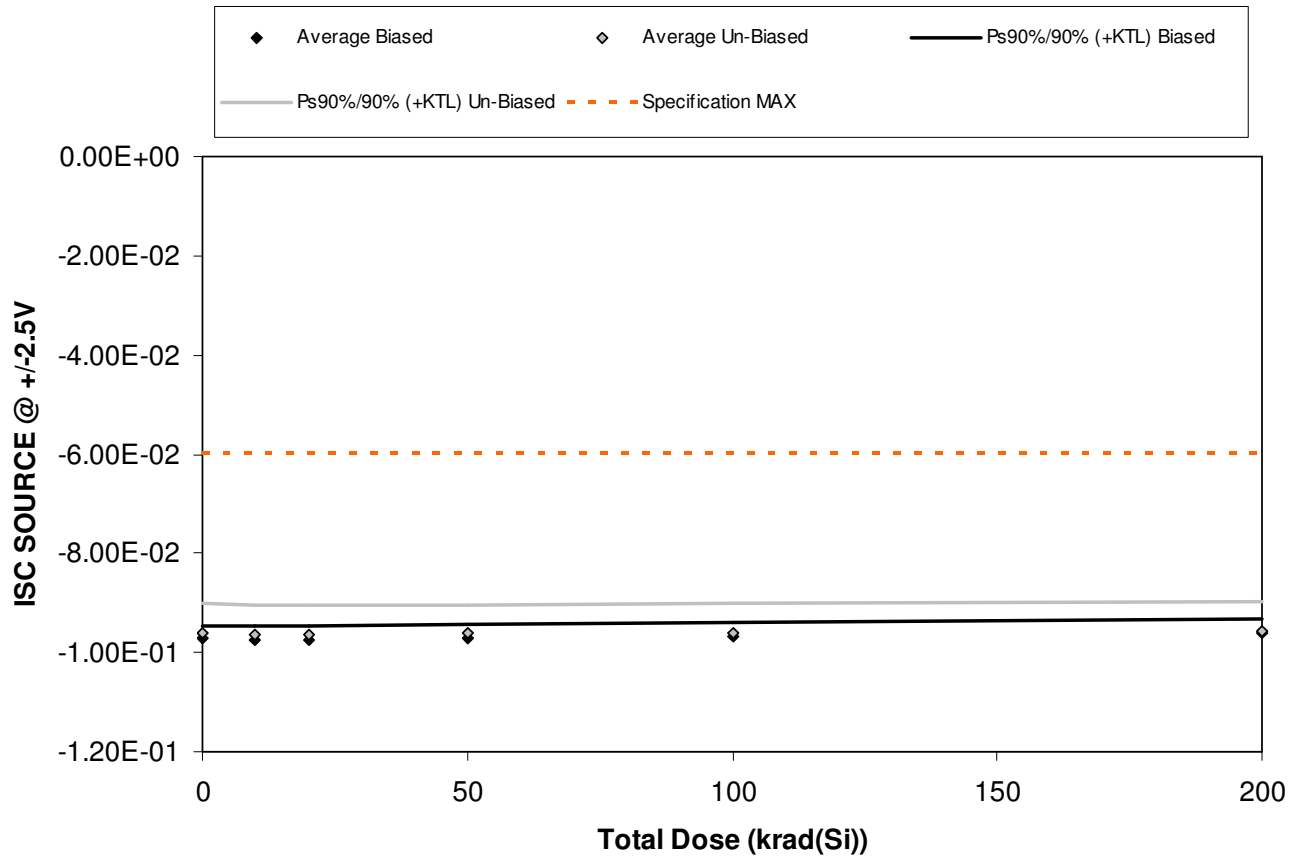


Figure 5.15. Plot of ISC SOURCE @ +/-2.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.15. Raw data for ISC SOURCE @ +/-2.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

ISC SOURCE @ +/-2.5V		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	-9.75E-02	-9.73E-02	-9.74E-02	-9.69E-02	-9.65E-02	-9.61E-02
	62	-9.64E-02	-9.66E-02	-9.65E-02	-9.61E-02	-9.58E-02	-9.50E-02
	63	-9.76E-02	-9.80E-02	-9.80E-02	-9.78E-02	-9.76E-02	-9.71E-02
	64	-9.84E-02	-9.86E-02	-9.85E-02	-9.84E-02	-9.81E-02	-9.73E-02
	65	-9.62E-02	-9.63E-02	-9.62E-02	-9.61E-02	-9.58E-02	-9.53E-02
	66	-9.34E-02	-9.36E-02	-9.36E-02	-9.36E-02	-9.34E-02	-9.30E-02
	67	-9.82E-02	-9.87E-02	-9.86E-02	-9.85E-02	-9.83E-02	-9.80E-02
	68	-9.75E-02	-9.77E-02	-9.77E-02	-9.71E-02	-9.74E-02	-9.71E-02
	69	-9.38E-02	-9.43E-02	-9.44E-02	-9.43E-02	-9.41E-02	-9.37E-02
	70	-9.71E-02	-9.73E-02	-9.73E-02	-9.72E-02	-9.71E-02	-9.67E-02
	71	-9.58E-02	-9.61E-02	-9.62E-02	-9.61E-02	-9.62E-02	-9.61E-02
	72	-9.92E-02	-9.98E-02	-9.98E-02	-9.99E-02	-9.97E-02	-9.96E-02
Biased Statistics							
	Average Biased	-9.72E-02	-9.74E-02	-9.73E-02	-9.70E-02	-9.68E-02	-9.62E-02
	Std Dev Biased	9.28E-04	9.58E-04	9.77E-04	1.01E-03	1.04E-03	1.02E-03
	Ps90%/90% (+KTL) Biased	-9.47E-02	-9.47E-02	-9.46E-02	-9.43E-02	-9.39E-02	-9.33E-02
	Ps90%/90% (-KTL) Biased	-9.98E-02	-1.00E-01	-1.00E-01	-9.98E-02	-9.96E-02	-9.90E-02
Un-Biased Statistics							
	Average Un-Biased	-9.60E-02	-9.63E-02	-9.63E-02	-9.61E-02	-9.61E-02	-9.57E-02
	Std Dev Un-Biased	2.21E-03	2.20E-03	2.19E-03	2.11E-03	2.18E-03	2.19E-03
	Ps90%/90% (+KTL) Un-Biased	-8.99E-02	-9.03E-02	-9.03E-02	-9.04E-02	-9.01E-02	-8.97E-02
	Ps90%/90% (-KTL) Un-Biased	-1.02E-01	-1.02E-01	-1.02E-01	-1.02E-01	-1.02E-01	-1.02E-01
	Specification MAX	-6.00E-02	-6.00E-02	-6.00E-02	-6.00E-02	-6.00E-02	-6.00E-02
	Status	PASS	PASS	PASS	PASS	PASS	PASS

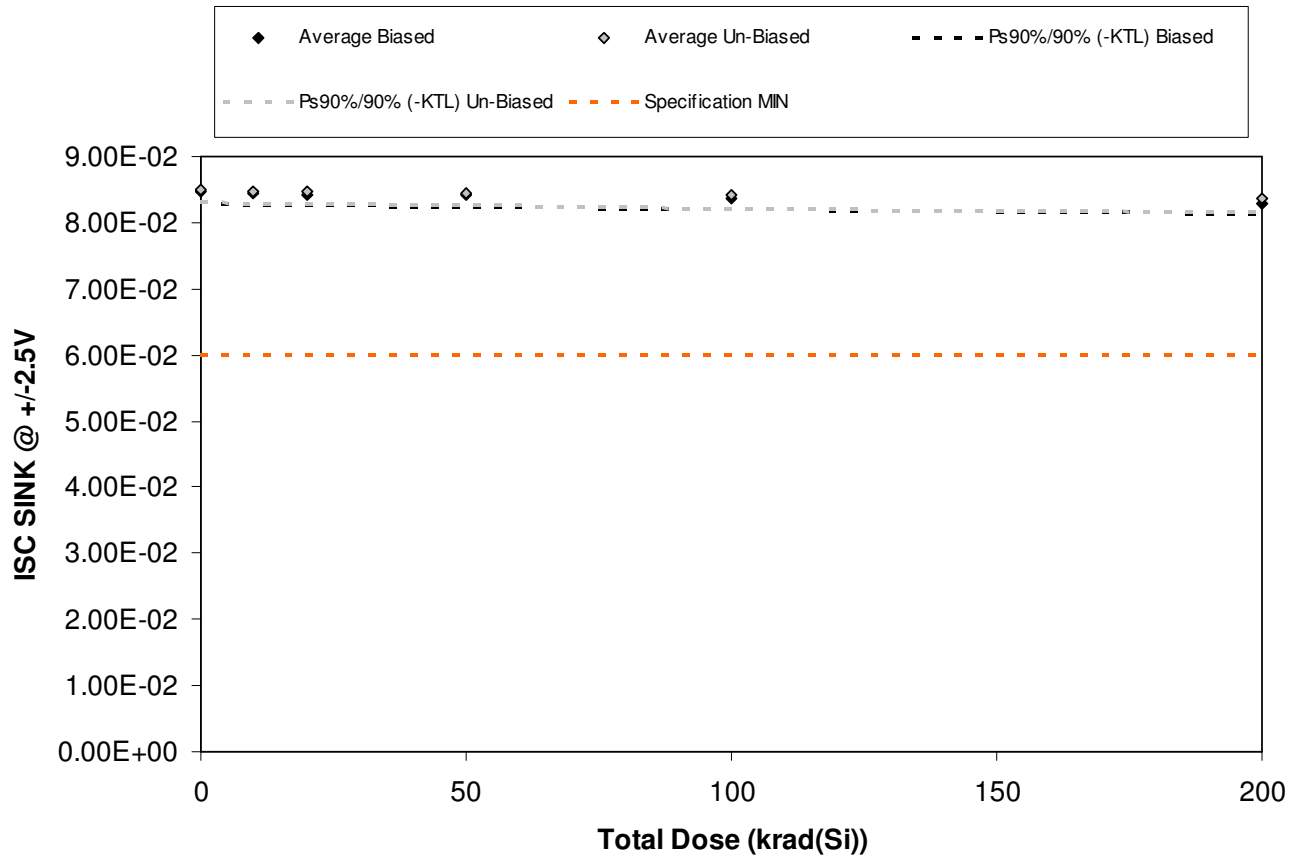


Figure 5.16. Plot of ISC SINK @ +/-2.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.16. Raw data for ISC SINK @ +/-2.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

ISC SINK @ +/-2.5V Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	8.51E-02	8.49E-02	8.48E-02	8.47E-02	8.43E-02	8.34E-02
62	8.54E-02	8.49E-02	8.49E-02	8.46E-02	8.40E-02	8.32E-02
63	8.47E-02	8.42E-02	8.41E-02	8.40E-02	8.36E-02	8.29E-02
64	8.48E-02	8.43E-02	8.43E-02	8.40E-02	8.36E-02	8.28E-02
65	8.38E-02	8.34E-02	8.34E-02	8.31E-02	8.27E-02	8.20E-02
66	8.58E-02	8.56E-02	8.55E-02	8.52E-02	8.49E-02	8.45E-02
67	8.40E-02	8.37E-02	8.37E-02	8.33E-02	8.29E-02	8.24E-02
68	8.50E-02	8.46E-02	8.46E-02	8.46E-02	8.40E-02	8.35E-02
69	8.55E-02	8.52E-02	8.50E-02	8.47E-02	8.44E-02	8.38E-02
70	8.51E-02	8.49E-02	8.48E-02	8.45E-02	8.42E-02	8.36E-02
71	8.44E-02	8.42E-02	8.41E-02	8.42E-02	8.42E-02	8.42E-02
72	8.48E-02	8.45E-02	8.45E-02	8.45E-02	8.45E-02	8.46E-02
Biased Statistics						
Average Biased	8.48E-02	8.43E-02	8.43E-02	8.41E-02	8.37E-02	8.29E-02
Std Dev Biased	6.21E-04	6.33E-04	5.96E-04	6.61E-04	6.10E-04	5.38E-04
Ps90%/90% (+KTL) Biased	8.65E-02	8.61E-02	8.59E-02	8.59E-02	8.53E-02	8.43E-02
Ps90%/90% (-KTL) Biased	8.31E-02	8.26E-02	8.26E-02	8.23E-02	8.20E-02	8.14E-02
Un-Biased Statistics						
Average Un-Biased	8.51E-02	8.48E-02	8.47E-02	8.45E-02	8.41E-02	8.36E-02
Std Dev Un-Biased	6.87E-04	7.21E-04	6.76E-04	7.29E-04	7.31E-04	7.44E-04
Ps90%/90% (+KTL) Un-Biased	8.70E-02	8.68E-02	8.66E-02	8.65E-02	8.61E-02	8.56E-02
Ps90%/90% (-KTL) Un-Biased	8.32E-02	8.28E-02	8.28E-02	8.25E-02	8.21E-02	8.15E-02
Specification MIN	6.00E-02	6.00E-02	6.00E-02	6.00E-02	6.00E-02	6.00E-02
Status	PASS	PASS	PASS	PASS	PASS	PASS

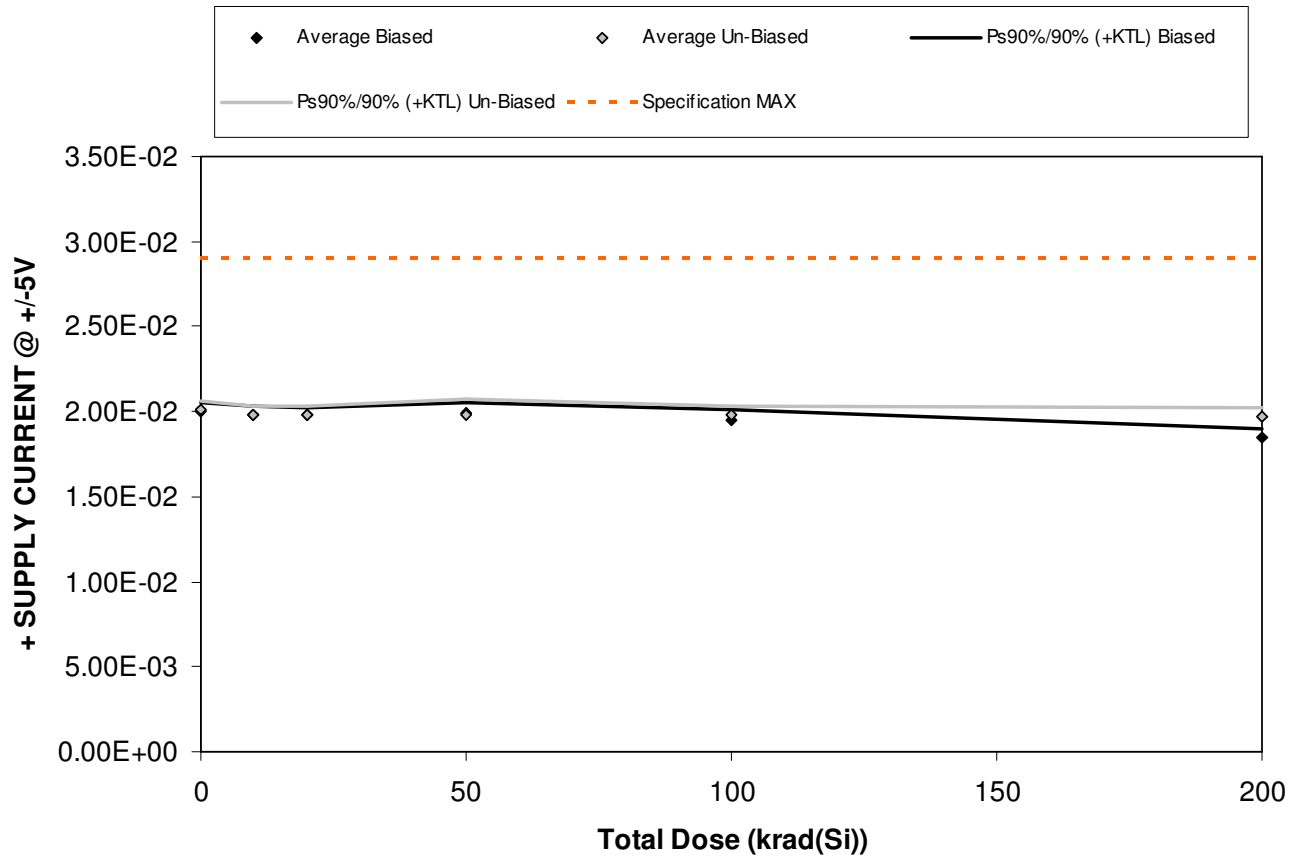


Figure 5.17. Plot of + SUPPLY CURRENT @ +/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.17. Raw data for + SUPPLY CURRENT @ +/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

+ SUPPLY CURRENT @ +/-5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device 61	2.00E-02	2.01E-02	1.99E-02	2.02E-02	1.97E-02	1.87E-02
62	2.02E-02	2.00E-02	1.99E-02	2.00E-02	1.94E-02	1.86E-02
63	2.02E-02	1.98E-02	1.98E-02	1.99E-02	1.97E-02	1.85E-02
64	2.01E-02	1.98E-02	1.98E-02	1.99E-02	1.96E-02	1.83E-02
65	1.98E-02	1.95E-02	1.96E-02	1.96E-02	1.92E-02	1.82E-02
66	2.01E-02	1.99E-02	1.99E-02	1.98E-02	1.99E-02	1.99E-02
67	1.99E-02	1.96E-02	1.96E-02	1.95E-02	1.96E-02	1.95E-02
68	2.03E-02	2.00E-02	2.00E-02	2.03E-02	2.00E-02	1.98E-02
69	2.03E-02	2.00E-02	2.00E-02	1.99E-02	1.99E-02	1.98E-02
70	1.99E-02	1.97E-02	1.96E-02	1.96E-02	1.95E-02	1.94E-02
71	2.00E-02	1.97E-02	1.97E-02	1.98E-02	1.98E-02	1.98E-02
72	2.02E-02	1.99E-02	1.99E-02	1.99E-02	1.99E-02	2.00E-02
Biased Statistics						
Average Biased	2.01E-02	1.98E-02	1.98E-02	1.99E-02	1.95E-02	1.85E-02
Std Dev Biased	1.77E-04	1.90E-04	1.34E-04	2.23E-04	2.21E-04	2.06E-04
Ps90%/90% (+KTL) Biased	2.06E-02	2.04E-02	2.02E-02	2.05E-02	2.01E-02	1.90E-02
Ps90%/90% (-KTL) Biased	1.96E-02	1.93E-02	1.95E-02	1.93E-02	1.89E-02	1.79E-02
Un-Biased Statistics						
Average Un-Biased	2.01E-02	1.98E-02	1.98E-02	1.98E-02	1.98E-02	1.97E-02
Std Dev Un-Biased	2.13E-04	1.92E-04	1.96E-04	3.10E-04	1.94E-04	2.09E-04
Ps90%/90% (+KTL) Un-Biased	2.07E-02	2.04E-02	2.04E-02	2.07E-02	2.03E-02	2.02E-02
Ps90%/90% (-KTL) Un-Biased	1.95E-02	1.93E-02	1.93E-02	1.90E-02	1.92E-02	1.91E-02
Specification MAX	2.90E-02	2.90E-02	2.90E-02	2.90E-02	2.90E-02	2.90E-02
Status	PASS	PASS	PASS	PASS	PASS	PASS

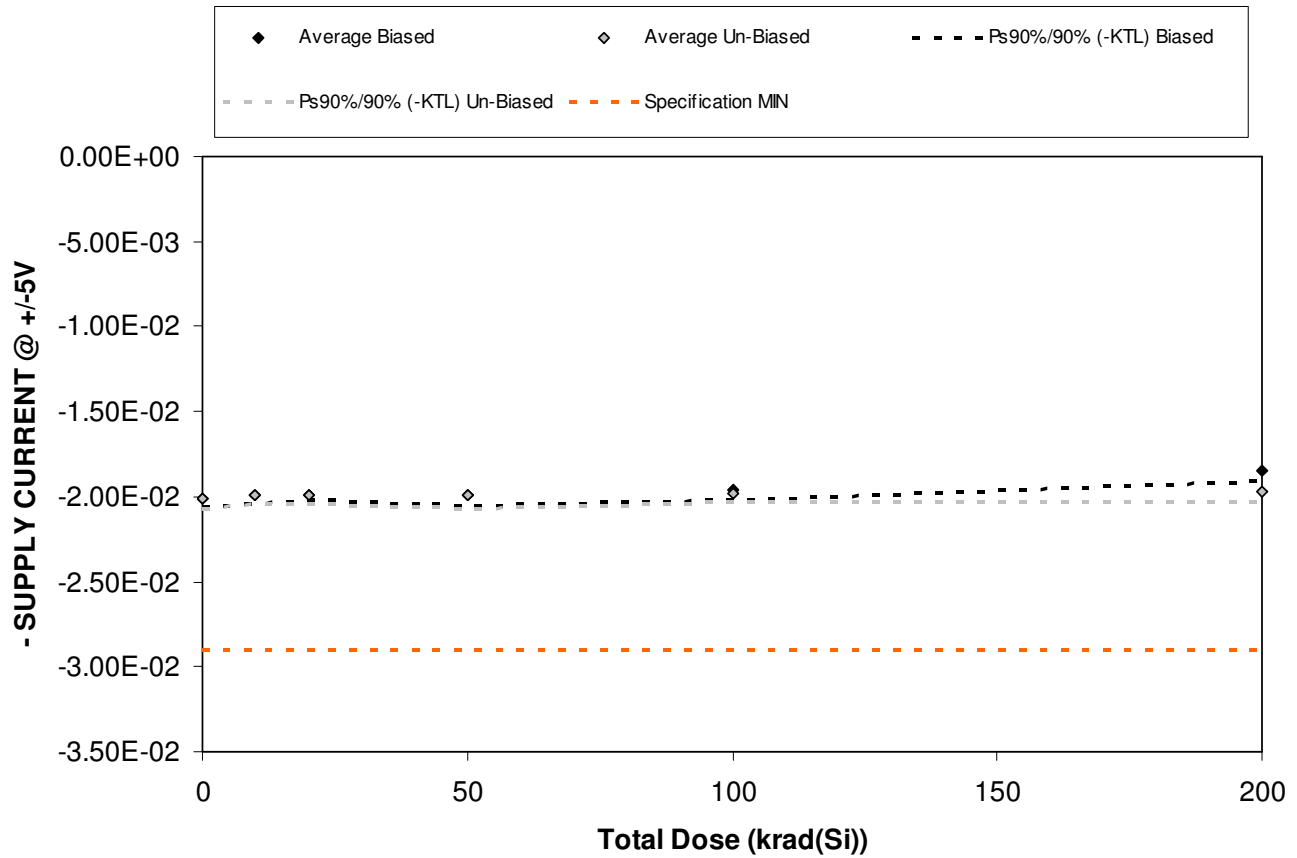


Figure 5.18. Plot of - SUPPLY CURRENT @ +/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.18. Raw data for - SUPPLY CURRENT @ +/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

- SUPPLY CURRENT @ +/-5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device 61	-2.01E-02	-2.01E-02	-2.00E-02	-2.02E-02	-1.98E-02	-1.87E-02
62	-2.03E-02	-2.00E-02	-2.00E-02	-2.01E-02	-1.95E-02	-1.87E-02
63	-2.03E-02	-1.99E-02	-1.99E-02	-1.99E-02	-1.97E-02	-1.86E-02
64	-2.01E-02	-1.99E-02	-1.99E-02	-1.99E-02	-1.96E-02	-1.83E-02
65	-1.99E-02	-1.96E-02	-1.97E-02	-1.96E-02	-1.92E-02	-1.83E-02
66	-2.02E-02	-1.99E-02	-1.99E-02	-1.99E-02	-1.99E-02	-1.99E-02
67	-1.99E-02	-1.96E-02	-1.97E-02	-1.96E-02	-1.96E-02	-1.95E-02
68	-2.03E-02	-2.01E-02	-2.01E-02	-2.04E-02	-2.00E-02	-1.98E-02
69	-2.04E-02	-2.00E-02	-2.00E-02	-2.00E-02	-2.00E-02	-1.99E-02
70	-1.99E-02	-1.97E-02	-1.97E-02	-1.97E-02	-1.96E-02	-1.95E-02
71	-2.01E-02	-1.98E-02	-1.98E-02	-1.98E-02	-1.98E-02	-1.99E-02
72	-2.03E-02	-1.99E-02	-2.00E-02	-1.99E-02	-2.00E-02	-2.01E-02
Biased Statistics						
Average Biased	-2.01E-02	-1.99E-02	-1.99E-02	-2.00E-02	-1.96E-02	-1.85E-02
Std Dev Biased	1.74E-04	1.91E-04	1.33E-04	2.20E-04	2.25E-04	2.05E-04
Ps90%/90% (+KTL) Biased	-1.96E-02	-1.94E-02	-1.95E-02	-1.94E-02	-1.89E-02	-1.79E-02
Ps90%/90% (-KTL) Biased	-2.06E-02	-2.04E-02	-2.02E-02	-2.06E-02	-2.02E-02	-1.91E-02
Un-Biased Statistics						
Average Un-Biased	-2.01E-02	-1.99E-02	-1.99E-02	-1.99E-02	-1.98E-02	-1.97E-02
Std Dev Un-Biased	2.19E-04	1.93E-04	1.93E-04	3.12E-04	1.97E-04	2.16E-04
Ps90%/90% (+KTL) Un-Biased	-1.95E-02	-1.94E-02	-1.94E-02	-1.91E-02	-1.93E-02	-1.91E-02
Ps90%/90% (-KTL) Un-Biased	-2.07E-02	-2.04E-02	-2.04E-02	-2.08E-02	-2.04E-02	-2.03E-02
Specification MIN	-2.90E-02	-2.90E-02	-2.90E-02	-2.90E-02	-2.90E-02	-2.90E-02
Status	PASS	PASS	PASS	PASS	PASS	PASS

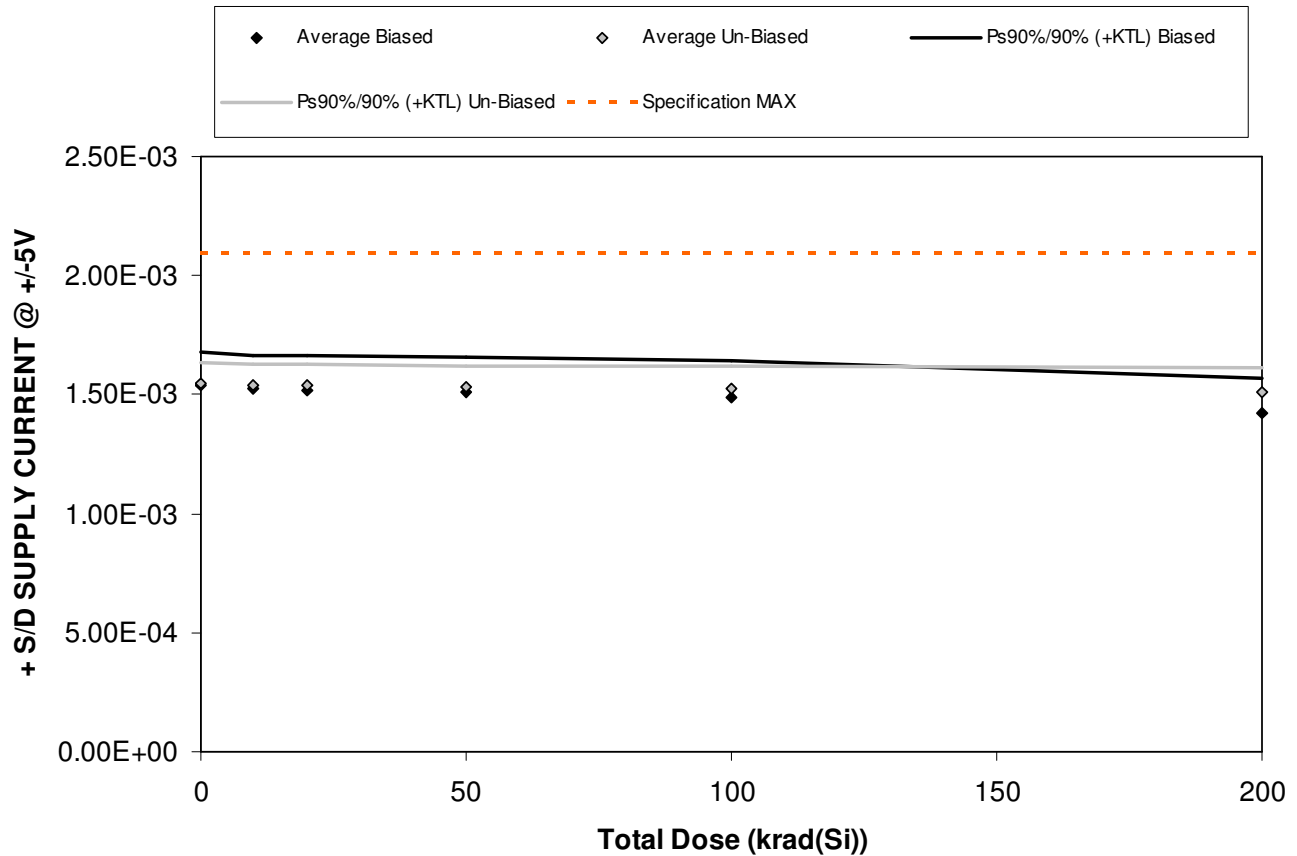


Figure 5.19. Plot of + S/D SUPPLY CURRENT @ +/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.19. Raw data for + S/D SUPPLY CURRENT @ +/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

+ S/D SUPPLY CURRENT @ +/-5V	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.51E-03	1.50E-03	1.49E-03	1.48E-03	1.46E-03	1.40E-03
62	1.54E-03	1.52E-03	1.51E-03	1.50E-03	1.47E-03	1.42E-03
63	1.53E-03	1.52E-03	1.51E-03	1.50E-03	1.48E-03	1.42E-03
64	1.63E-03	1.61E-03	1.61E-03	1.60E-03	1.58E-03	1.51E-03
65	1.49E-03	1.48E-03	1.47E-03	1.46E-03	1.43E-03	1.38E-03
66	1.60E-03	1.59E-03	1.59E-03	1.59E-03	1.58E-03	1.57E-03
67	1.53E-03	1.52E-03	1.52E-03	1.52E-03	1.51E-03	1.50E-03
68	1.52E-03	1.52E-03	1.51E-03	1.51E-03	1.50E-03	1.48E-03
69	1.56E-03	1.55E-03	1.55E-03	1.55E-03	1.54E-03	1.52E-03
70	1.52E-03	1.51E-03	1.51E-03	1.51E-03	1.50E-03	1.48E-03
71	1.51E-03	1.51E-03	1.50E-03	1.51E-03	1.51E-03	1.51E-03
72	1.56E-03	1.55E-03	1.55E-03	1.55E-03	1.55E-03	1.56E-03
Biased Statistics						
Average Biased	1.54E-03	1.53E-03	1.52E-03	1.51E-03	1.48E-03	1.42E-03
Std Dev Biased	5.20E-05	5.16E-05	5.37E-05	5.32E-05	5.64E-05	5.19E-05
Ps90%/90% (+KTL) Biased	1.68E-03	1.67E-03	1.66E-03	1.65E-03	1.64E-03	1.57E-03
Ps90%/90% (-KTL) Biased	1.40E-03	1.38E-03	1.37E-03	1.36E-03	1.33E-03	1.28E-03
Un-Biased Statistics						
Average Un-Biased	1.54E-03	1.54E-03	1.54E-03	1.53E-03	1.53E-03	1.51E-03
Std Dev Un-Biased	3.34E-05	3.33E-05	3.33E-05	3.21E-05	3.40E-05	3.63E-05
Ps90%/90% (+KTL) Un-Biased	1.64E-03	1.63E-03	1.63E-03	1.62E-03	1.62E-03	1.61E-03
Ps90%/90% (-KTL) Un-Biased	1.45E-03	1.45E-03	1.45E-03	1.45E-03	1.43E-03	1.41E-03
Specification MAX	2.10E-03	2.10E-03	2.10E-03	2.10E-03	2.10E-03	2.10E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS

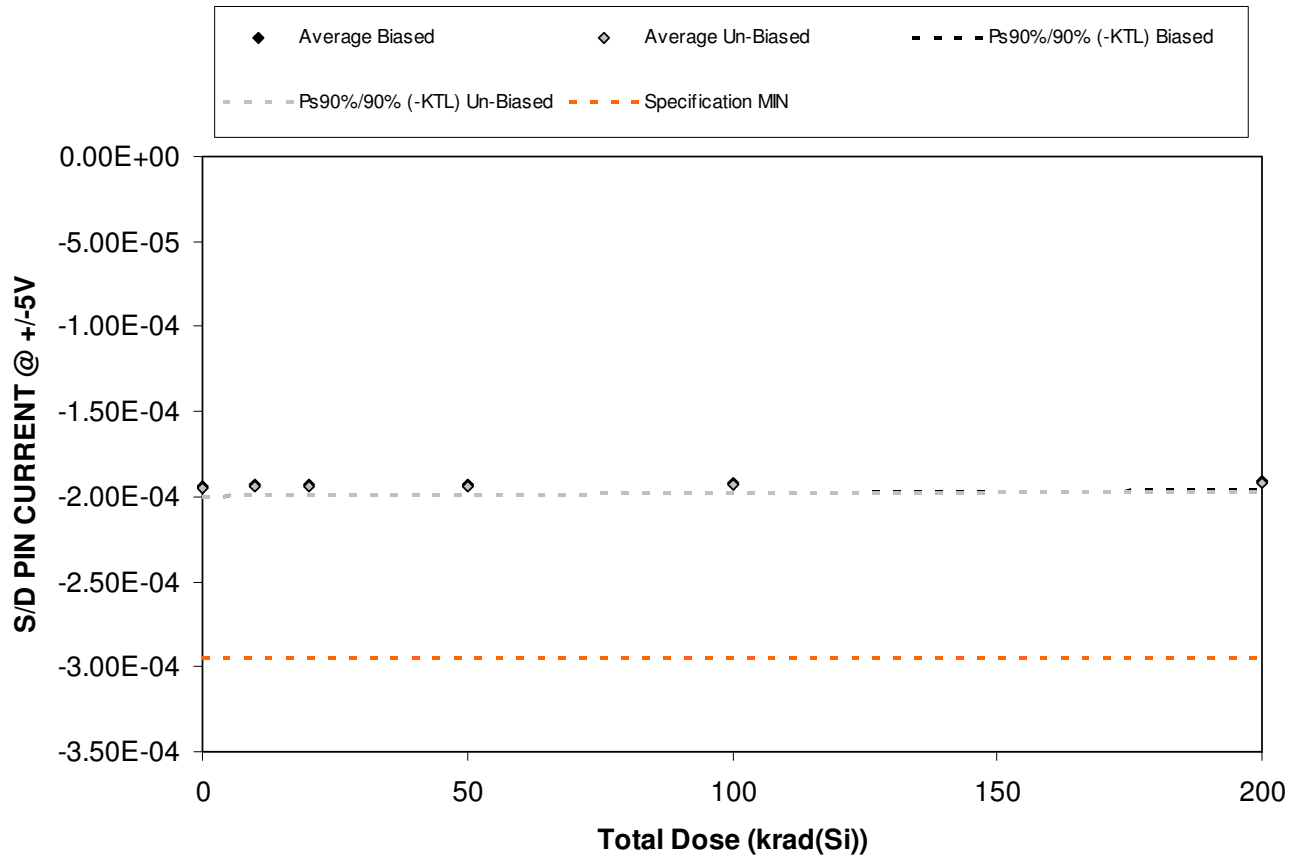


Figure 5.20. Plot of S/D PIN CURRENT @ +/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.20. Raw data for S/D PIN CURRENT @ +/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

S/D PIN CURRENT @ +/-5V Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	-1.93E-04	-1.93E-04	-1.92E-04	-1.92E-04	-1.92E-04	-1.90E-04
62	-1.97E-04	-1.97E-04	-1.96E-04	-1.96E-04	-1.95E-04	-1.94E-04
63	-1.94E-04	-1.93E-04	-1.93E-04	-1.92E-04	-1.92E-04	-1.91E-04
64	-1.94E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.92E-04
65	-1.92E-04	-1.91E-04	-1.91E-04	-1.91E-04	-1.90E-04	-1.89E-04
66	-1.94E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.92E-04	-1.92E-04
67	-1.95E-04	-1.94E-04	-1.94E-04	-1.94E-04	-1.93E-04	-1.92E-04
68	-1.93E-04	-1.92E-04	-1.92E-04	-1.92E-04	-1.91E-04	-1.90E-04
69	-1.98E-04	-1.97E-04	-1.97E-04	-1.97E-04	-1.96E-04	-1.95E-04
70	-1.94E-04	-1.93E-04	-1.93E-04	-1.92E-04	-1.92E-04	-1.91E-04
71	-1.92E-04	-1.92E-04	-1.92E-04	-1.92E-04	-1.92E-04	-1.92E-04
72	-1.97E-04	-1.96E-04	-1.96E-04	-1.96E-04	-1.96E-04	-1.96E-04
Biased Statistics						
Average Biased	-1.94E-04	-1.93E-04	-1.93E-04	-1.93E-04	-1.92E-04	-1.91E-04
Std Dev Biased	2.06E-06	2.03E-06	2.00E-06	2.09E-06	1.96E-06	1.95E-06
Ps90%/90% (+KTL) Biased	-1.88E-04	-1.88E-04	-1.88E-04	-1.87E-04	-1.87E-04	-1.86E-04
Ps90%/90% (-KTL) Biased	-2.00E-04	-1.99E-04	-1.99E-04	-1.99E-04	-1.98E-04	-1.96E-04
Un-Biased Statistics						
Average Un-Biased	-1.95E-04	-1.94E-04	-1.94E-04	-1.94E-04	-1.93E-04	-1.92E-04
Std Dev Un-Biased	2.07E-06	2.00E-06	2.01E-06	1.87E-06	1.99E-06	1.97E-06
Ps90%/90% (+KTL) Un-Biased	-1.89E-04	-1.89E-04	-1.88E-04	-1.88E-04	-1.88E-04	-1.87E-04
Ps90%/90% (-KTL) Un-Biased	-2.00E-04	-1.99E-04	-1.99E-04	-1.99E-04	-1.98E-04	-1.98E-04
Specification MIN	-2.95E-04	-2.95E-04	-2.95E-04	-2.95E-04	-2.95E-04	-2.95E-04
Status	PASS	PASS	PASS	PASS	PASS	PASS

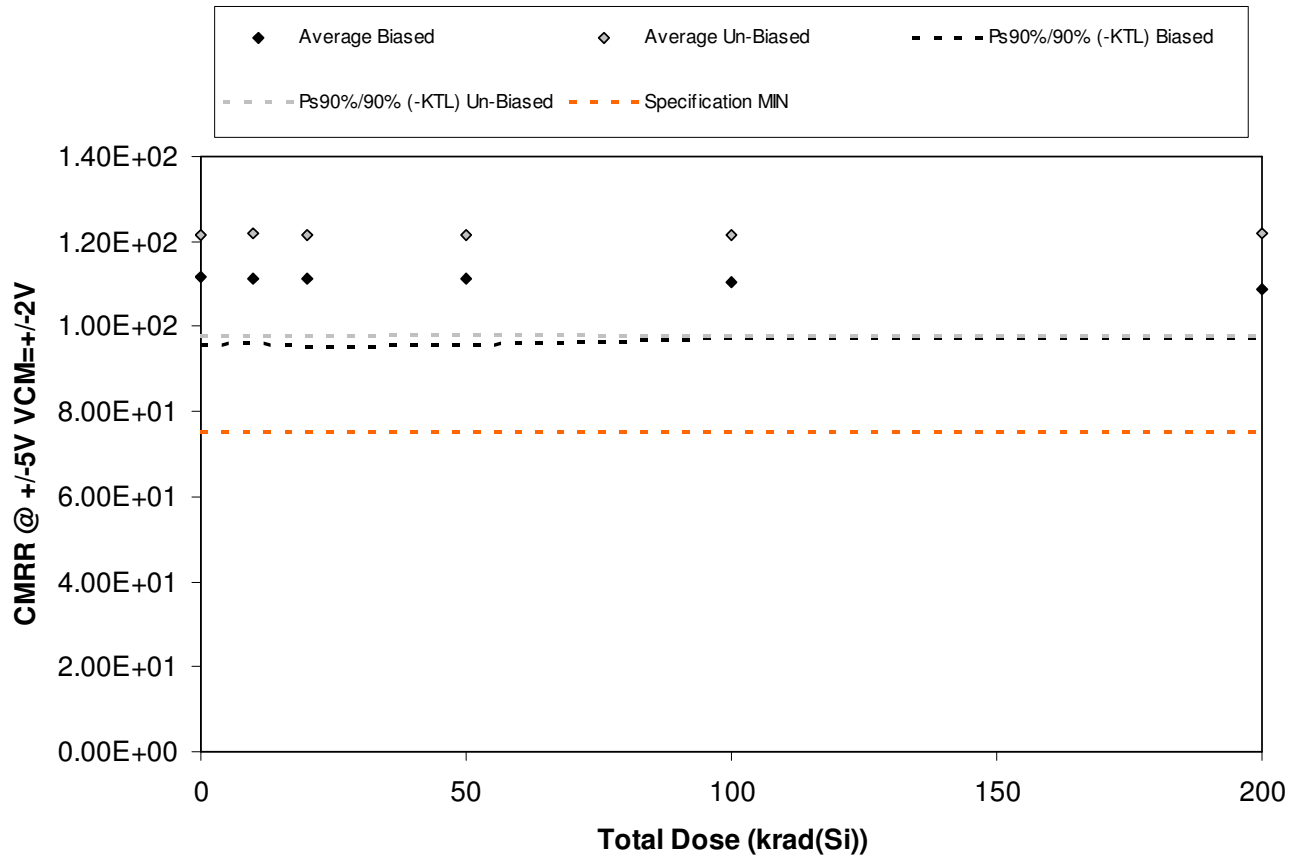


Figure 5.21. Plot of CMRR @ +/-5V VCM=+/-2V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.21. Raw data for CMRR @ +/-5V VCM=+/-2V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

CMRR @ +/-5V VCM=+/-2V Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	1.13E+02	1.13E+02	1.13E+02	1.13E+02	1.12E+02	1.10E+02
62	1.21E+02	1.20E+02	1.20E+02	1.20E+02	1.18E+02	1.13E+02
63	1.06E+02	1.06E+02	1.06E+02	1.06E+02	1.06E+02	1.04E+02
64	1.11E+02	1.11E+02	1.11E+02	1.11E+02	1.11E+02	1.13E+02
65	1.07E+02	1.06E+02	1.06E+02	1.07E+02	1.06E+02	1.04E+02
66	1.06E+02	1.06E+02	1.06E+02	1.06E+02	1.06E+02	1.07E+02
67	1.29E+02	1.27E+02	1.27E+02	1.26E+02	1.26E+02	1.24E+02
68	1.23E+02	1.24E+02	1.24E+02	1.24E+02	1.24E+02	1.28E+02
69	1.24E+02	1.24E+02	1.24E+02	1.24E+02	1.23E+02	1.23E+02
70	1.26E+02	1.28E+02	1.26E+02	1.26E+02	1.28E+02	1.27E+02
71	1.10E+02	1.10E+02	1.10E+02	1.10E+02	1.10E+02	1.10E+02
72	1.26E+02	1.25E+02	1.25E+02	1.25E+02	1.25E+02	1.26E+02
Biased Statistics						
Average Biased	1.11E+02	1.11E+02	1.11E+02	1.11E+02	1.11E+02	1.09E+02
Std Dev Biased	5.83E+00	5.59E+00	5.83E+00	5.77E+00	4.82E+00	4.29E+00
Ps90%/90% (+KTL) Biased	1.27E+02	1.27E+02	1.27E+02	1.27E+02	1.24E+02	1.21E+02
Ps90%/90% (-KTL) Biased	9.55E+01	9.60E+01	9.54E+01	9.56E+01	9.73E+01	9.71E+01
Un-Biased Statistics						
Average Un-Biased	1.22E+02	1.22E+02	1.22E+02	1.22E+02	1.21E+02	1.22E+02
Std Dev Un-Biased	8.76E+00	8.86E+00	8.66E+00	8.53E+00	8.58E+00	8.81E+00
Ps90%/90% (+KTL) Un-Biased	1.46E+02	1.46E+02	1.45E+02	1.45E+02	1.45E+02	1.46E+02
Ps90%/90% (-KTL) Un-Biased	9.76E+01	9.76E+01	9.79E+01	9.81E+01	9.79E+01	9.76E+01
Specification MIN	7.50E+01	7.50E+01	7.50E+01	7.50E+01	7.50E+01	7.50E+01
Status	PASS	PASS	PASS	PASS	PASS	PASS

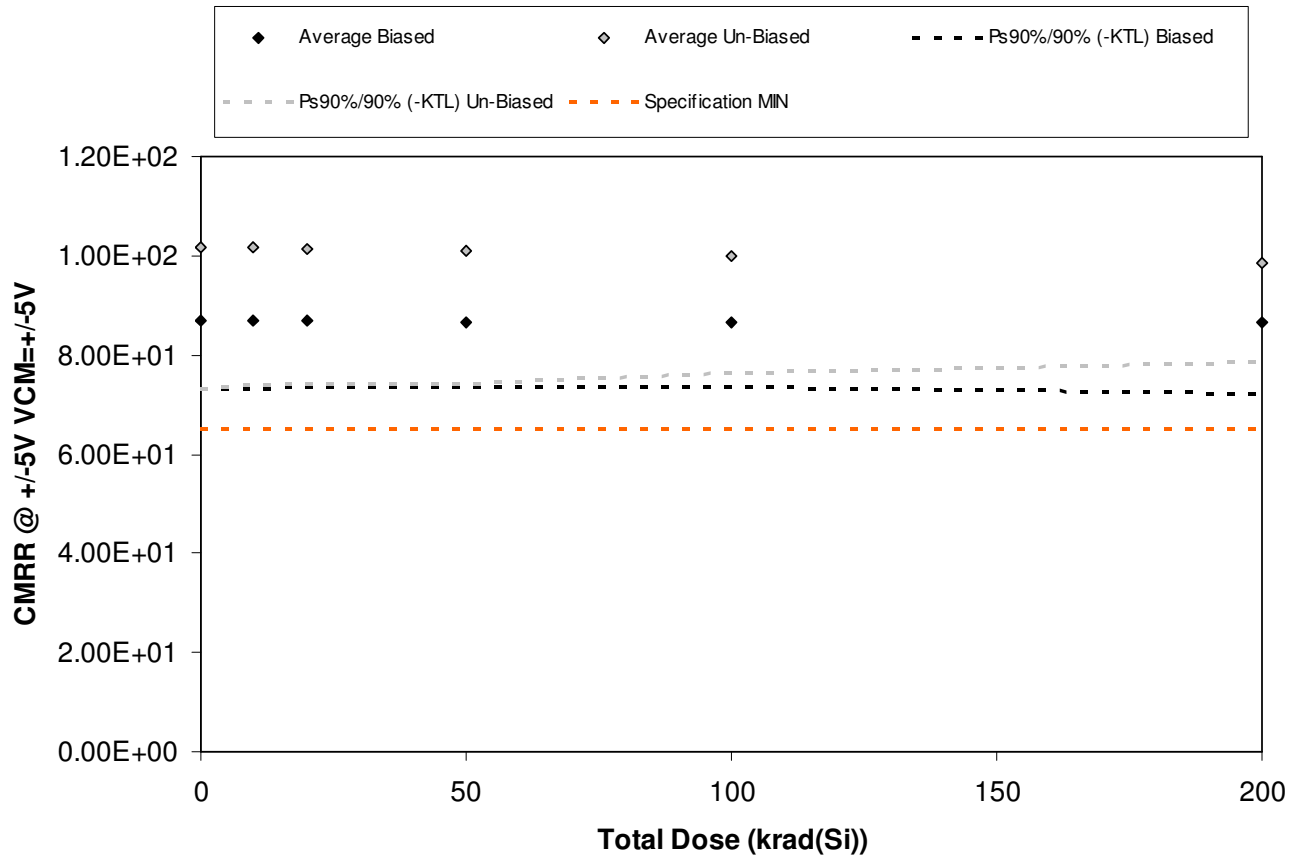


Figure 5.22. Plot of CMRR @ +/-5V VCM=+/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.22. Raw data for CMRR @ +/-5V VCM=+/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

CMRR @ +/-5V VCM=+/-5V		Total Dose (krad(Si))					
Device		0	10	20	50	100	200
61	8.52E+01	8.52E+01	8.52E+01	8.52E+01	8.52E+01	8.52E+01	8.49E+01
62	8.75E+01	8.75E+01	8.75E+01	8.75E+01	8.74E+01	8.72E+01	8.65E+01
63	8.18E+01	8.19E+01	8.19E+01	8.19E+01	8.19E+01	8.18E+01	8.15E+01
64	9.48E+01	9.48E+01	9.47E+01	9.46E+01	9.45E+01	9.45E+01	9.52E+01
65	8.44E+01	8.44E+01	8.44E+01	8.45E+01	8.44E+01	8.44E+01	8.40E+01
66	8.89E+01	8.90E+01	8.89E+01	8.89E+01	8.89E+01	8.88E+01	8.86E+01
67	9.47E+01	9.47E+01	9.46E+01	9.43E+01	9.39E+01	9.32E+01	9.32E+01
68	1.15E+02	1.15E+02	1.14E+02	1.14E+02	1.10E+02	1.06E+02	1.06E+02
69	1.08E+02	1.07E+02	1.07E+02	1.06E+02	1.05E+02	1.03E+02	1.03E+02
70	1.03E+02	1.03E+02	1.03E+02	1.02E+02	1.02E+02	1.01E+02	1.01E+02
71	8.83E+01	8.84E+01	8.84E+01	8.84E+01	8.84E+01	8.84E+01	8.84E+01
72	9.86E+01	9.88E+01	9.88E+01	9.88E+01	9.88E+01	9.88E+01	9.87E+01
Biased Statistics							
Average Biased	8.68E+01	8.68E+01	8.68E+01	8.67E+01	8.66E+01	8.64E+01	8.64E+01
Std Dev Biased	4.95E+00	4.92E+00	4.88E+00	4.84E+00	4.83E+00	5.26E+00	5.26E+00
Ps90%/90% (+KTL) Biased	1.00E+02	1.00E+02	1.00E+02	1.00E+02	9.99E+01	1.01E+02	1.01E+02
Ps90%/90% (-KTL) Biased	7.32E+01	7.33E+01	7.34E+01	7.34E+01	7.34E+01	7.20E+01	7.20E+01
Un-Biased Statistics							
Average Un-Biased	1.02E+02	1.02E+02	1.01E+02	1.01E+02	9.98E+01	9.84E+01	9.84E+01
Std Dev Un-Biased	1.04E+01	1.02E+01	9.88E+00	9.75E+00	8.54E+00	7.25E+00	7.25E+00
Ps90%/90% (+KTL) Un-Biased	1.31E+02	1.30E+02	1.28E+02	1.28E+02	1.23E+02	1.18E+02	1.18E+02
Ps90%/90% (-KTL) Un-Biased	7.32E+01	7.38E+01	7.43E+01	7.43E+01	7.64E+01	7.85E+01	7.85E+01
Specification MIN	6.50E+01	6.50E+01	6.50E+01	6.50E+01	6.50E+01	6.50E+01	6.50E+01
Status	PASS	PASS	PASS	PASS	PASS	PASS	PASS

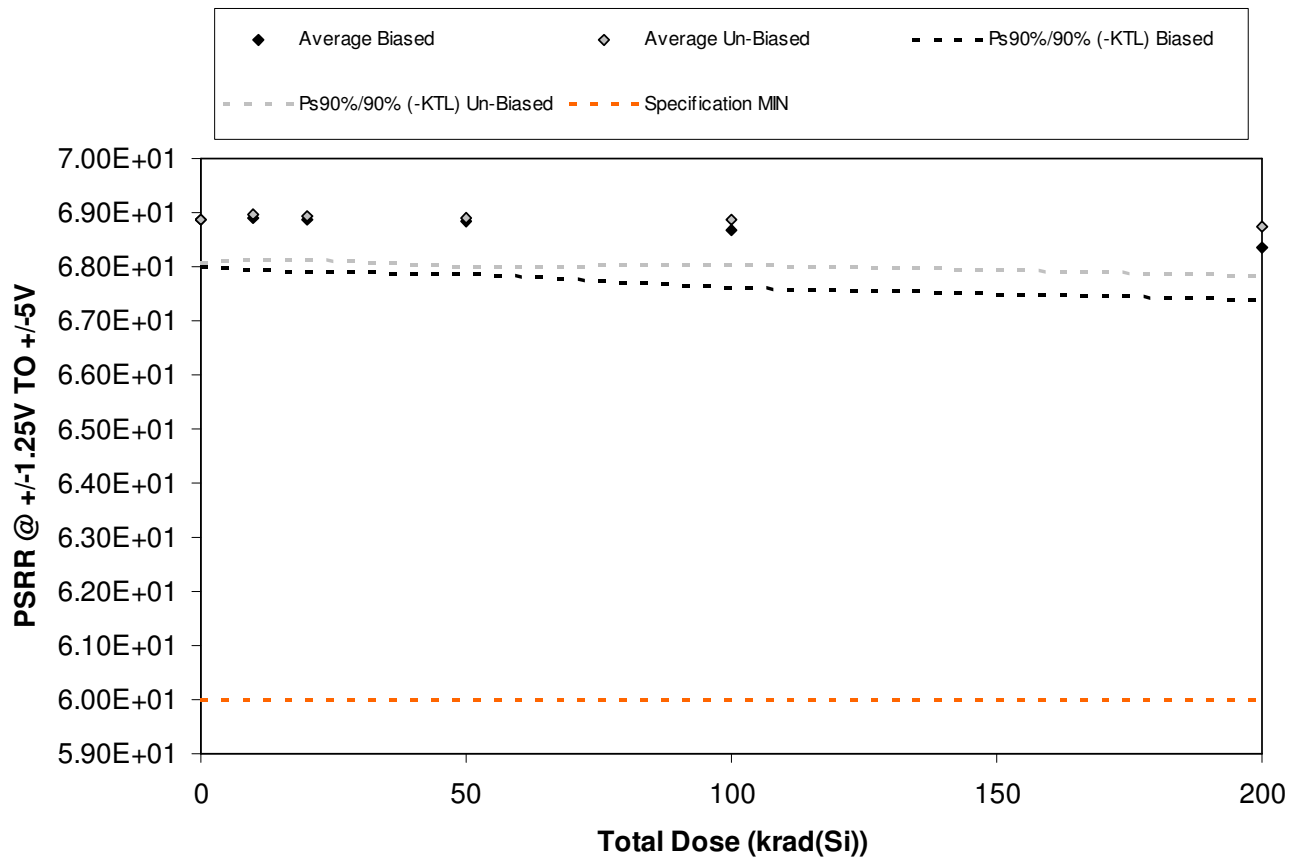


Figure 5.23. Plot of PSRR @ +/-1.25V TO +/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.23. Raw data for PSRR @ +/-1.25V TO +/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

PSRR @ +/-1.25V TO +/-5V		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	6.86E+01	6.86E+01	6.86E+01	6.85E+01	6.83E+01	6.81E+01
	62	6.90E+01	6.90E+01	6.90E+01	6.89E+01	6.87E+01	6.84E+01
	63	6.93E+01	6.94E+01	6.94E+01	6.94E+01	6.93E+01	6.89E+01
	64	6.89E+01	6.89E+01	6.89E+01	6.89E+01	6.87E+01	6.83E+01
	65	6.85E+01	6.86E+01	6.85E+01	6.85E+01	6.84E+01	6.80E+01
	66	6.93E+01	6.94E+01	6.94E+01	6.94E+01	6.94E+01	6.93E+01
	67	6.89E+01	6.90E+01	6.90E+01	6.89E+01	6.89E+01	6.87E+01
	68	6.87E+01	6.88E+01	6.88E+01	6.86E+01	6.87E+01	6.85E+01
	69	6.89E+01	6.90E+01	6.90E+01	6.90E+01	6.89E+01	6.88E+01
	70	6.86E+01	6.86E+01	6.86E+01	6.86E+01	6.86E+01	6.84E+01
	71	6.92E+01	6.93E+01	6.93E+01	6.93E+01	6.93E+01	6.93E+01
	72	6.87E+01	6.89E+01	6.89E+01	6.89E+01	6.89E+01	6.88E+01
Biased Statistics							
	Average Biased	6.89E+01	6.89E+01	6.89E+01	6.88E+01	6.87E+01	6.83E+01
	Std Dev Biased	3.16E-01	3.50E-01	3.55E-01	3.50E-01	3.87E-01	3.48E-01
	Ps90%/90% (+KTL) Biased	6.97E+01	6.99E+01	6.99E+01	6.98E+01	6.97E+01	6.93E+01
	Ps90%/90% (-KTL) Biased	6.80E+01	6.79E+01	6.79E+01	6.79E+01	6.76E+01	6.74E+01
Un-Biased Statistics							
	Average Un-Biased	6.89E+01	6.90E+01	6.90E+01	6.89E+01	6.89E+01	6.87E+01
	Std Dev Un-Biased	2.93E-01	3.06E-01	3.02E-01	3.27E-01	3.05E-01	3.31E-01
	Ps90%/90% (+KTL) Un-Biased	6.97E+01	6.98E+01	6.98E+01	6.98E+01	6.97E+01	6.96E+01
	Ps90%/90% (-KTL) Un-Biased	6.81E+01	6.81E+01	6.81E+01	6.80E+01	6.80E+01	6.78E+01
	Specification MIN	6.00E+01	6.00E+01	6.00E+01	6.00E+01	6.00E+01	6.00E+01
	Status	PASS	PASS	PASS	PASS	PASS	PASS

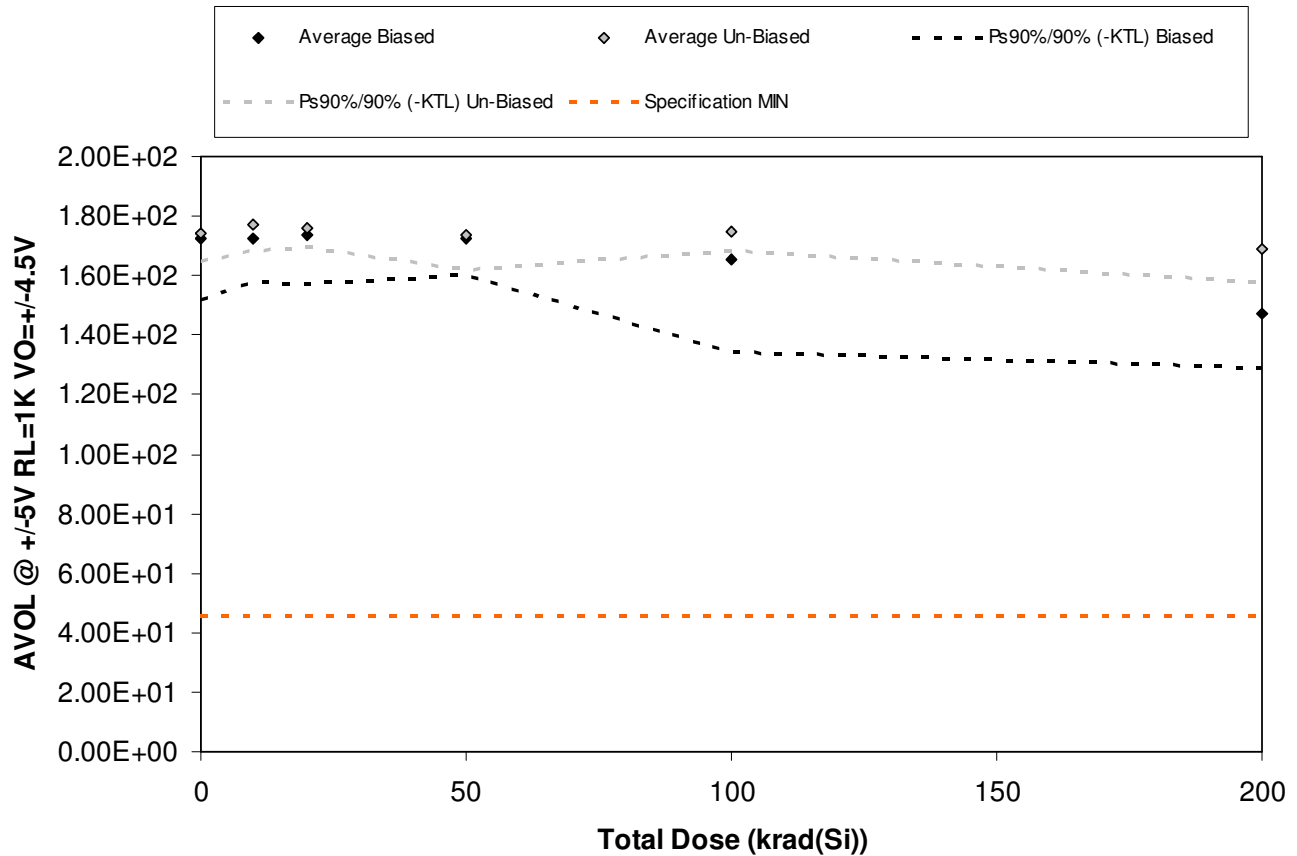


Figure 5.24. Plot of AVOL @ +/-5V RL=1K VO=+/-4.5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.24. Raw data for AVOL @ +/-5V RL=1K VO=+/-4.5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

AVOL @ +/-5V RL=1K VO=+/-4.5V Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	1.75E+02	1.69E+02	1.74E+02	1.70E+02	1.54E+02	1.43E+02
62	1.79E+02	1.77E+02	1.78E+02	1.75E+02	1.70E+02	1.46E+02
63	1.73E+02	1.76E+02	1.78E+02	1.76E+02	1.79E+02	1.59E+02
64	1.76E+02	1.76E+02	1.76E+02	1.77E+02	1.70E+02	1.44E+02
65	1.60E+02	1.65E+02	1.64E+02	1.66E+02	1.53E+02	1.45E+02
66	1.78E+02	1.82E+02	1.79E+02	1.76E+02	1.79E+02	1.75E+02
67	1.75E+02	1.78E+02	1.78E+02	1.78E+02	1.76E+02	1.68E+02
68	1.71E+02	1.75E+02	1.75E+02	1.68E+02	1.74E+02	1.67E+02
69	1.77E+02	1.79E+02	1.76E+02	1.77E+02	1.74E+02	1.71E+02
70	1.70E+02	1.73E+02	1.73E+02	1.70E+02	1.73E+02	1.64E+02
71	1.74E+02	1.78E+02	1.76E+02	1.78E+02	1.75E+02	1.80E+02
72	1.75E+02	1.75E+02	1.72E+02	1.78E+02	1.80E+02	1.79E+02
Biased Statistics						
Average Biased	1.72E+02	1.72E+02	1.74E+02	1.73E+02	1.65E+02	1.47E+02
Std Dev Biased	7.40E+00	5.41E+00	5.99E+00	4.67E+00	1.13E+01	6.51E+00
Ps90%/90% (+KTL) Biased	1.93E+02	1.87E+02	1.90E+02	1.85E+02	1.96E+02	1.65E+02
Ps90%/90% (-KTL) Biased	1.52E+02	1.58E+02	1.57E+02	1.60E+02	1.34E+02	1.29E+02
Un-Biased Statistics						
Average Un-Biased	1.74E+02	1.77E+02	1.76E+02	1.74E+02	1.75E+02	1.69E+02
Std Dev Un-Biased	3.48E+00	3.31E+00	2.29E+00	4.40E+00	2.35E+00	4.13E+00
Ps90%/90% (+KTL) Un-Biased	1.84E+02	1.86E+02	1.82E+02	1.86E+02	1.81E+02	1.80E+02
Ps90%/90% (-KTL) Un-Biased	1.65E+02	1.68E+02	1.70E+02	1.62E+02	1.69E+02	1.58E+02
Specification MIN	4.60E+01	4.60E+01	4.60E+01	4.60E+01	4.60E+01	4.60E+01
Status	PASS	PASS	PASS	PASS	PASS	PASS

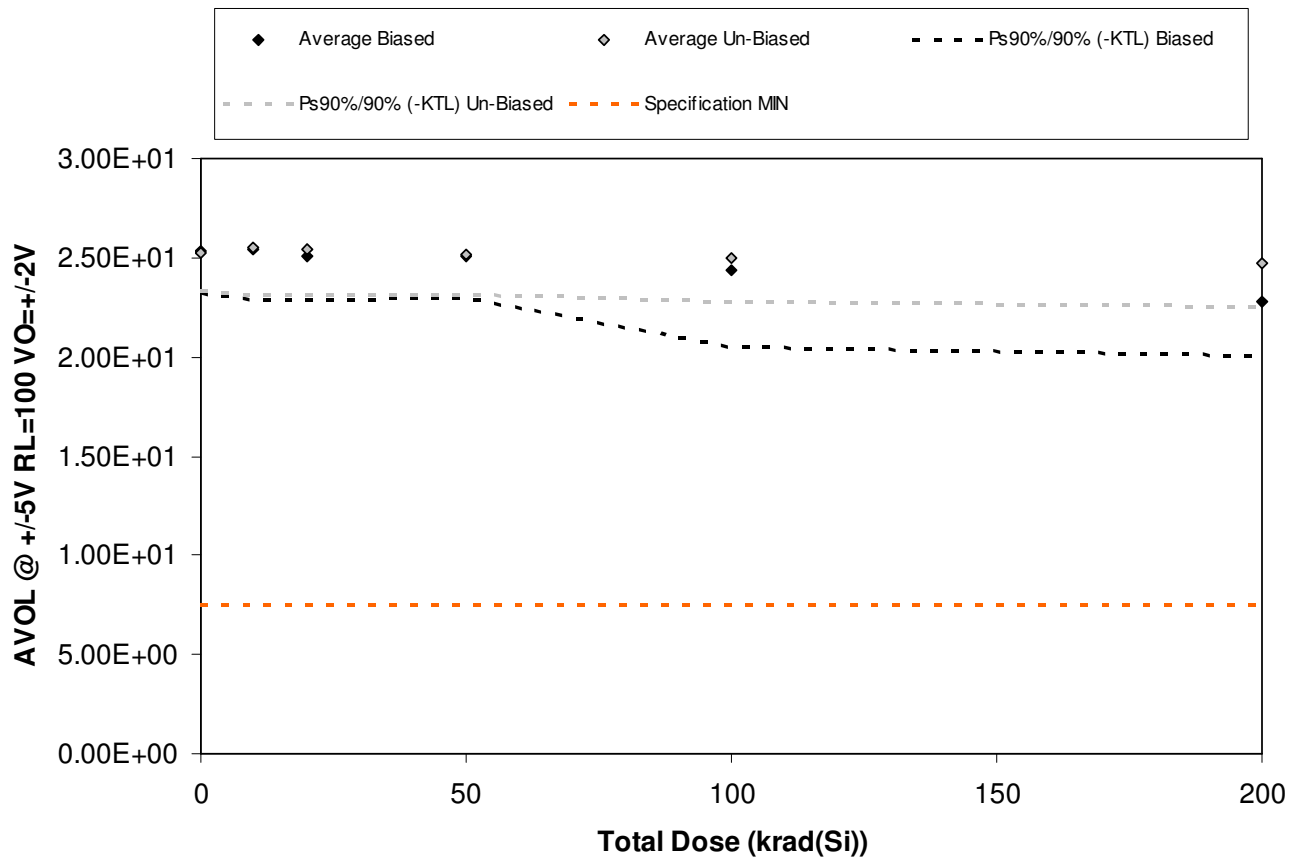


Figure 5.25. Plot of AVOL @ +/-5V RL=100 VO=+/-2V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.25. Raw data for AVOL @ +/-5V RL=100 VO=+/-2V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

AVOL @ +/-5V RL=100 VO=+/-2V Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	2.47E+01	2.45E+01	2.45E+01	2.46E+01	2.35E+01	2.25E+01
62	2.55E+01	2.59E+01	2.53E+01	2.49E+01	2.44E+01	2.28E+01
63	2.65E+01	2.66E+01	2.64E+01	2.64E+01	2.65E+01	2.43E+01
64	2.52E+01	2.56E+01	2.49E+01	2.50E+01	2.46E+01	2.28E+01
65	2.46E+01	2.45E+01	2.44E+01	2.45E+01	2.28E+01	2.15E+01
66	2.64E+01	2.66E+01	2.64E+01	2.64E+01	2.64E+01	2.60E+01
67	2.52E+01	2.55E+01	2.52E+01	2.50E+01	2.47E+01	2.45E+01
68	2.47E+01	2.48E+01	2.48E+01	2.46E+01	2.47E+01	2.44E+01
69	2.55E+01	2.60E+01	2.62E+01	2.51E+01	2.46E+01	2.46E+01
70	2.46E+01	2.45E+01	2.45E+01	2.46E+01	2.45E+01	2.39E+01
71	2.64E+01	2.64E+01	2.67E+01	2.64E+01	2.65E+01	2.66E+01
72	2.59E+01	2.58E+01	2.58E+01	2.59E+01	2.59E+01	2.62E+01
Biased Statistics						
Average Biased	2.53E+01	2.54E+01	2.51E+01	2.51E+01	2.44E+01	2.28E+01
Std Dev Biased	7.65E-01	9.15E-01	8.09E-01	7.66E-01	1.40E+00	1.00E+00
Ps90%/90% (+KTL) Biased	2.74E+01	2.79E+01	2.73E+01	2.72E+01	2.82E+01	2.55E+01
Ps90%/90% (-KTL) Biased	2.32E+01	2.29E+01	2.29E+01	2.30E+01	2.05E+01	2.00E+01
Un-Biased Statistics						
Average Un-Biased	2.53E+01	2.55E+01	2.54E+01	2.51E+01	2.50E+01	2.47E+01
Std Dev Un-Biased	7.26E-01	8.58E-01	8.44E-01	7.40E-01	7.98E-01	7.85E-01
Ps90%/90% (+KTL) Un-Biased	2.73E+01	2.78E+01	2.77E+01	2.72E+01	2.72E+01	2.68E+01
Ps90%/90% (-KTL) Un-Biased	2.33E+01	2.31E+01	2.31E+01	2.31E+01	2.28E+01	2.25E+01
Specification MIN	7.50E+00	7.50E+00	7.50E+00	7.50E+00	7.50E+00	7.50E+00
Status	PASS	PASS	PASS	PASS	PASS	PASS

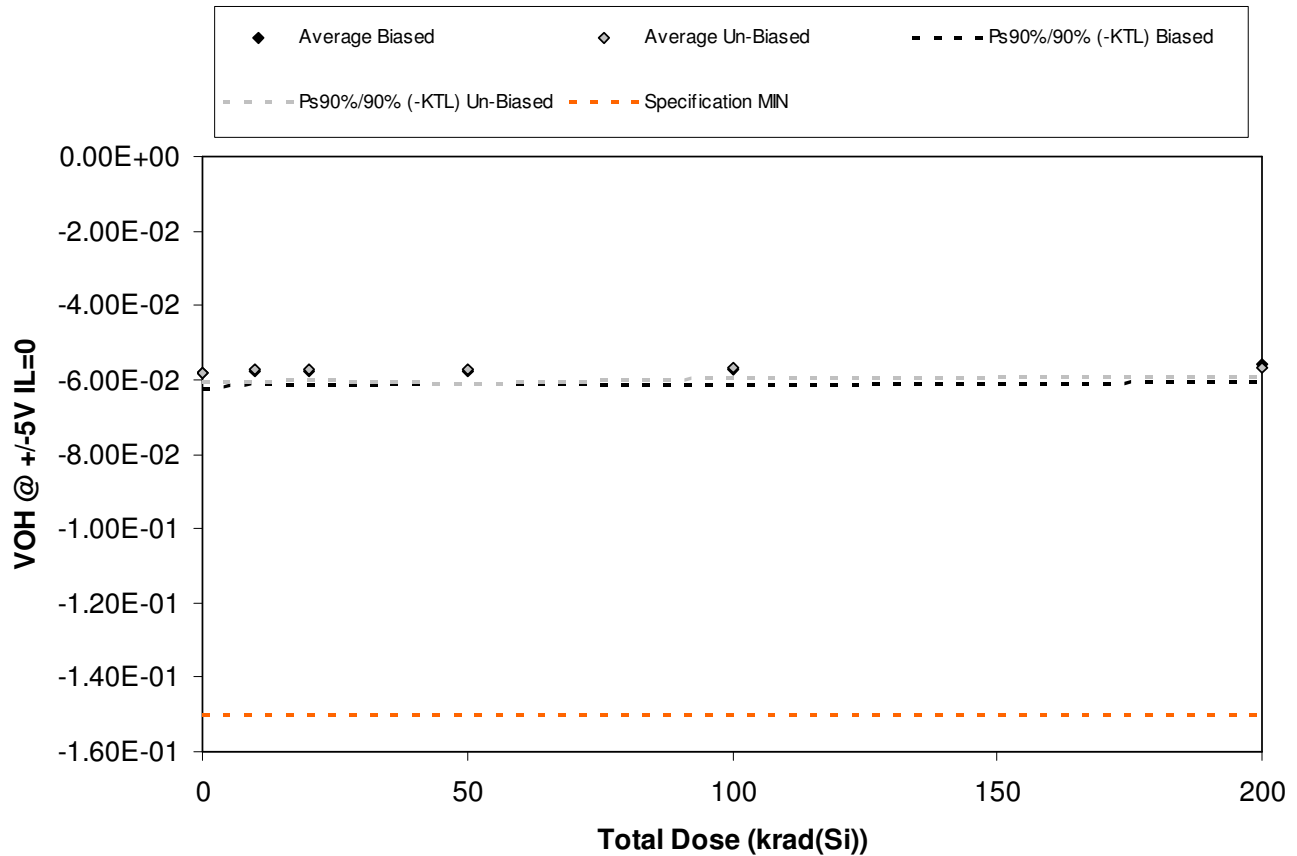


Figure 5.26. Plot of VOH @ +/-5V IL=0 versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.26. Raw data for VOH @ +/-5V IL=0 versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOH @ +/-5V IL=0		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	-5.80E-02	-5.84E-02	-5.81E-02	-5.85E-02	-5.85E-02	-5.68E-02
	62	-5.61E-02	-5.55E-02	-5.54E-02	-5.55E-02	-5.46E-02	-5.34E-02
	63	-5.95E-02	-5.82E-02	-5.84E-02	-5.82E-02	-5.77E-02	-5.67E-02
	64	-5.90E-02	-5.80E-02	-5.82E-02	-5.77E-02	-5.73E-02	-5.60E-02
	65	-5.93E-02	-5.85E-02	-5.87E-02	-5.84E-02	-5.80E-02	-5.74E-02
	66	-5.90E-02	-5.80E-02	-5.80E-02	-5.78E-02	-5.78E-02	-5.75E-02
	67	-5.74E-02	-5.62E-02	-5.65E-02	-5.60E-02	-5.58E-02	-5.58E-02
	68	-5.91E-02	-5.83E-02	-5.83E-02	-5.92E-02	-5.77E-02	-5.74E-02
	69	-5.74E-02	-5.57E-02	-5.58E-02	-5.57E-02	-5.56E-02	-5.55E-02
	70	-5.82E-02	-5.76E-02	-5.76E-02	-5.71E-02	-5.70E-02	-5.67E-02
	71	-5.96E-02	-5.88E-02	-5.87E-02	-5.88E-02	-5.90E-02	-5.90E-02
	72	-5.78E-02	-5.69E-02	-5.68E-02	-5.71E-02	-5.70E-02	-5.73E-02
Biased Statistics							
	Average Biased	-5.84E-02	-5.77E-02	-5.78E-02	-5.77E-02	-5.72E-02	-5.61E-02
	Std Dev Biased	1.42E-03	1.27E-03	1.33E-03	1.22E-03	1.52E-03	1.56E-03
	Ps90%/90% (+KTL) Biased	-5.45E-02	-5.42E-02	-5.41E-02	-5.43E-02	-5.30E-02	-5.18E-02
	Ps90%/90% (-KTL) Biased	-6.23E-02	-6.12E-02	-6.14E-02	-6.10E-02	-6.14E-02	-6.04E-02
Un-Biased Statistics							
	Average Un-Biased	-5.82E-02	-5.72E-02	-5.72E-02	-5.72E-02	-5.68E-02	-5.66E-02
	Std Dev Un-Biased	8.37E-04	1.15E-03	1.06E-03	1.40E-03	1.01E-03	9.33E-04
	Ps90%/90% (+KTL) Un-Biased	-5.59E-02	-5.40E-02	-5.43E-02	-5.33E-02	-5.40E-02	-5.40E-02
	Ps90%/90% (-KTL) Un-Biased	-6.05E-02	-6.03E-02	-6.01E-02	-6.10E-02	-5.96E-02	-5.91E-02
	Specification MIN	-1.50E-01	-1.50E-01	-1.50E-01	-1.50E-01	-1.50E-01	-1.50E-01
	Status	PASS	PASS	PASS	PASS	PASS	PASS

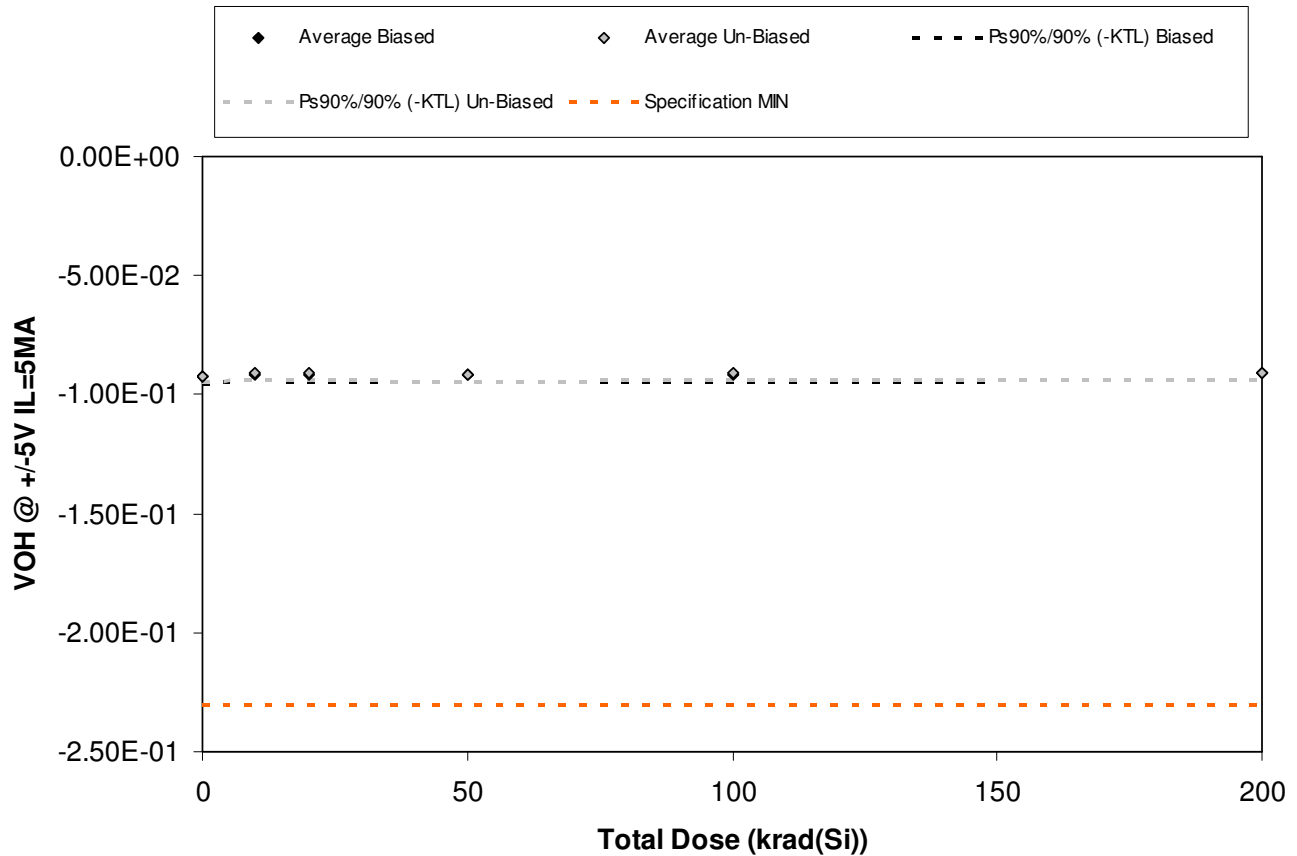


Figure 5.27. Plot of VOH @ +/-5V IL=5MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.27. Raw data for VOH @ +/-5V IL=5MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOH @ +/-5V IL=5MA		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	-9.11E-02	-9.20E-02	-9.16E-02	-9.26E-02	-9.25E-02	-9.15E-02
	62	-9.05E-02	-9.01E-02	-9.00E-02	-9.06E-02	-8.98E-02	-8.95E-02
	63	-9.32E-02	-9.15E-02	-9.21E-02	-9.20E-02	-9.20E-02	-9.13E-02
	64	-9.22E-02	-9.12E-02	-9.17E-02	-9.15E-02	-9.11E-02	-9.08E-02
	65	-9.32E-02	-9.24E-02	-9.27E-02	-9.27E-02	-9.25E-02	-9.22E-02
	66	-9.36E-02	-9.21E-02	-9.24E-02	-9.24E-02	-9.24E-02	-9.27E-02
	67	-9.12E-02	-8.98E-02	-9.01E-02	-9.00E-02	-8.98E-02	-9.00E-02
	68	-9.25E-02	-9.17E-02	-9.16E-02	-9.29E-02	-9.15E-02	-9.16E-02
	69	-9.21E-02	-9.05E-02	-9.08E-02	-9.05E-02	-9.04E-02	-9.06E-02
	70	-9.18E-02	-9.10E-02	-9.08E-02	-9.09E-02	-9.06E-02	-9.07E-02
	71	-9.37E-02	-9.25E-02	-9.23E-02	-9.27E-02	-9.28E-02	-9.29E-02
	72	-9.19E-02	-9.02E-02	-9.05E-02	-9.04E-02	-9.06E-02	-9.12E-02
Biased Statistics							
	Average Biased	-9.20E-02	-9.14E-02	-9.16E-02	-9.19E-02	-9.16E-02	-9.11E-02
	Std Dev Biased	1.23E-03	8.75E-04	9.86E-04	8.74E-04	1.14E-03	1.02E-03
	Ps90%/90% (+KTL) Biased	-8.87E-02	-8.90E-02	-8.89E-02	-8.95E-02	-8.85E-02	-8.83E-02
	Ps90%/90% (-KTL) Biased	-9.54E-02	-9.38E-02	-9.43E-02	-9.43E-02	-9.47E-02	-9.39E-02
Un-Biased Statistics							
	Average Un-Biased	-9.22E-02	-9.10E-02	-9.12E-02	-9.13E-02	-9.10E-02	-9.11E-02
	Std Dev Un-Biased	8.86E-04	9.09E-04	8.93E-04	1.27E-03	1.03E-03	1.05E-03
	Ps90%/90% (+KTL) Un-Biased	-8.98E-02	-8.85E-02	-8.87E-02	-8.78E-02	-8.81E-02	-8.83E-02
	Ps90%/90% (-KTL) Un-Biased	-9.47E-02	-9.35E-02	-9.36E-02	-9.48E-02	-9.38E-02	-9.40E-02
	Specification MIN	-2.30E-01	-2.30E-01	-2.30E-01	-2.30E-01	-2.30E-01	-2.30E-01
	Status	PASS	PASS	PASS	PASS	PASS	PASS

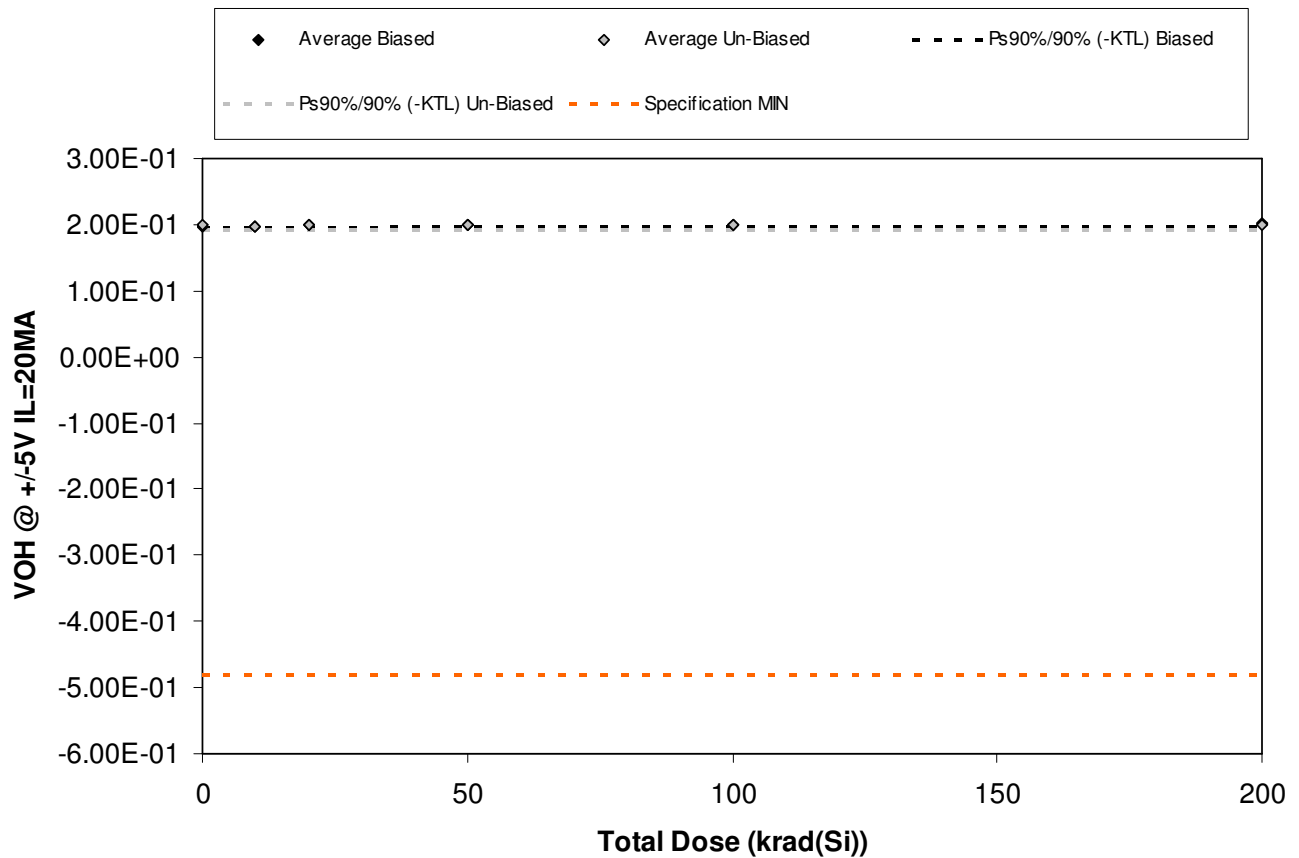


Figure 5.28. Plot of VOH @ +/-5V IL=20MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.28. Raw data for VOH @ +/-5V IL=20MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOH @ +/-5V IL=20MA		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
61	1.96E-01	1.98E-01	1.98E-01	2.00E-01	2.01E-01	2.02E-01	
62	1.99E-01	1.99E-01	1.99E-01	2.01E-01	2.02E-01	2.05E-01	
63	1.99E-01	1.98E-01	1.98E-01	1.99E-01	2.00E-01	2.01E-01	
64	1.97E-01	1.97E-01	1.97E-01	1.98E-01	1.99E-01	2.01E-01	
65	2.00E-01	1.99E-01	2.00E-01	2.01E-01	2.01E-01	2.02E-01	
66	2.03E-01	2.02E-01	2.02E-01	2.02E-01	2.03E-01	2.04E-01	
67	1.97E-01	1.96E-01	1.96E-01	1.96E-01	1.97E-01	1.98E-01	
68	1.98E-01	1.97E-01	1.97E-01	1.99E-01	1.98E-01	1.99E-01	
69	2.02E-01	2.01E-01	2.01E-01	2.01E-01	2.02E-01	2.03E-01	
70	1.97E-01	1.96E-01	1.96E-01	1.97E-01	1.97E-01	1.98E-01	
71	2.00E-01	1.99E-01	1.98E-01	1.99E-01	1.99E-01	1.99E-01	
72	1.97E-01	1.95E-01	1.95E-01	1.95E-01	1.95E-01	1.96E-01	
Biased Statistics							
Average Biased	1.98E-01	1.98E-01	1.99E-01	2.00E-01	2.01E-01	2.02E-01	
Std Dev Biased	1.57E-03	9.87E-04	1.15E-03	1.25E-03	1.38E-03	1.56E-03	
Ps90%/90% (+KTL) Biased	2.02E-01	2.01E-01	2.02E-01	2.03E-01	2.04E-01	2.06E-01	
Ps90%/90% (-KTL) Biased	1.94E-01	1.95E-01	1.95E-01	1.96E-01	1.97E-01	1.98E-01	
Un-Biased Statistics							
Average Un-Biased	1.99E-01	1.98E-01	1.99E-01	1.99E-01	1.99E-01	2.00E-01	
Std Dev Un-Biased	2.91E-03	2.83E-03	2.82E-03	2.67E-03	3.02E-03	3.20E-03	
Ps90%/90% (+KTL) Un-Biased	2.07E-01	2.06E-01	2.06E-01	2.06E-01	2.08E-01	2.09E-01	
Ps90%/90% (-KTL) Un-Biased	1.91E-01	1.91E-01	1.91E-01	1.92E-01	1.91E-01	1.92E-01	
Specification MIN	-4.80E-01	-4.80E-01	-4.80E-01	-4.80E-01	-4.80E-01	-4.80E-01	
Status	PASS	PASS	PASS	PASS	PASS	PASS	

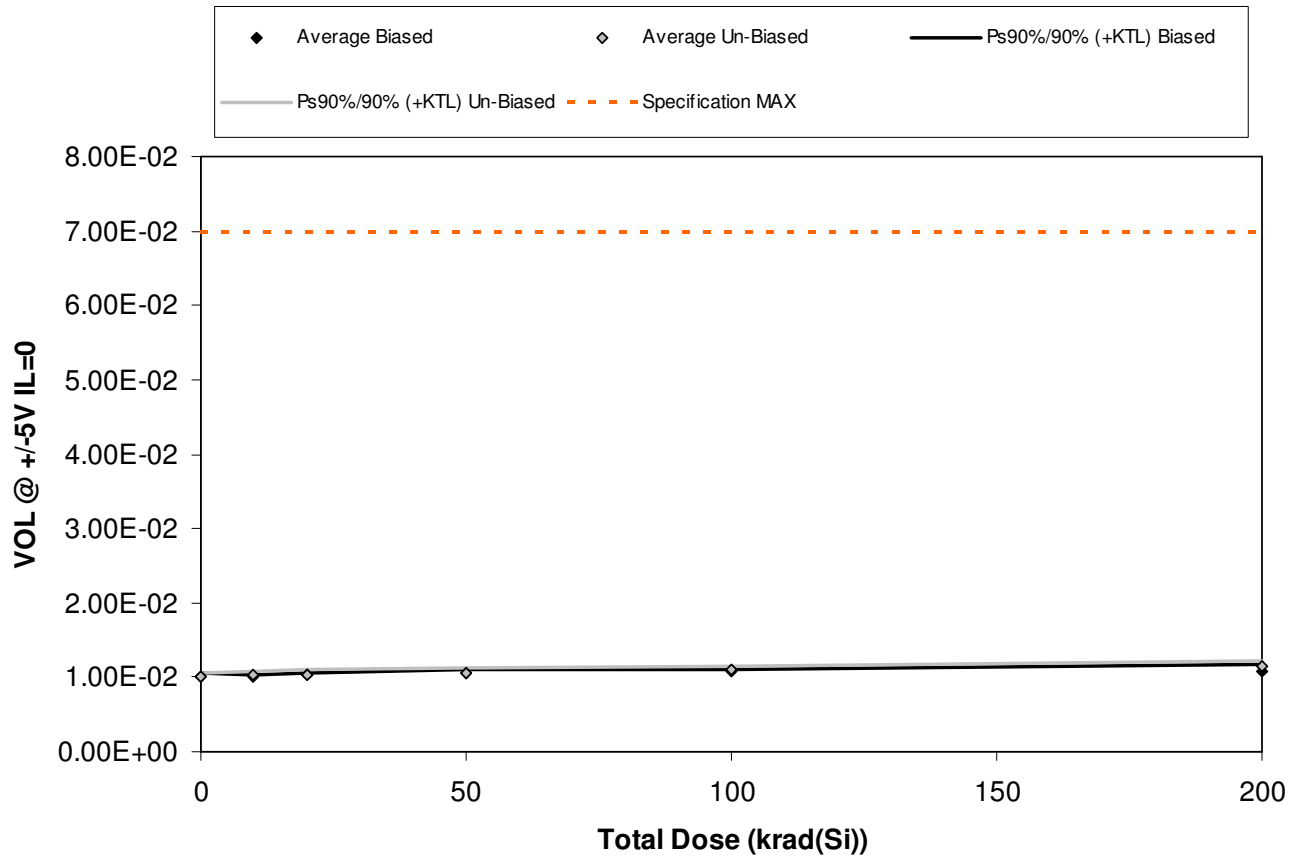


Figure 5.29. Plot of VOL @ +/-5V IL=0 versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.29. Raw data for VOL @ +/-5V IL=0 versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOL @ +/-5V IL=0 Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	1.03E-02	1.02E-02	1.03E-02	1.09E-02	1.09E-02	1.10E-02
62	1.02E-02	1.00E-02	1.02E-02	1.05E-02	1.07E-02	1.13E-02
63	1.03E-02	1.02E-02	1.02E-02	1.06E-02	1.06E-02	1.07E-02
64	1.01E-02	1.01E-02	1.04E-02	1.05E-02	1.07E-02	1.08E-02
65	1.01E-02	1.01E-02	1.04E-02	1.04E-02	1.05E-02	1.06E-02
66	9.91E-03	1.01E-02	1.02E-02	1.07E-02	1.10E-02	1.16E-02
67	1.01E-02	1.02E-02	1.03E-02	1.04E-02	1.08E-02	1.13E-02
68	1.03E-02	1.05E-02	1.07E-02	1.09E-02	1.12E-02	1.18E-02
69	1.02E-02	1.04E-02	1.05E-02	1.05E-02	1.08E-02	1.15E-02
70	1.01E-02	1.01E-02	1.02E-02	1.05E-02	1.07E-02	1.10E-02
71	1.02E-02	1.01E-02	1.02E-02	1.01E-02	1.02E-02	1.04E-02
72	1.05E-02	1.02E-02	1.02E-02	1.01E-02	1.03E-02	1.05E-02
Biased Statistics						
Average Biased	1.02E-02	1.01E-02	1.03E-02	1.06E-02	1.07E-02	1.09E-02
Std Dev Biased	9.41E-05	9.57E-05	1.02E-04	1.82E-04	1.51E-04	2.89E-04
Ps90%/90% (+KTL) Biased	1.05E-02	1.04E-02	1.06E-02	1.11E-02	1.11E-02	1.17E-02
Ps90%/90% (-KTL) Biased	9.94E-03	9.88E-03	1.00E-02	1.01E-02	1.03E-02	1.01E-02
Un-Biased Statistics						
Average Un-Biased	1.01E-02	1.03E-02	1.04E-02	1.06E-02	1.09E-02	1.15E-02
Std Dev Un-Biased	1.45E-04	1.60E-04	2.11E-04	2.22E-04	2.15E-04	2.85E-04
Ps90%/90% (+KTL) Un-Biased	1.05E-02	1.07E-02	1.10E-02	1.12E-02	1.15E-02	1.22E-02
Ps90%/90% (-KTL) Un-Biased	9.72E-03	9.81E-03	9.82E-03	1.00E-02	1.03E-02	1.07E-02
Specification MAX	7.00E-02	7.00E-02	7.00E-02	7.00E-02	7.00E-02	7.00E-02
Status	PASS	PASS	PASS	PASS	PASS	PASS

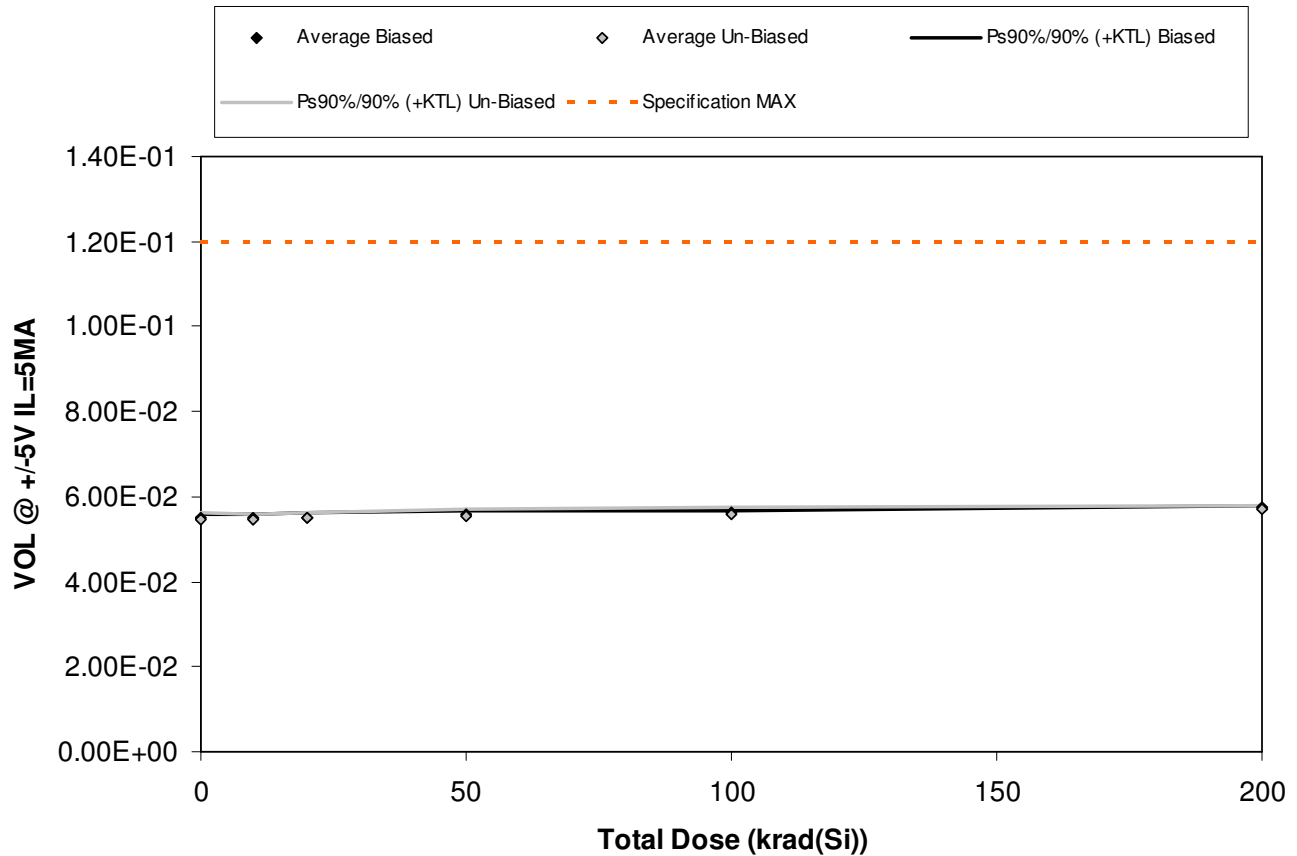


Figure 5.30. Plot of VOL @ +/-5V IL=5MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.30. Raw data for VOL @ +/-5V IL=5MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOL @ +/-5V IL=5MA	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	5.46E-02	5.48E-02	5.51E-02	5.61E-02	5.65E-02	5.77E-02
62	5.48E-02	5.43E-02	5.44E-02	5.54E-02	5.61E-02	5.75E-02
63	5.54E-02	5.52E-02	5.53E-02	5.58E-02	5.61E-02	5.75E-02
64	5.50E-02	5.50E-02	5.54E-02	5.57E-02	5.62E-02	5.74E-02
65	5.51E-02	5.51E-02	5.56E-02	5.54E-02	5.64E-02	5.74E-02
66	5.43E-02	5.41E-02	5.45E-02	5.48E-02	5.55E-02	5.68E-02
67	5.56E-02	5.52E-02	5.54E-02	5.62E-02	5.66E-02	5.75E-02
68	5.51E-02	5.51E-02	5.55E-02	5.59E-02	5.64E-02	5.73E-02
69	5.45E-02	5.43E-02	5.46E-02	5.51E-02	5.58E-02	5.68E-02
70	5.45E-02	5.45E-02	5.47E-02	5.51E-02	5.56E-02	5.67E-02
71	5.52E-02	5.47E-02	5.46E-02	5.48E-02	5.48E-02	5.46E-02
72	5.54E-02	5.50E-02	5.50E-02	5.50E-02	5.49E-02	5.53E-02
Biased Statistics						
Average Biased	5.50E-02	5.49E-02	5.52E-02	5.57E-02	5.63E-02	5.75E-02
Std Dev Biased	2.88E-04	3.43E-04	4.54E-04	2.90E-04	1.88E-04	1.28E-04
Ps90%/90% (+KTL) Biased	5.58E-02	5.58E-02	5.64E-02	5.65E-02	5.68E-02	5.78E-02
Ps90%/90% (-KTL) Biased	5.42E-02	5.39E-02	5.39E-02	5.49E-02	5.58E-02	5.71E-02
Un-Biased Statistics						
Average Un-Biased	5.48E-02	5.46E-02	5.49E-02	5.54E-02	5.60E-02	5.70E-02
Std Dev Un-Biased	5.52E-04	4.88E-04	4.60E-04	6.10E-04	5.06E-04	3.91E-04
Ps90%/90% (+KTL) Un-Biased	5.63E-02	5.60E-02	5.62E-02	5.71E-02	5.74E-02	5.81E-02
Ps90%/90% (-KTL) Un-Biased	5.33E-02	5.33E-02	5.37E-02	5.38E-02	5.46E-02	5.59E-02
Specification MAX	1.20E-01	1.20E-01	1.20E-01	1.20E-01	1.20E-01	1.20E-01
Status	PASS	PASS	PASS	PASS	PASS	PASS

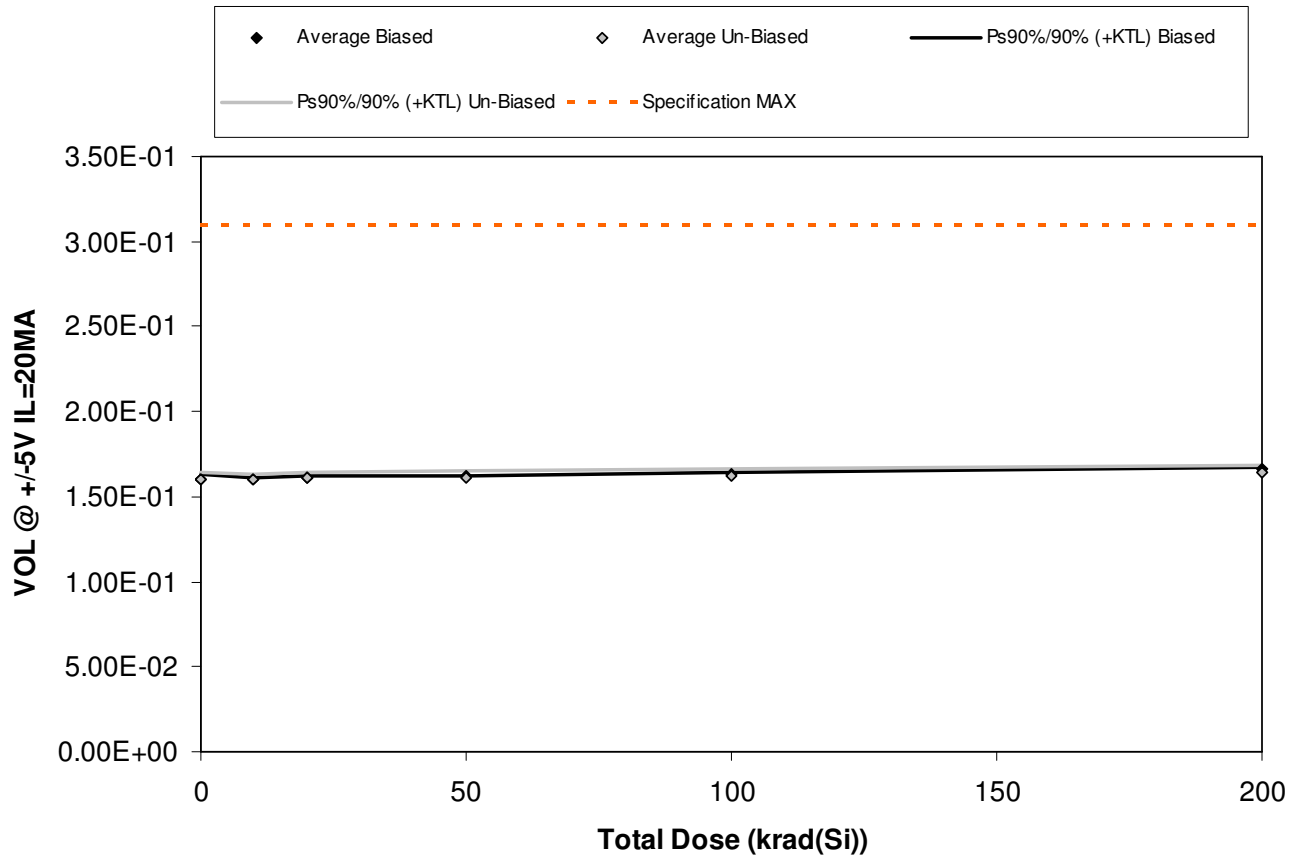


Figure 5.31. Plot of VOL @ +/-5V IL=20MA versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.31. Raw data for VOL @ +/-5V IL=20MA versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOL @ +/-5V IL=20MA		Total Dose (krad(Si))					
		0	10	20	50	100	200
Device							
	61	1.59E-01	1.60E-01	1.61E-01	1.62E-01	1.64E-01	1.66E-01
	62	1.60E-01	1.60E-01	1.61E-01	1.62E-01	1.64E-01	1.67E-01
	63	1.61E-01	1.61E-01	1.61E-01	1.62E-01	1.63E-01	1.66E-01
	64	1.61E-01	1.61E-01	1.61E-01	1.62E-01	1.63E-01	1.66E-01
	65	1.61E-01	1.61E-01	1.61E-01	1.62E-01	1.63E-01	1.65E-01
	66	1.59E-01	1.59E-01	1.59E-01	1.60E-01	1.61E-01	1.63E-01
	67	1.63E-01	1.62E-01	1.63E-01	1.63E-01	1.65E-01	1.66E-01
	68	1.61E-01	1.60E-01	1.61E-01	1.62E-01	1.63E-01	1.64E-01
	69	1.61E-01	1.60E-01	1.61E-01	1.62E-01	1.63E-01	1.64E-01
	70	1.60E-01	1.59E-01	1.60E-01	1.61E-01	1.61E-01	1.63E-01
	71	1.60E-01	1.60E-01	1.59E-01	1.60E-01	1.60E-01	1.60E-01
	72	1.62E-01	1.61E-01	1.61E-01	1.61E-01	1.61E-01	1.61E-01
Biased Statistics							
	Average Biased	1.61E-01	1.61E-01	1.61E-01	1.62E-01	1.63E-01	1.66E-01
	Std Dev Biased	8.08E-04	3.70E-04	3.77E-04	2.92E-04	4.42E-04	4.26E-04
	Ps90%/90% (+KTL) Biased	1.63E-01	1.62E-01	1.62E-01	1.63E-01	1.65E-01	1.67E-01
	Ps90%/90% (-KTL) Biased	1.58E-01	1.60E-01	1.60E-01	1.61E-01	1.62E-01	1.65E-01
Un-Biased Statistics							
	Average Un-Biased	1.61E-01	1.60E-01	1.61E-01	1.62E-01	1.63E-01	1.64E-01
	Std Dev Un-Biased	1.39E-03	1.23E-03	1.44E-03	1.36E-03	1.42E-03	1.30E-03
	Ps90%/90% (+KTL) Un-Biased	1.64E-01	1.64E-01	1.65E-01	1.65E-01	1.66E-01	1.68E-01
	Ps90%/90% (-KTL) Un-Biased	1.57E-01	1.57E-01	1.57E-01	1.58E-01	1.59E-01	1.61E-01
	Specification MAX	3.10E-01	3.10E-01	3.10E-01	3.10E-01	3.10E-01	3.10E-01
	Status	PASS	PASS	PASS	PASS	PASS	PASS

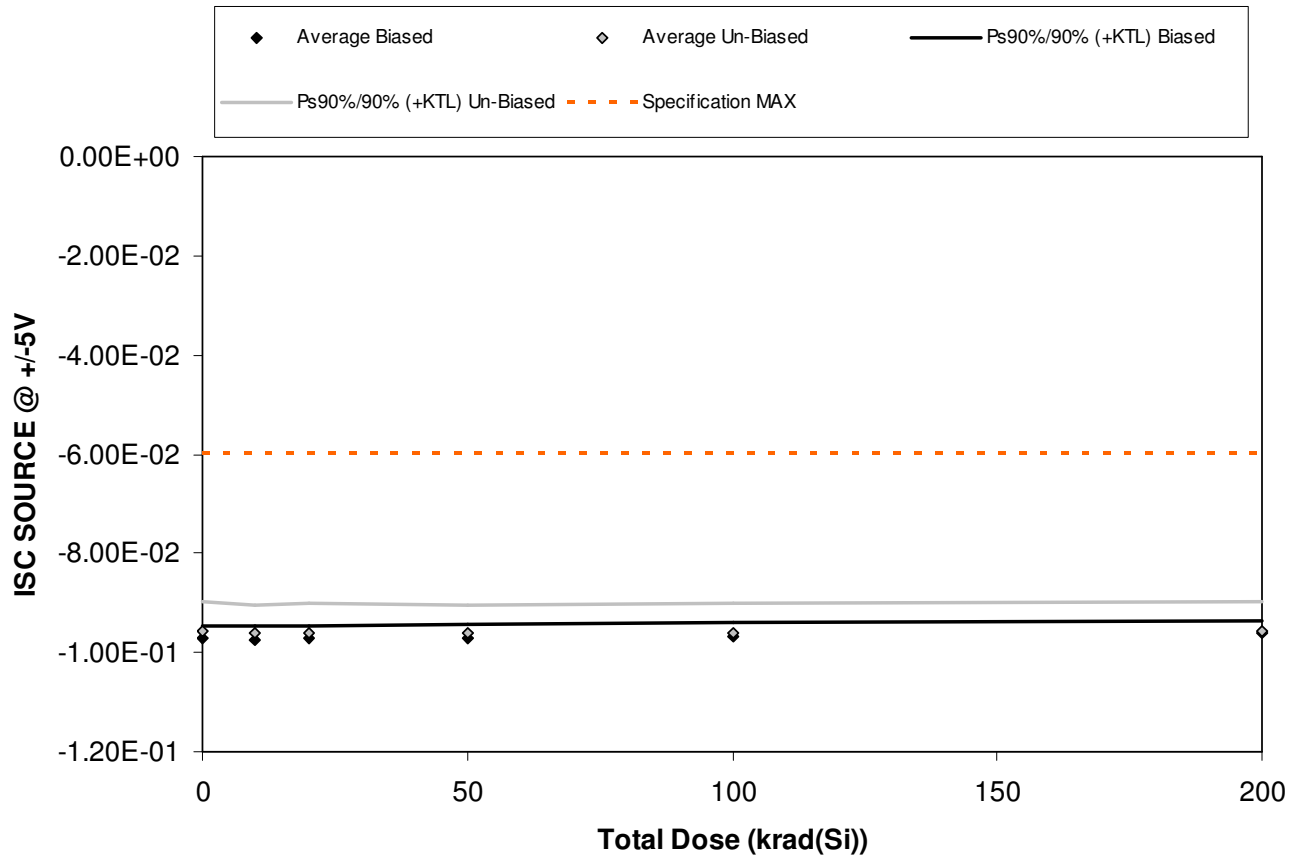


Figure 5.32. Plot of ISC SOURCE @ +/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.32. Raw data for ISC SOURCE @ +/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

ISC SOURCE @ +/-5V		Total Dose (krad(Si))					
Device		0	10	20	50	100	200
61		-9.74E-02	-9.73E-02	-9.73E-02	-9.70E-02	-9.66E-02	-9.62E-02
62		-9.62E-02	-9.64E-02	-9.65E-02	-9.61E-02	-9.57E-02	-9.51E-02
63		-9.75E-02	-9.80E-02	-9.79E-02	-9.77E-02	-9.76E-02	-9.70E-02
64		-9.83E-02	-9.86E-02	-9.85E-02	-9.84E-02	-9.81E-02	-9.74E-02
65		-9.61E-02	-9.64E-02	-9.62E-02	-9.62E-02	-9.59E-02	-9.54E-02
66		-9.34E-02	-9.37E-02	-9.36E-02	-9.36E-02	-9.34E-02	-9.31E-02
67		-9.79E-02	-9.83E-02	-9.82E-02	-9.83E-02	-9.81E-02	-9.78E-02
68		-9.74E-02	-9.77E-02	-9.77E-02	-9.72E-02	-9.75E-02	-9.71E-02
69		-9.37E-02	-9.42E-02	-9.41E-02	-9.41E-02	-9.40E-02	-9.37E-02
70		-9.72E-02	-9.74E-02	-9.74E-02	-9.74E-02	-9.73E-02	-9.70E-02
71		-9.58E-02	-9.61E-02	-9.61E-02	-9.61E-02	-9.60E-02	-9.60E-02
72		-9.89E-02	-9.95E-02	-9.95E-02	-9.96E-02	-9.94E-02	-9.93E-02
Biased Statistics							
Average Biased		-9.71E-02	-9.73E-02	-9.73E-02	-9.71E-02	-9.68E-02	-9.62E-02
Std Dev Biased		9.37E-04	9.74E-04	9.42E-04	9.94E-04	1.05E-03	9.83E-04
Ps90%/90% (+KTL) Biased		-9.45E-02	-9.47E-02	-9.47E-02	-9.43E-02	-9.39E-02	-9.35E-02
Ps90%/90% (-KTL) Biased		-9.97E-02	-1.00E-01	-9.99E-02	-9.98E-02	-9.97E-02	-9.89E-02
Un-Biased Statistics							
Average Un-Biased		-9.59E-02	-9.62E-02	-9.62E-02	-9.61E-02	-9.60E-02	-9.57E-02
Std Dev Un-Biased		2.19E-03	2.15E-03	2.18E-03	2.10E-03	2.17E-03	2.15E-03
Ps90%/90% (+KTL) Un-Biased		-8.99E-02	-9.03E-02	-9.02E-02	-9.03E-02	-9.01E-02	-8.98E-02
Ps90%/90% (-KTL) Un-Biased		-1.02E-01	-1.02E-01	-1.02E-01	-1.02E-01	-1.02E-01	-1.02E-01
Specification MAX		-6.00E-02	-6.00E-02	-6.00E-02	-6.00E-02	-6.00E-02	-6.00E-02
Status		PASS	PASS	PASS	PASS	PASS	PASS

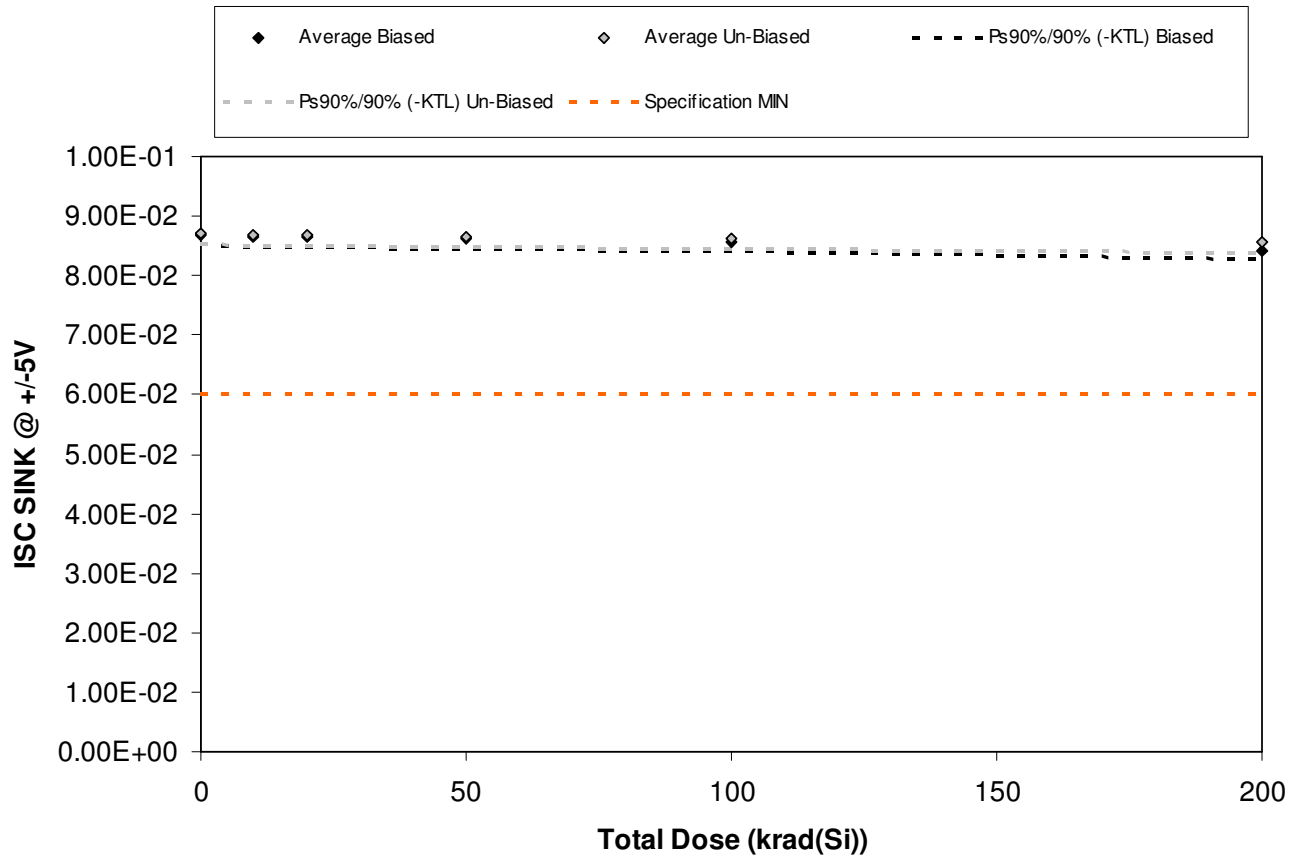


Figure 5.33. Plot of ISC SINK @ +/-5V versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.33. Raw data for ISC SINK @ +/-5V versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

ISC SINK @ +/-5V		Total Dose (krad(Si))					
Device		0	10	20	50	100	200
61	8.72E-02	8.71E-02	8.69E-02	8.69E-02	8.61E-02	8.48E-02	
62	8.74E-02	8.71E-02	8.69E-02	8.67E-02	8.58E-02	8.47E-02	
63	8.68E-02	8.64E-02	8.63E-02	8.62E-02	8.57E-02	8.42E-02	
64	8.69E-02	8.66E-02	8.66E-02	8.64E-02	8.58E-02	8.41E-02	
65	8.58E-02	8.56E-02	8.55E-02	8.53E-02	8.46E-02	8.34E-02	
66	8.78E-02	8.76E-02	8.75E-02	8.74E-02	8.71E-02	8.66E-02	
67	8.61E-02	8.59E-02	8.58E-02	8.55E-02	8.52E-02	8.46E-02	
68	8.71E-02	8.68E-02	8.67E-02	8.67E-02	8.63E-02	8.57E-02	
69	8.76E-02	8.73E-02	8.72E-02	8.69E-02	8.66E-02	8.60E-02	
70	8.73E-02	8.70E-02	8.69E-02	8.67E-02	8.64E-02	8.59E-02	
71	8.65E-02	8.63E-02	8.63E-02	8.63E-02	8.64E-02	8.64E-02	
72	8.69E-02	8.67E-02	8.67E-02	8.67E-02	8.67E-02	8.67E-02	
Biased Statistics							
Average Biased	8.68E-02	8.66E-02	8.64E-02	8.63E-02	8.56E-02	8.43E-02	
Std Dev Biased	5.99E-04	6.27E-04	6.04E-04	6.25E-04	5.66E-04	5.54E-04	
Ps90%/90% (+KTL) Biased	8.85E-02	8.83E-02	8.81E-02	8.80E-02	8.72E-02	8.58E-02	
Ps90%/90% (-KTL) Biased	8.52E-02	8.48E-02	8.48E-02	8.46E-02	8.41E-02	8.28E-02	
Un-Biased Statistics							
Average Un-Biased	8.72E-02	8.69E-02	8.68E-02	8.67E-02	8.63E-02	8.58E-02	
Std Dev Un-Biased	6.62E-04	6.64E-04	6.64E-04	6.99E-04	6.83E-04	7.21E-04	
Ps90%/90% (+KTL) Un-Biased	8.90E-02	8.87E-02	8.87E-02	8.86E-02	8.82E-02	8.77E-02	
Ps90%/90% (-KTL) Un-Biased	8.54E-02	8.51E-02	8.50E-02	8.47E-02	8.45E-02	8.38E-02	
Specification MIN	6.00E-02	6.00E-02	6.00E-02	6.00E-02	6.00E-02	6.00E-02	
Status	PASS	PASS	PASS	PASS	PASS	PASS	

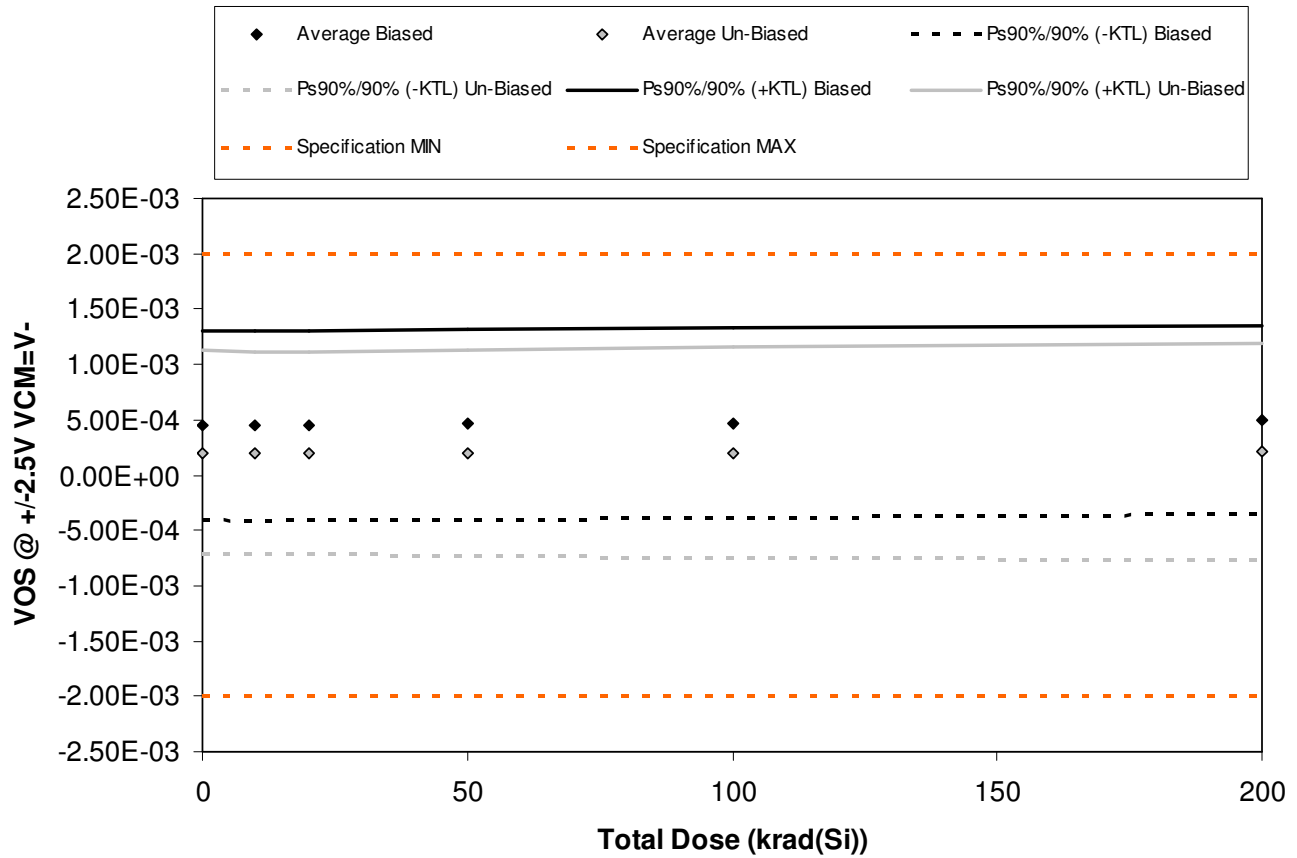


Figure 5.34. Plot of VOS @ +/-2.5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.34. Raw data for VOS @ +/-2.5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOS @ +/-2.5V VCM=V-	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	9.97E-04	9.92E-04	9.92E-04	1.01E-03	1.02E-03	1.05E-03
62	2.24E-04	2.21E-04	2.24E-04	2.44E-04	2.63E-04	3.07E-04
63	3.07E-04	3.02E-04	3.07E-04	3.09E-04	3.19E-04	3.33E-04
64	3.55E-04	3.43E-04	3.53E-04	3.58E-04	3.67E-04	3.82E-04
65	3.67E-04	3.55E-04	3.67E-04	3.67E-04	3.70E-04	3.92E-04
66	-6.00E-05	-6.80E-05	-7.00E-05	-7.00E-05	-7.00E-05	-8.20E-05
67	4.26E-04	4.16E-04	4.21E-04	4.23E-04	4.33E-04	4.47E-04
68	2.73E-04	2.63E-04	2.68E-04	2.70E-04	2.68E-04	2.73E-04
69	-2.16E-04	-2.16E-04	-2.16E-04	-2.16E-04	-2.23E-04	-2.30E-04
70	5.91E-04	5.86E-04	5.86E-04	5.98E-04	6.10E-04	6.22E-04
71	9.30E-05	9.00E-05	9.50E-05	8.80E-05	8.80E-05	8.80E-05
72	4.74E-04	4.52E-04	4.53E-04	4.55E-04	4.55E-04	4.55E-04
Biased Statistics						
Average Biased	4.50E-04	4.43E-04	4.49E-04	4.58E-04	4.69E-04	4.92E-04
Std Dev Biased	3.11E-04	3.12E-04	3.09E-04	3.13E-04	3.14E-04	3.11E-04
Ps90%/90% (+KTL) Biased	1.30E-03	1.30E-03	1.30E-03	1.32E-03	1.33E-03	1.35E-03
Ps90%/90% (-KTL) Biased	-4.03E-04	-4.12E-04	-3.98E-04	-4.01E-04	-3.91E-04	-3.62E-04
Un-Biased Statistics						
Average Un-Biased	2.03E-04	1.96E-04	1.98E-04	2.01E-04	2.04E-04	2.06E-04
Std Dev Un-Biased	3.35E-04	3.33E-04	3.35E-04	3.39E-04	3.46E-04	3.57E-04
Ps90%/90% (+KTL) Un-Biased	1.12E-03	1.11E-03	1.12E-03	1.13E-03	1.15E-03	1.18E-03
Ps90%/90% (-KTL) Un-Biased	-7.17E-04	-7.18E-04	-7.20E-04	-7.28E-04	-7.45E-04	-7.72E-04
Specification MIN	-2.00E-03	-2.00E-03	-2.00E-03	-2.00E-03	-2.00E-03	-2.00E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	2.00E-03	2.00E-03	2.00E-03	2.00E-03	2.00E-03	2.00E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS

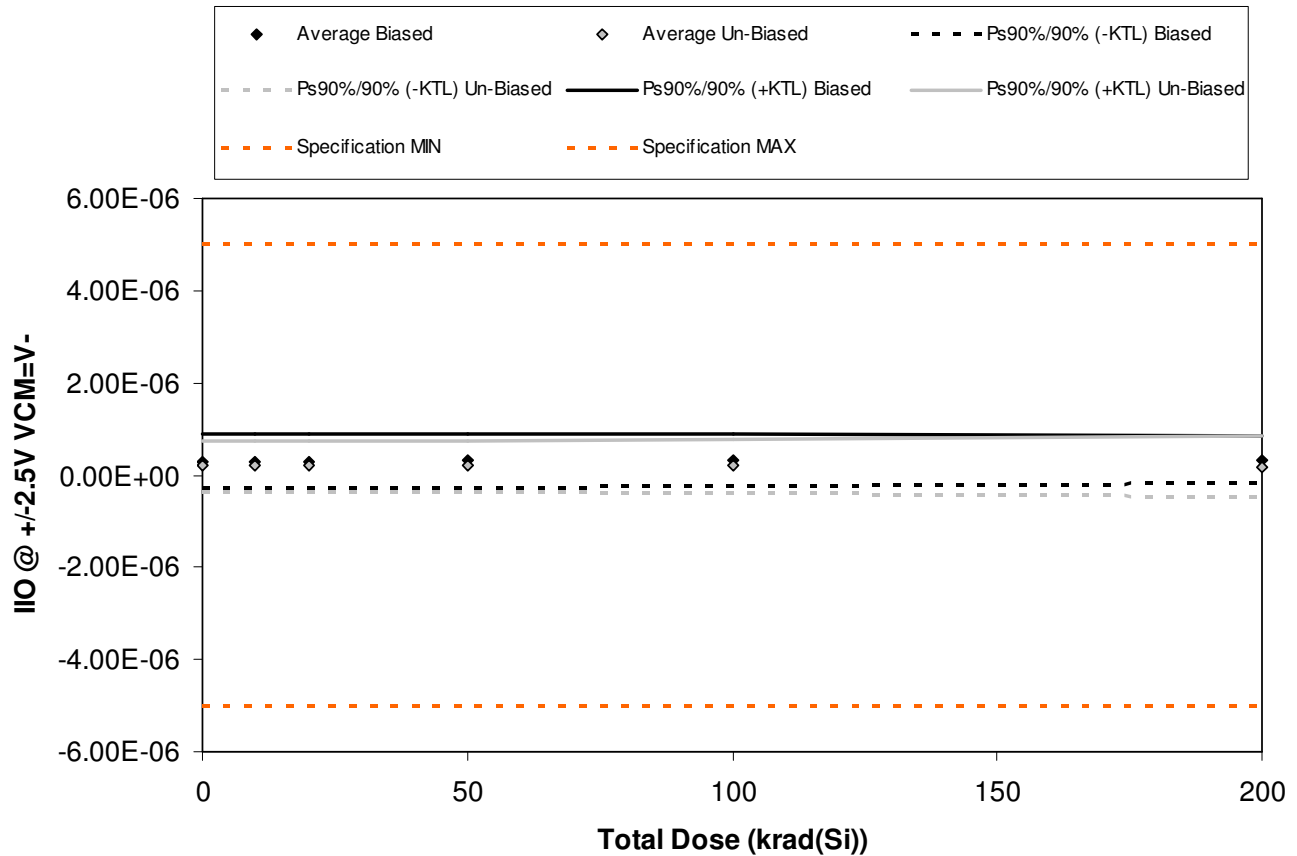


Figure 5.35. Plot of IIO @ +/-2.5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.35. Raw data for IIO @ +/-2.5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IIO @ +/-2.5V VCM=V-	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	6.78E-07	6.76E-07	6.76E-07	6.82E-07	6.76E-07	6.62E-07
62	1.56E-07	1.54E-07	1.56E-07	1.60E-07	1.88E-07	2.80E-07
63	2.14E-07	2.18E-07	2.18E-07	2.26E-07	2.35E-07	2.35E-07
64	2.08E-07	2.06E-07	2.06E-07	2.11E-07	2.03E-07	2.05E-07
65	2.43E-07	2.40E-07	2.41E-07	2.46E-07	2.45E-07	2.62E-07
66	2.56E-07	2.55E-07	2.55E-07	2.54E-07	2.54E-07	2.53E-07
67	2.93E-07	2.93E-07	2.97E-07	3.01E-07	3.08E-07	3.05E-07
68	1.63E-07	1.61E-07	1.61E-07	1.56E-07	1.54E-07	1.45E-07
69	-1.29E-07	-1.27E-07	-1.34E-07	-1.42E-07	-1.55E-07	-2.17E-07
70	3.90E-07	3.92E-07	3.92E-07	3.94E-07	4.00E-07	4.06E-07
71	5.60E-08	6.00E-08	5.90E-08	5.80E-08	5.90E-08	5.80E-08
72	3.12E-07	3.06E-07	3.06E-07	3.06E-07	3.06E-07	3.08E-07
Biased Statistics						
Average Biased	3.00E-07	2.99E-07	2.99E-07	3.05E-07	3.09E-07	3.29E-07
Std Dev Biased	2.14E-07	2.13E-07	2.13E-07	2.13E-07	2.06E-07	1.88E-07
Ps90%/90% (+KTL) Biased	8.86E-07	8.83E-07	8.83E-07	8.89E-07	8.75E-07	8.45E-07
Ps90%/90% (-KTL) Biased	-2.86E-07	-2.86E-07	-2.84E-07	-2.79E-07	-2.56E-07	-1.88E-07
Un-Biased Statistics						
Average Un-Biased	1.95E-07	1.95E-07	1.94E-07	1.93E-07	1.92E-07	1.78E-07
Std Dev Un-Biased	1.98E-07	1.98E-07	2.01E-07	2.06E-07	2.14E-07	2.40E-07
Ps90%/90% (+KTL) Un-Biased	7.38E-07	7.38E-07	7.46E-07	7.57E-07	7.78E-07	8.37E-07
Ps90%/90% (-KTL) Un-Biased	-3.49E-07	-3.48E-07	-3.58E-07	-3.72E-07	-3.93E-07	-4.80E-07
Specification MIN	-5.00E-06	-5.00E-06	-5.00E-06	-5.00E-06	-5.00E-06	-5.00E-06
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	5.00E-06	5.00E-06	5.00E-06	5.00E-06	5.00E-06	5.00E-06
Status	PASS	PASS	PASS	PASS	PASS	PASS

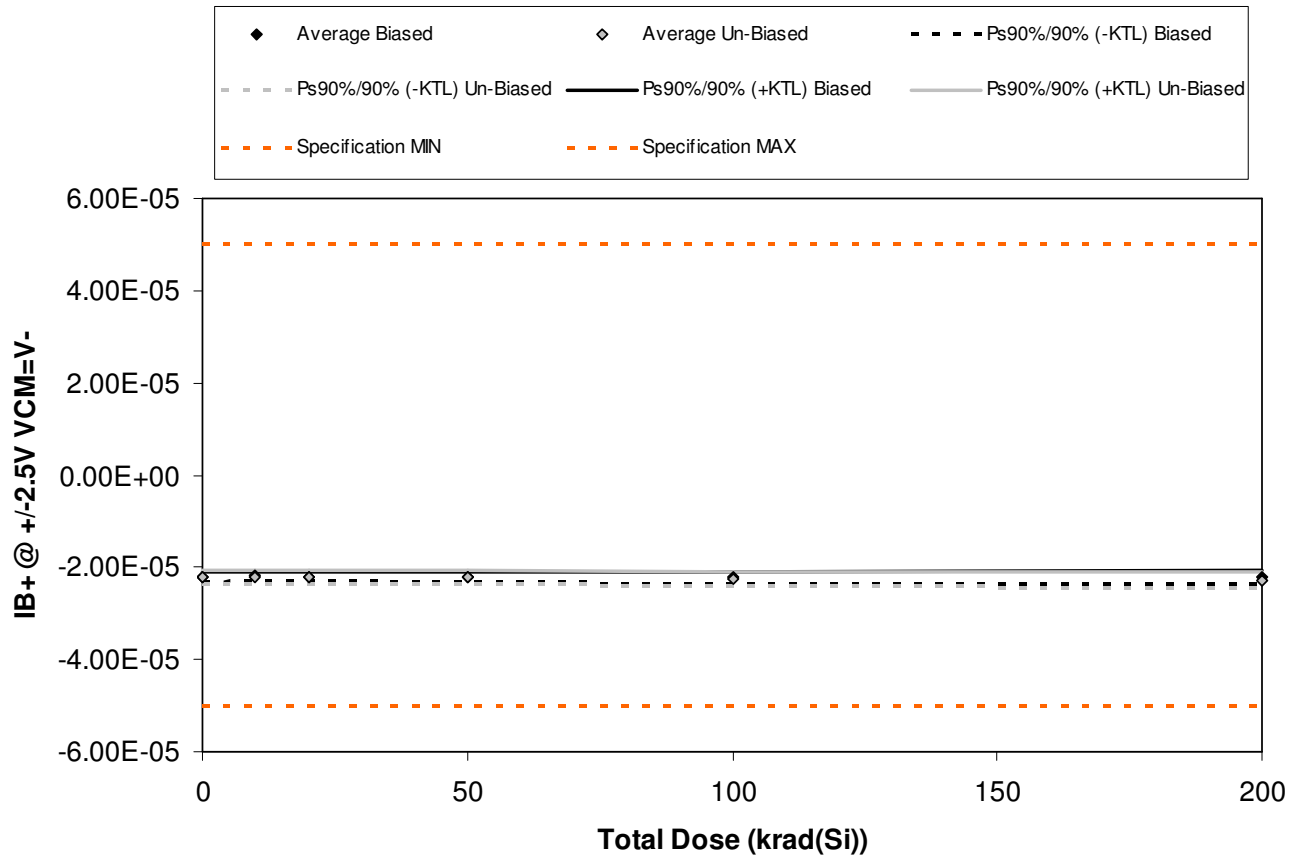


Figure 5.36. Plot of IB+ @ +/-2.5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.36. Raw data for IB+ @ +/-2.5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB+ @ +/-2.5V VCM=V-	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	-2.19E-05	-2.18E-05	-2.18E-05	-2.19E-05	-2.19E-05	-2.20E-05
62	-2.22E-05	-2.21E-05	-2.22E-05	-2.24E-05	-2.26E-05	-2.29E-05
63	-2.24E-05	-2.23E-05	-2.23E-05	-2.25E-05	-2.25E-05	-2.25E-05
64	-2.23E-05	-2.22E-05	-2.22E-05	-2.24E-05	-2.24E-05	-2.24E-05
65	-2.15E-05	-2.13E-05	-2.14E-05	-2.14E-05	-2.14E-05	-2.15E-05
66	-2.25E-05	-2.25E-05	-2.25E-05	-2.26E-05	-2.27E-05	-2.29E-05
67	-2.13E-05	-2.13E-05	-2.13E-05	-2.14E-05	-2.16E-05	-2.20E-05
68	-2.22E-05	-2.22E-05	-2.22E-05	-2.24E-05	-2.24E-05	-2.27E-05
69	-2.26E-05	-2.26E-05	-2.27E-05	-2.28E-05	-2.30E-05	-2.37E-05
70	-2.19E-05	-2.19E-05	-2.20E-05	-2.21E-05	-2.21E-05	-2.24E-05
71	-2.20E-05	-2.19E-05	-2.19E-05	-2.19E-05	-2.19E-05	-2.19E-05
72	-2.14E-05	-2.13E-05	-2.13E-05	-2.13E-05	-2.13E-05	-2.13E-05
Biased Statistics						
Average Biased	-2.21E-05	-2.19E-05	-2.20E-05	-2.21E-05	-2.22E-05	-2.23E-05
Std Dev Biased	3.92E-07	4.01E-07	3.93E-07	4.27E-07	4.89E-07	5.65E-07
Ps90%/90% (+KTL) Biased	-2.10E-05	-2.08E-05	-2.09E-05	-2.09E-05	-2.08E-05	-2.07E-05
Ps90%/90% (-KTL) Biased	-2.31E-05	-2.30E-05	-2.31E-05	-2.33E-05	-2.35E-05	-2.38E-05
Un-Biased Statistics						
Average Un-Biased	-2.21E-05	-2.21E-05	-2.22E-05	-2.22E-05	-2.24E-05	-2.27E-05
Std Dev Un-Biased	5.28E-07	5.28E-07	5.26E-07	5.33E-07	5.35E-07	6.12E-07
Ps90%/90% (+KTL) Un-Biased	-2.06E-05	-2.07E-05	-2.07E-05	-2.08E-05	-2.09E-05	-2.11E-05
Ps90%/90% (-KTL) Un-Biased	-2.35E-05	-2.36E-05	-2.36E-05	-2.37E-05	-2.39E-05	-2.44E-05
Specification MIN	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

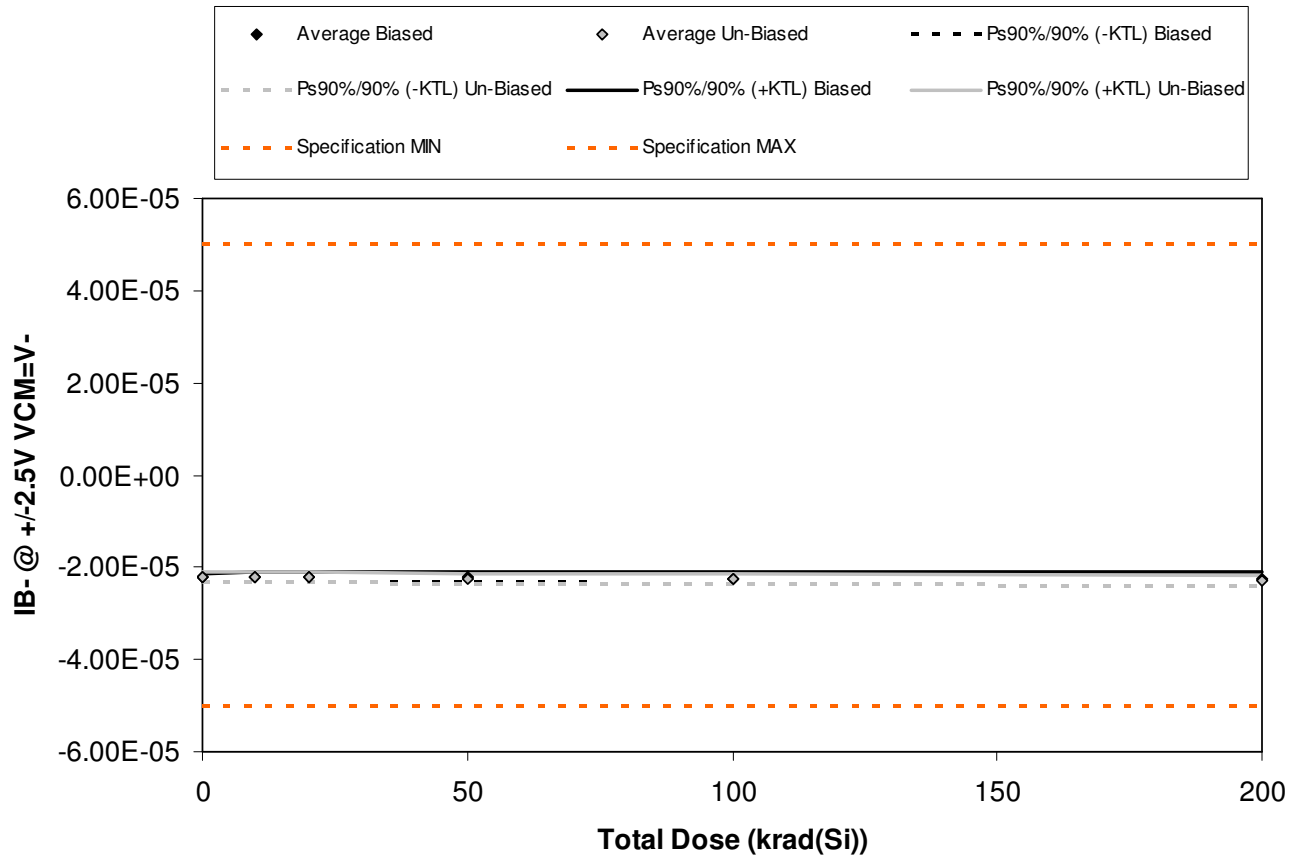


Figure 5.37. Plot of IB- @ +/-2.5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.37. Raw data for IB- @ +/-2.5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB- @ +/-2.5V VCM=V- Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	-2.25E-05	-2.24E-05	-2.24E-05	-2.25E-05	-2.25E-05	-2.25E-05
62	-2.23E-05	-2.22E-05	-2.22E-05	-2.24E-05	-2.27E-05	-2.31E-05
63	-2.26E-05	-2.24E-05	-2.25E-05	-2.26E-05	-2.27E-05	-2.26E-05
64	-2.24E-05	-2.23E-05	-2.24E-05	-2.25E-05	-2.25E-05	-2.25E-05
65	-2.16E-05	-2.15E-05	-2.15E-05	-2.16E-05	-2.16E-05	-2.16E-05
66	-2.27E-05	-2.27E-05	-2.27E-05	-2.27E-05	-2.29E-05	-2.30E-05
67	-2.15E-05	-2.15E-05	-2.15E-05	-2.17E-05	-2.19E-05	-2.23E-05
68	-2.23E-05	-2.23E-05	-2.23E-05	-2.24E-05	-2.25E-05	-2.28E-05
69	-2.24E-05	-2.24E-05	-2.24E-05	-2.26E-05	-2.28E-05	-2.34E-05
70	-2.22E-05	-2.23E-05	-2.23E-05	-2.24E-05	-2.25E-05	-2.27E-05
71	-2.20E-05	-2.19E-05	-2.19E-05	-2.19E-05	-2.19E-05	-2.19E-05
72	-2.16E-05	-2.15E-05	-2.15E-05	-2.15E-05	-2.15E-05	-2.16E-05
Biased Statistics						
Average Biased	-2.23E-05	-2.21E-05	-2.22E-05	-2.23E-05	-2.24E-05	-2.25E-05
Std Dev Biased	3.76E-07	3.96E-07	3.87E-07	4.11E-07	4.57E-07	5.40E-07
Ps90%/90% (+KTL) Biased	-2.12E-05	-2.11E-05	-2.11E-05	-2.12E-05	-2.11E-05	-2.10E-05
Ps90%/90% (-KTL) Biased	-2.33E-05	-2.32E-05	-2.33E-05	-2.35E-05	-2.37E-05	-2.40E-05
Un-Biased Statistics						
Average Un-Biased	-2.22E-05	-2.22E-05	-2.23E-05	-2.24E-05	-2.25E-05	-2.28E-05
Std Dev Un-Biased	4.38E-07	4.37E-07	4.30E-07	4.19E-07	3.99E-07	4.09E-07
Ps90%/90% (+KTL) Un-Biased	-2.10E-05	-2.10E-05	-2.11E-05	-2.12E-05	-2.14E-05	-2.17E-05
Ps90%/90% (-KTL) Un-Biased	-2.34E-05	-2.34E-05	-2.34E-05	-2.35E-05	-2.36E-05	-2.39E-05
Specification MIN	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

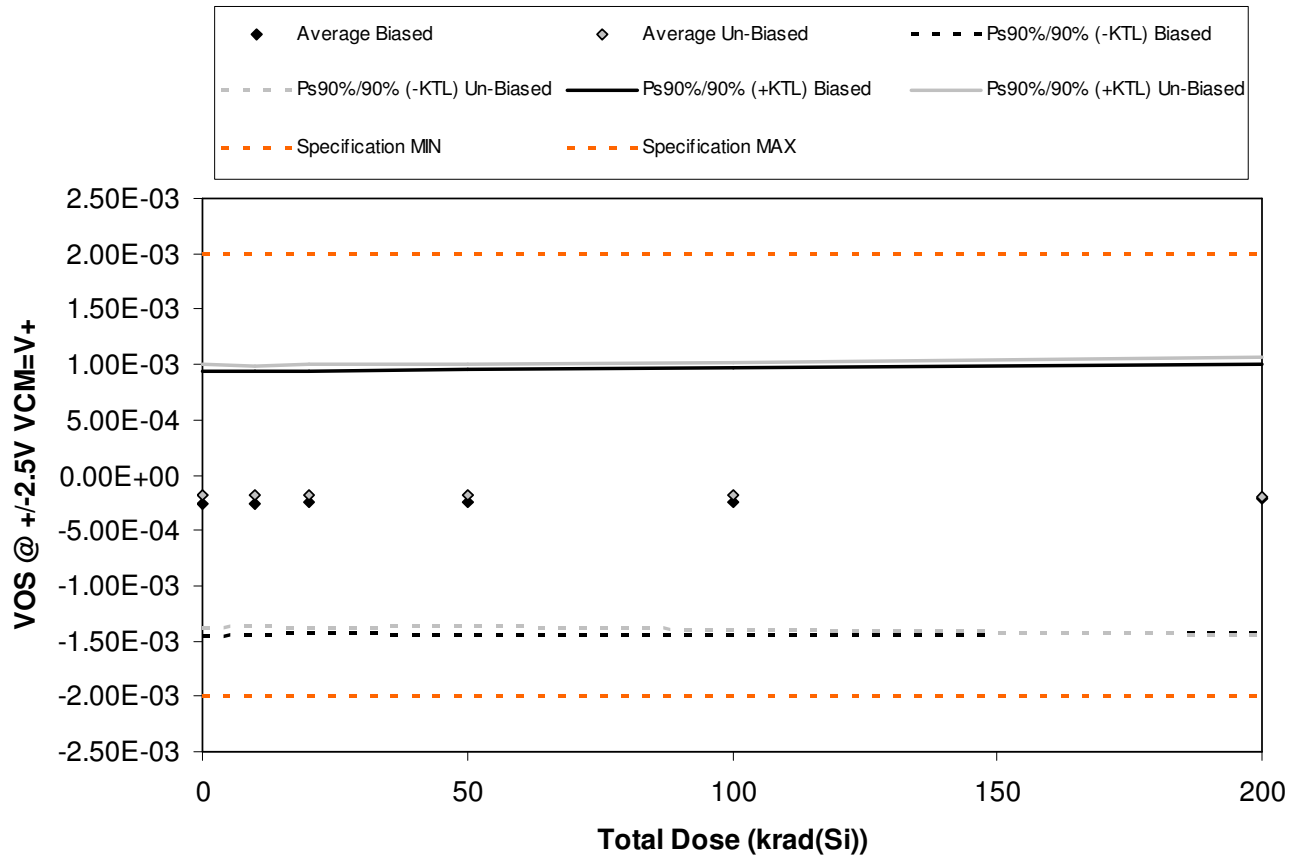


Figure 5.38. Plot of VOS @ +/-2.5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.38. Raw data for VOS @ +/-2.5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOS @ +/-2.5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.97E-04	1.97E-04	1.97E-04	2.10E-04	2.14E-04	2.41E-04
62	-4.44E-04	-4.40E-04	-4.34E-04	-4.22E-04	-4.10E-04	-3.76E-04
63	-7.51E-04	-7.51E-04	-7.41E-04	-7.43E-04	-7.38E-04	-7.38E-04
64	2.17E-04	2.12E-04	2.17E-04	2.22E-04	2.34E-04	2.46E-04
65	-4.95E-04	-4.95E-04	-4.83E-04	-4.83E-04	-4.83E-04	-4.71E-04
66	-7.51E-04	-7.38E-04	-7.48E-04	-7.46E-04	-7.50E-04	-7.75E-04
67	5.10E-05	5.10E-05	5.20E-05	5.60E-05	5.40E-05	6.10E-05
68	5.00E-06	3.00E-06	3.00E-06	3.00E-06	-4.00E-06	-9.00E-06
69	-5.32E-04	-5.20E-04	-5.22E-04	-5.20E-04	-5.32E-04	-5.56E-04
70	2.90E-04	2.89E-04	2.95E-04	2.95E-04	3.07E-04	3.19E-04
71	-5.80E-04	-5.68E-04	-5.68E-04	-5.68E-04	-5.68E-04	-5.78E-04
72	1.61E-04	1.53E-04	1.58E-04	1.51E-04	1.53E-04	1.49E-04
Biased Statistics						
Average Biased	-2.55E-04	-2.55E-04	-2.49E-04	-2.43E-04	-2.37E-04	-2.20E-04
Std Dev Biased	4.38E-04	4.36E-04	4.32E-04	4.36E-04	4.38E-04	4.43E-04
Ps90%/90% (+KTL) Biased	9.45E-04	9.40E-04	9.36E-04	9.53E-04	9.64E-04	9.95E-04
Ps90%/90% (-KTL) Biased	-1.46E-03	-1.45E-03	-1.43E-03	-1.44E-03	-1.44E-03	-1.43E-03
Un-Biased Statistics						
Average Un-Biased	-1.87E-04	-1.83E-04	-1.84E-04	-1.82E-04	-1.85E-04	-1.92E-04
Std Dev Un-Biased	4.35E-04	4.28E-04	4.34E-04	4.33E-04	4.39E-04	4.56E-04
Ps90%/90% (+KTL) Un-Biased	1.01E-03	9.91E-04	1.01E-03	1.01E-03	1.02E-03	1.06E-03
Ps90%/90% (-KTL) Un-Biased	-1.38E-03	-1.36E-03	-1.37E-03	-1.37E-03	-1.39E-03	-1.44E-03
Specification MIN	-2.00E-03	-2.00E-03	-2.00E-03	-2.00E-03	-2.00E-03	-2.00E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	2.00E-03	2.00E-03	2.00E-03	2.00E-03	2.00E-03	2.00E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS

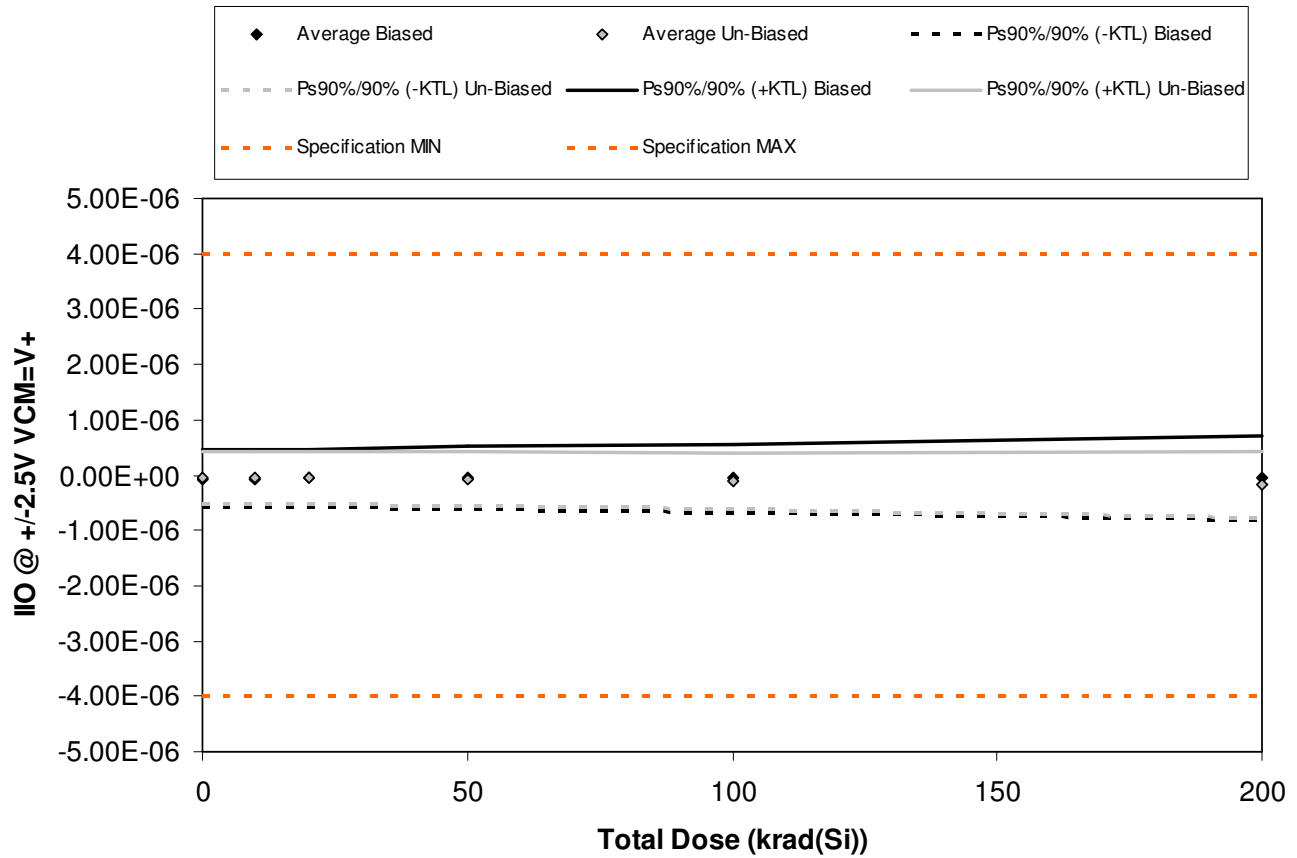


Figure 5.39. Plot of IIO @ +/-2.5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.39. Raw data for IIO @ +/-2.5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IIO @ +/-2.5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.31E-07	1.31E-07	1.36E-07	1.48E-07	1.65E-07	2.01E-07
62	-1.63E-07	-1.69E-07	-1.69E-07	-1.73E-07	-1.87E-07	-2.06E-07
63	-2.63E-07	-2.62E-07	-2.65E-07	-2.77E-07	-3.09E-07	-4.05E-07
64	1.46E-07	1.52E-07	1.56E-07	1.76E-07	2.00E-07	2.46E-07
65	-1.71E-07	-1.71E-07	-1.70E-07	-1.65E-07	-1.54E-07	-1.34E-07
66	-2.57E-07	-2.57E-07	-2.57E-07	-2.64E-07	-2.80E-07	-3.14E-07
67	2.20E-08	1.90E-08	1.10E-08	-1.50E-08	-5.60E-08	-1.68E-07
68	4.50E-08	4.10E-08	3.40E-08	2.60E-08	-3.50E-08	-1.59E-07
69	-1.80E-07	-1.84E-07	-1.94E-07	-2.26E-07	-2.72E-07	-4.14E-07
70	1.50E-07	1.53E-07	1.52E-07	1.53E-07	1.58E-07	1.60E-07
71	-2.25E-07	-2.21E-07	-2.21E-07	-2.21E-07	-2.22E-07	-2.22E-07
72	1.11E-07	1.12E-07	1.12E-07	1.12E-07	1.12E-07	1.11E-07
Biased Statistics						
Average Biased	-6.40E-08	-6.38E-08	-6.24E-08	-5.82E-08	-5.70E-08	-5.96E-08
Std Dev Biased	1.89E-07	1.91E-07	1.94E-07	2.06E-07	2.26E-07	2.77E-07
Ps90%/90% (+KTL) Biased	4.54E-07	4.61E-07	4.70E-07	5.07E-07	5.64E-07	7.01E-07
Ps90%/90% (-KTL) Biased	-5.82E-07	-5.88E-07	-5.95E-07	-6.23E-07	-6.78E-07	-8.20E-07
Un-Biased Statistics						
Average Un-Biased	-4.40E-08	-4.56E-08	-5.08E-08	-6.52E-08	-9.70E-08	-1.79E-07
Std Dev Un-Biased	1.69E-07	1.70E-07	1.70E-07	1.76E-07	1.83E-07	2.17E-07
Ps90%/90% (+KTL) Un-Biased	4.18E-07	4.19E-07	4.14E-07	4.17E-07	4.06E-07	4.17E-07
Ps90%/90% (-KTL) Un-Biased	-5.06E-07	-5.10E-07	-5.16E-07	-5.48E-07	-6.00E-07	-7.75E-07
Specification MIN	-4.00E-06	-4.00E-06	-4.00E-06	-4.00E-06	-4.00E-06	-4.00E-06
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	4.00E-06	4.00E-06	4.00E-06	4.00E-06	4.00E-06	4.00E-06
Status	PASS	PASS	PASS	PASS	PASS	PASS

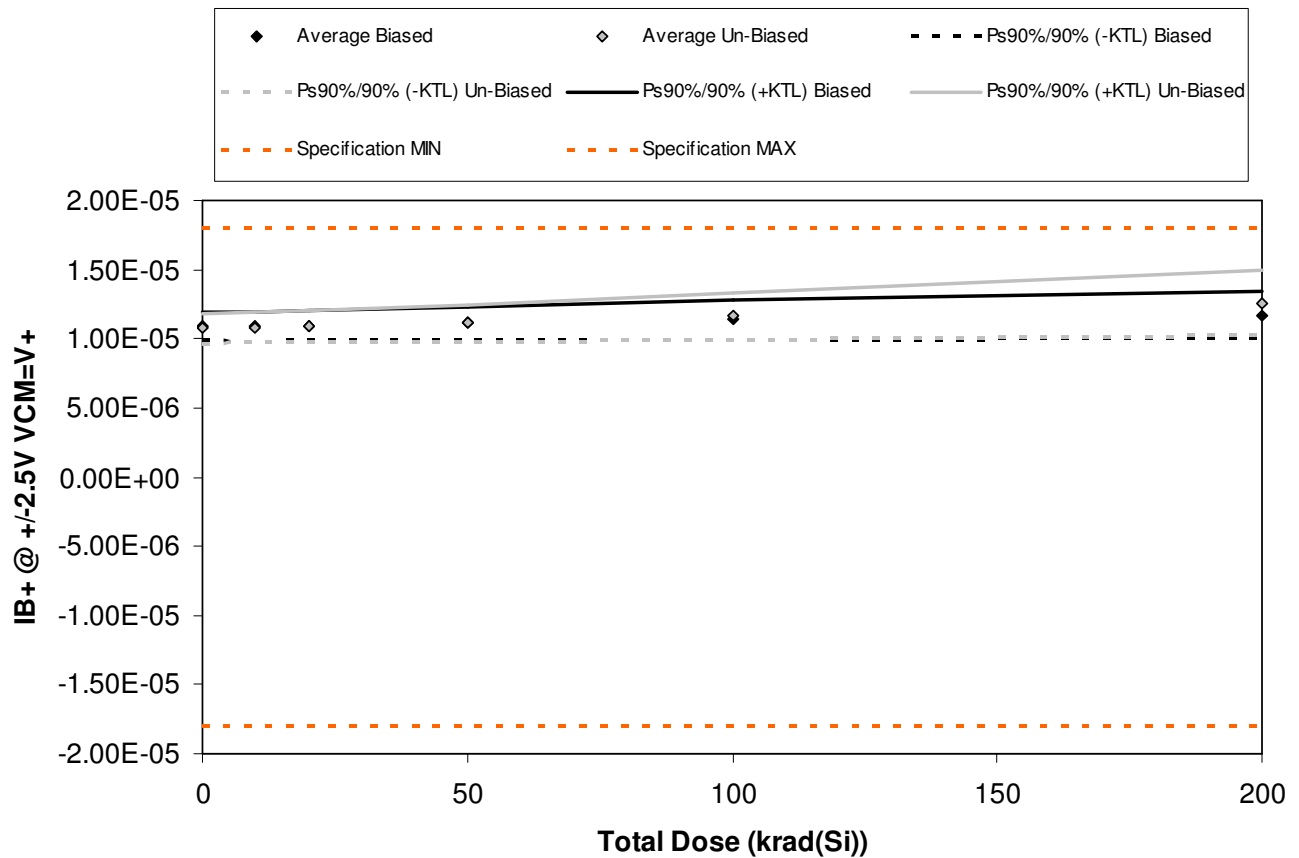


Figure 5.40. Plot of IB+ @ +/-2.5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.40. Raw data for IB+ @ +/-2.5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB+ @ +/-2.5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.10E-05	1.10E-05	1.11E-05	1.12E-05	1.13E-05	1.16E-05
62	1.11E-05	1.11E-05	1.12E-05	1.15E-05	1.19E-05	1.25E-05
63	1.08E-05	1.08E-05	1.09E-05	1.10E-05	1.13E-05	1.16E-05
64	1.13E-05	1.13E-05	1.13E-05	1.15E-05	1.17E-05	1.21E-05
65	1.03E-05	1.03E-05	1.03E-05	1.04E-05	1.06E-05	1.08E-05
66	1.01E-05	1.01E-05	1.01E-05	1.03E-05	1.06E-05	1.11E-05
67	1.10E-05	1.11E-05	1.11E-05	1.15E-05	1.21E-05	1.32E-05
68	1.09E-05	1.10E-05	1.10E-05	1.12E-05	1.17E-05	1.28E-05
69	1.09E-05	1.10E-05	1.11E-05	1.15E-05	1.20E-05	1.32E-05
70	1.09E-05	1.10E-05	1.10E-05	1.13E-05	1.17E-05	1.26E-05
71	1.06E-05	1.06E-05	1.06E-05	1.06E-05	1.06E-05	1.06E-05
72	1.12E-05	1.12E-05	1.12E-05	1.12E-05	1.12E-05	1.12E-05
Biased Statistics						
Average Biased	1.09E-05	1.09E-05	1.10E-05	1.11E-05	1.14E-05	1.17E-05
Std Dev Biased	3.73E-07	3.95E-07	4.07E-07	4.43E-07	5.10E-07	6.19E-07
Ps90%/90% (+KTL) Biased	1.19E-05	1.20E-05	1.21E-05	1.23E-05	1.28E-05	1.34E-05
Ps90%/90% (-KTL) Biased	9.87E-06	9.82E-06	9.84E-06	9.92E-06	9.96E-06	1.00E-05
Un-Biased Statistics						
Average Un-Biased	1.07E-05	1.08E-05	1.09E-05	1.11E-05	1.16E-05	1.26E-05
Std Dev Un-Biased	3.81E-07	4.04E-07	4.21E-07	4.89E-07	6.21E-07	8.51E-07
Ps90%/90% (+KTL) Un-Biased	1.18E-05	1.19E-05	1.21E-05	1.25E-05	1.33E-05	1.49E-05
Ps90%/90% (-KTL) Un-Biased	9.70E-06	9.72E-06	9.74E-06	9.79E-06	9.92E-06	1.02E-05
Specification MIN	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

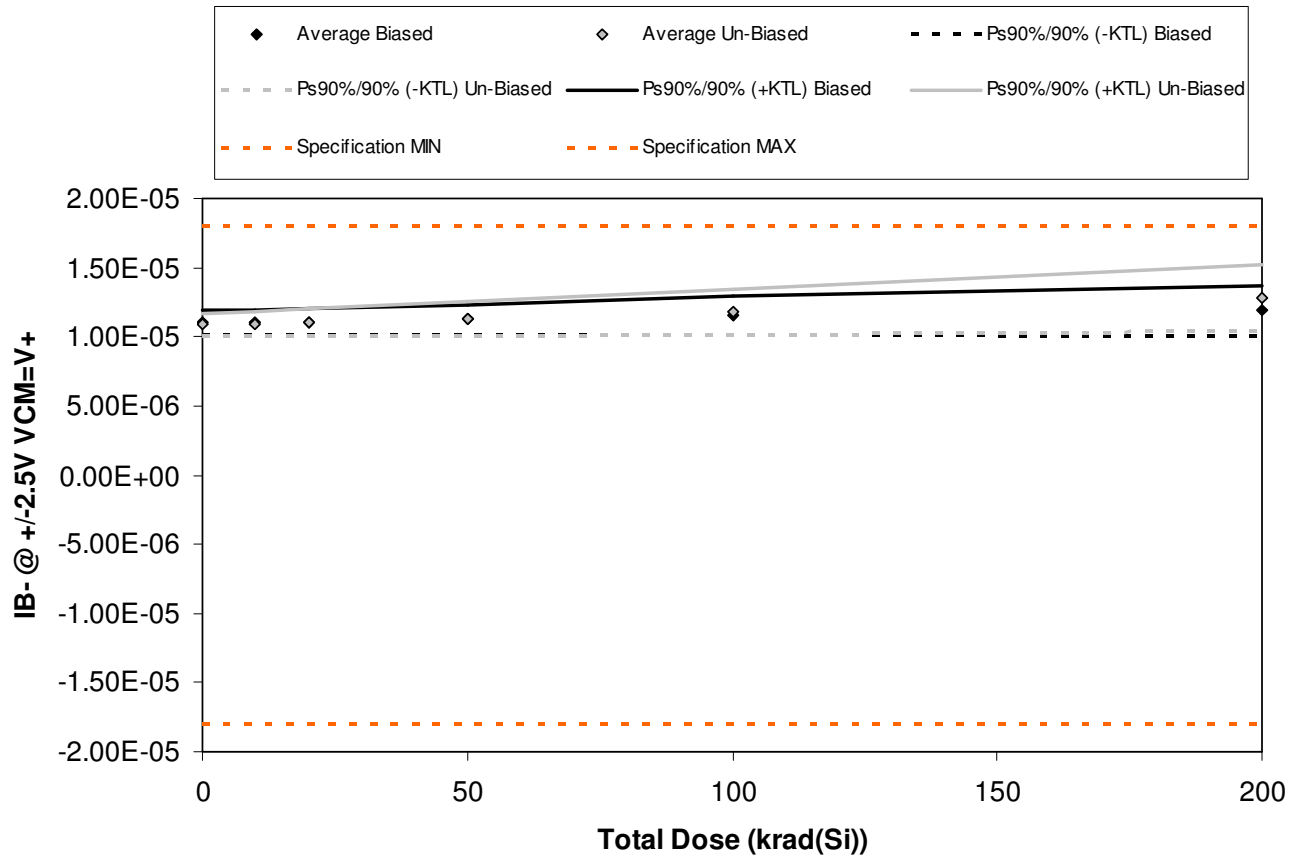


Figure 5.41. Plot of IB- @ +/-2.5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.41. Raw data for IB- @ +/-2.5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB- @ +/-2.5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.10E-05	1.10E-05	1.10E-05	1.11E-05	1.13E-05	1.15E-05
62	1.13E-05	1.14E-05	1.15E-05	1.18E-05	1.22E-05	1.28E-05
63	1.11E-05	1.12E-05	1.12E-05	1.14E-05	1.17E-05	1.21E-05
64	1.12E-05	1.12E-05	1.12E-05	1.14E-05	1.16E-05	1.19E-05
65	1.05E-05	1.05E-05	1.06E-05	1.07E-05	1.08E-05	1.11E-05
66	1.04E-05	1.04E-05	1.04E-05	1.06E-05	1.09E-05	1.15E-05
67	1.10E-05	1.11E-05	1.12E-05	1.16E-05	1.23E-05	1.35E-05
68	1.09E-05	1.10E-05	1.11E-05	1.12E-05	1.18E-05	1.30E-05
69	1.12E-05	1.13E-05	1.14E-05	1.18E-05	1.24E-05	1.37E-05
70	1.08E-05	1.09E-05	1.10E-05	1.12E-05	1.16E-05	1.25E-05
71	1.09E-05	1.09E-05	1.09E-05	1.09E-05	1.09E-05	1.09E-05
72	1.11E-05	1.12E-05	1.12E-05	1.12E-05	1.12E-05	1.12E-05
Biased Statistics						
Average Biased	1.10E-05	1.10E-05	1.11E-05	1.13E-05	1.15E-05	1.19E-05
Std Dev Biased	3.02E-07	3.32E-07	3.45E-07	3.97E-07	4.98E-07	6.57E-07
Ps90%/90% (+KTL) Biased	1.19E-05	1.20E-05	1.20E-05	1.24E-05	1.29E-05	1.37E-05
Ps90%/90% (-KTL) Biased	1.02E-05	1.01E-05	1.02E-05	1.02E-05	1.01E-05	1.01E-05
Un-Biased Statistics						
Average Un-Biased	1.09E-05	1.09E-05	1.10E-05	1.13E-05	1.18E-05	1.28E-05
Std Dev Un-Biased	3.09E-07	3.32E-07	3.59E-07	4.48E-07	5.98E-07	8.77E-07
Ps90%/90% (+KTL) Un-Biased	1.17E-05	1.19E-05	1.20E-05	1.25E-05	1.34E-05	1.53E-05
Ps90%/90% (-KTL) Un-Biased	1.00E-05	1.00E-05	1.00E-05	1.00E-05	1.02E-05	1.04E-05
Specification MIN	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

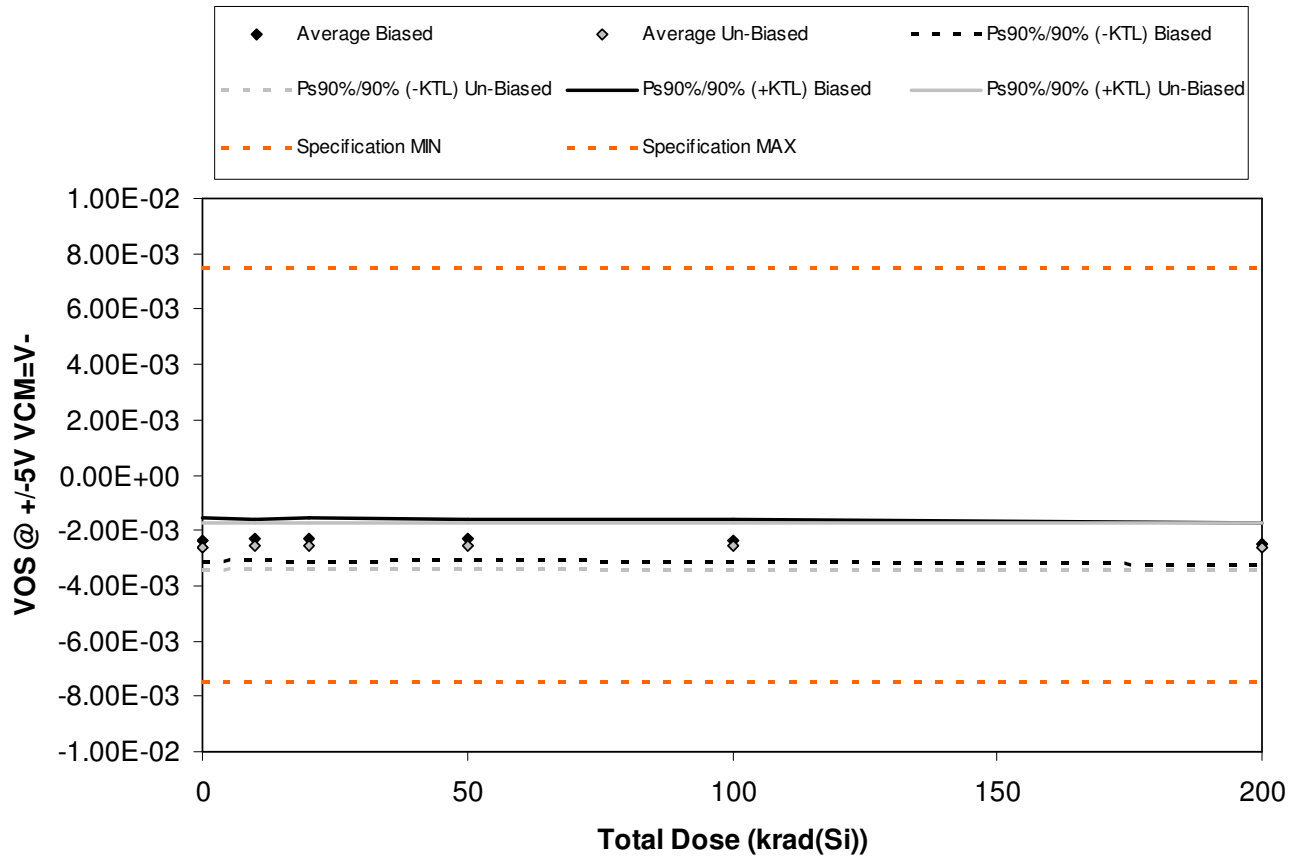


Figure 5.42. Plot of VOS @ +/-5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.42. Raw data for VOS @ +/-5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOS @ +/-5V VCM=V-	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	-1.86E-03	-1.87E-03	-1.86E-03	-1.87E-03	-1.92E-03	-2.01E-03
62	-2.54E-03	-2.52E-03	-2.51E-03	-2.52E-03	-2.58E-03	-2.63E-03
63	-2.33E-03	-2.30E-03	-2.31E-03	-2.31E-03	-2.32E-03	-2.47E-03
64	-2.47E-03	-2.44E-03	-2.46E-03	-2.45E-03	-2.48E-03	-2.65E-03
65	-2.53E-03	-2.50E-03	-2.52E-03	-2.50E-03	-2.56E-03	-2.69E-03
66	-2.79E-03	-2.77E-03	-2.77E-03	-2.77E-03	-2.79E-03	-2.82E-03
67	-2.33E-03	-2.31E-03	-2.31E-03	-2.31E-03	-2.31E-03	-2.33E-03
68	-2.57E-03	-2.55E-03	-2.55E-03	-2.58E-03	-2.55E-03	-2.59E-03
69	-2.99E-03	-2.95E-03	-2.95E-03	-2.95E-03	-2.96E-03	-3.00E-03
70	-2.27E-03	-2.25E-03	-2.25E-03	-2.24E-03	-2.24E-03	-2.26E-03
71	-2.60E-03	-2.56E-03	-2.56E-03	-2.56E-03	-2.57E-03	-2.57E-03
72	-2.32E-03	-2.29E-03	-2.29E-03	-2.30E-03	-2.29E-03	-2.31E-03
Biased Statistics						
Average Biased	-2.34E-03	-2.33E-03	-2.33E-03	-2.33E-03	-2.37E-03	-2.49E-03
Std Dev Biased	2.85E-04	2.70E-04	2.78E-04	2.71E-04	2.72E-04	2.83E-04
Ps90%/90% (+KTL) Biased	-1.56E-03	-1.59E-03	-1.57E-03	-1.59E-03	-1.62E-03	-1.71E-03
Ps90%/90% (-KTL) Biased	-3.13E-03	-3.07E-03	-3.09E-03	-3.07E-03	-3.12E-03	-3.27E-03
Un-Biased Statistics						
Average Un-Biased	-2.59E-03	-2.56E-03	-2.57E-03	-2.57E-03	-2.57E-03	-2.60E-03
Std Dev Un-Biased	3.02E-04	2.98E-04	2.98E-04	3.00E-04	3.09E-04	3.14E-04
Ps90%/90% (+KTL) Un-Biased	-1.76E-03	-1.75E-03	-1.75E-03	-1.75E-03	-1.72E-03	-1.74E-03
Ps90%/90% (-KTL) Un-Biased	-3.42E-03	-3.38E-03	-3.38E-03	-3.39E-03	-3.42E-03	-3.46E-03
Specification MIN	-7.50E-03	-7.50E-03	-7.50E-03	-7.50E-03	-7.50E-03	-7.50E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	7.50E-03	7.50E-03	7.50E-03	7.50E-03	7.50E-03	7.50E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS

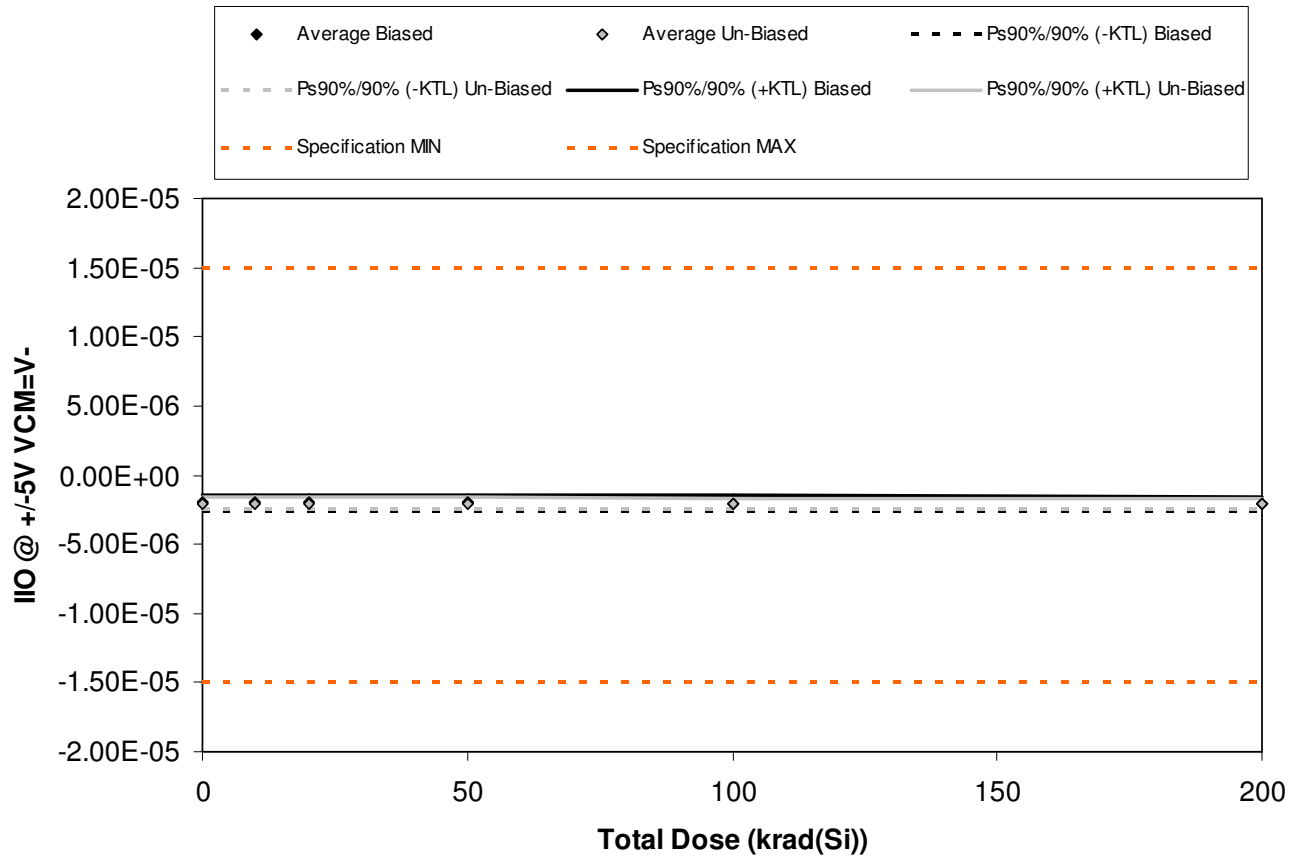


Figure 5.43. Plot of IIO @ +/-5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.43. Raw data for IIO @ +/-5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IIO @ +/-5V VCM=V- Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	-1.62E-06	-1.62E-06	-1.63E-06	-1.64E-06	-1.68E-06	-1.74E-06
62	-2.12E-06	-2.11E-06	-2.12E-06	-2.14E-06	-2.16E-06	-2.14E-06
63	-1.98E-06	-1.96E-06	-1.97E-06	-1.98E-06	-1.99E-06	-2.04E-06
64	-2.12E-06	-2.11E-06	-2.12E-06	-2.13E-06	-2.17E-06	-2.22E-06
65	-2.07E-06	-2.06E-06	-2.07E-06	-2.07E-06	-2.10E-06	-2.14E-06
66	-2.02E-06	-2.01E-06	-2.02E-06	-2.02E-06	-2.04E-06	-2.07E-06
67	-1.87E-06	-1.87E-06	-1.87E-06	-1.87E-06	-1.89E-06	-1.95E-06
68	-2.18E-06	-2.18E-06	-2.18E-06	-2.21E-06	-2.21E-06	-2.26E-06
69	-2.24E-06	-2.25E-06	-2.25E-06	-2.25E-06	-2.24E-06	-2.24E-06
70	-1.94E-06	-1.94E-06	-1.94E-06	-1.95E-06	-1.96E-06	-1.99E-06
71	-2.16E-06	-2.15E-06	-2.15E-06	-2.15E-06	-2.15E-06	-2.15E-06
72	-1.89E-06	-1.88E-06	-1.88E-06	-1.88E-06	-1.88E-06	-1.89E-06
Biased Statistics						
Average Biased	-1.98E-06	-1.97E-06	-1.98E-06	-1.99E-06	-2.02E-06	-2.06E-06
Std Dev Biased	2.11E-07	2.05E-07	2.08E-07	2.08E-07	2.04E-07	1.86E-07
Ps90%/90% (+KTL) Biased	-1.40E-06	-1.41E-06	-1.41E-06	-1.42E-06	-1.46E-06	-1.55E-06
Ps90%/90% (-KTL) Biased	-2.56E-06	-2.53E-06	-2.55E-06	-2.56E-06	-2.58E-06	-2.56E-06
Un-Biased Statistics						
Average Un-Biased	-2.05E-06	-2.05E-06	-2.05E-06	-2.06E-06	-2.07E-06	-2.10E-06
Std Dev Un-Biased	1.55E-07	1.60E-07	1.59E-07	1.62E-07	1.56E-07	1.43E-07
Ps90%/90% (+KTL) Un-Biased	-1.63E-06	-1.61E-06	-1.61E-06	-1.61E-06	-1.64E-06	-1.71E-06
Ps90%/90% (-KTL) Un-Biased	-2.48E-06	-2.49E-06	-2.49E-06	-2.50E-06	-2.49E-06	-2.49E-06
Specification MIN	-1.50E-05	-1.50E-05	-1.50E-05	-1.50E-05	-1.50E-05	-1.50E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	1.50E-05	1.50E-05	1.50E-05	1.50E-05	1.50E-05	1.50E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

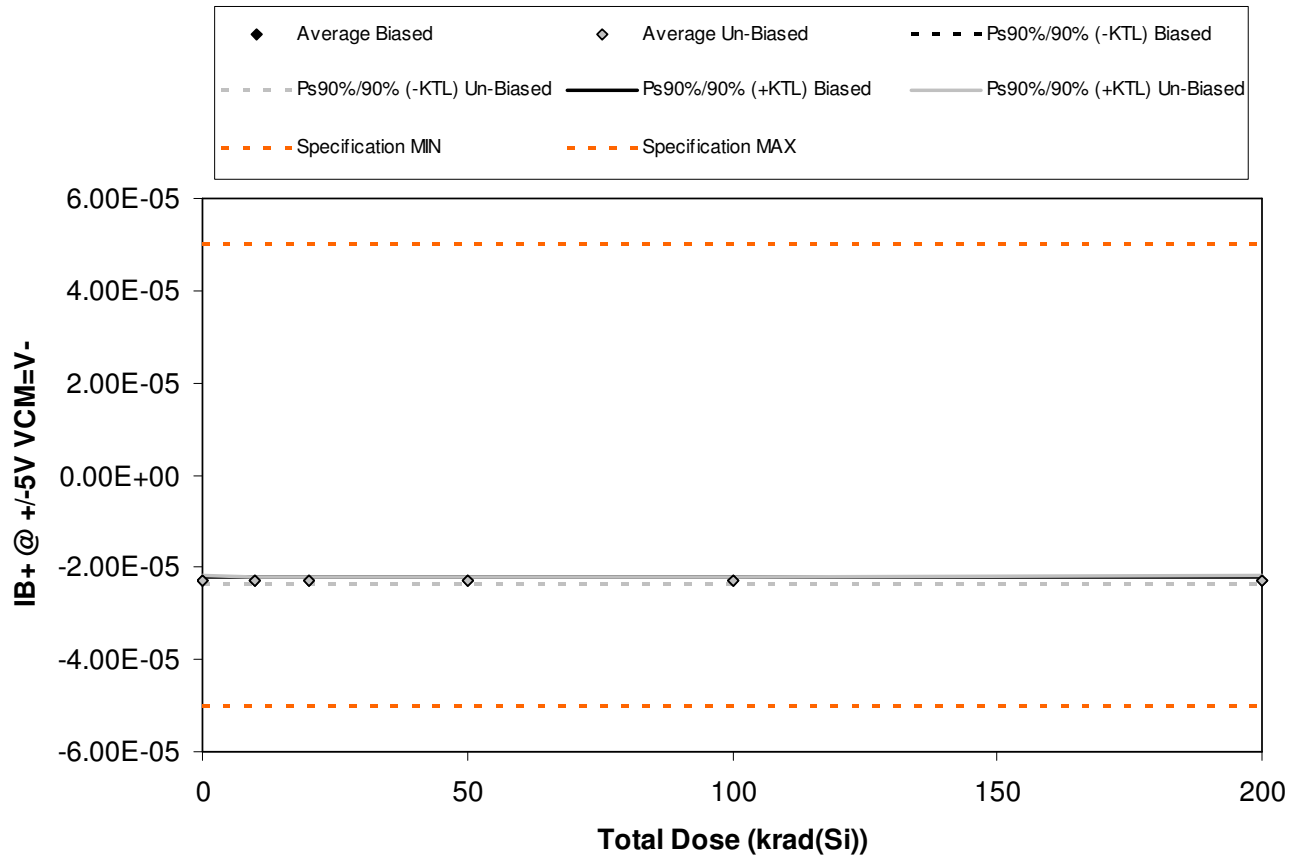


Figure 5.44. Plot of IB+ @ +/-5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.44. Raw data for IB+ @ +/-5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB+ @ +/-5V VCM=V- Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	-2.35E-05	-2.35E-05	-2.35E-05	-2.35E-05	-2.35E-05	-2.34E-05
62	-2.28E-05	-2.29E-05	-2.29E-05	-2.29E-05	-2.28E-05	-2.28E-05
63	-2.30E-05	-2.31E-05	-2.31E-05	-2.31E-05	-2.31E-05	-2.29E-05
64	-2.29E-05	-2.29E-05	-2.29E-05	-2.30E-05	-2.29E-05	-2.28E-05
65	-2.28E-05	-2.29E-05	-2.29E-05	-2.29E-05	-2.28E-05	-2.27E-05
66	-2.26E-05	-2.26E-05	-2.26E-05	-2.26E-05	-2.26E-05	-2.26E-05
67	-2.30E-05	-2.31E-05	-2.31E-05	-2.31E-05	-2.31E-05	-2.31E-05
68	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05
69	-2.24E-05	-2.24E-05	-2.24E-05	-2.25E-05	-2.24E-05	-2.24E-05
70	-2.31E-05	-2.31E-05	-2.31E-05	-2.32E-05	-2.32E-05	-2.31E-05
71	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05
72	-2.31E-05	-2.31E-05	-2.31E-05	-2.31E-05	-2.31E-05	-2.31E-05
Biased Statistics						
Average Biased	-2.30E-05	-2.31E-05	-2.31E-05	-2.31E-05	-2.30E-05	-2.29E-05
Std Dev Biased	2.86E-07	2.71E-07	2.78E-07	2.71E-07	2.70E-07	2.82E-07
Ps90%/90% (+KTL) Biased	-2.22E-05	-2.23E-05	-2.23E-05	-2.23E-05	-2.23E-05	-2.21E-05
Ps90%/90% (-KTL) Biased	-2.38E-05	-2.38E-05	-2.38E-05	-2.38E-05	-2.38E-05	-2.37E-05
Un-Biased Statistics						
Average Un-Biased	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05	-2.28E-05
Std Dev Un-Biased	3.05E-07	2.98E-07	3.02E-07	3.01E-07	3.07E-07	3.19E-07
Ps90%/90% (+KTL) Un-Biased	-2.19E-05	-2.20E-05	-2.20E-05	-2.20E-05	-2.20E-05	-2.19E-05
Ps90%/90% (-KTL) Un-Biased	-2.36E-05	-2.36E-05	-2.37E-05	-2.37E-05	-2.37E-05	-2.37E-05
Specification MIN	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

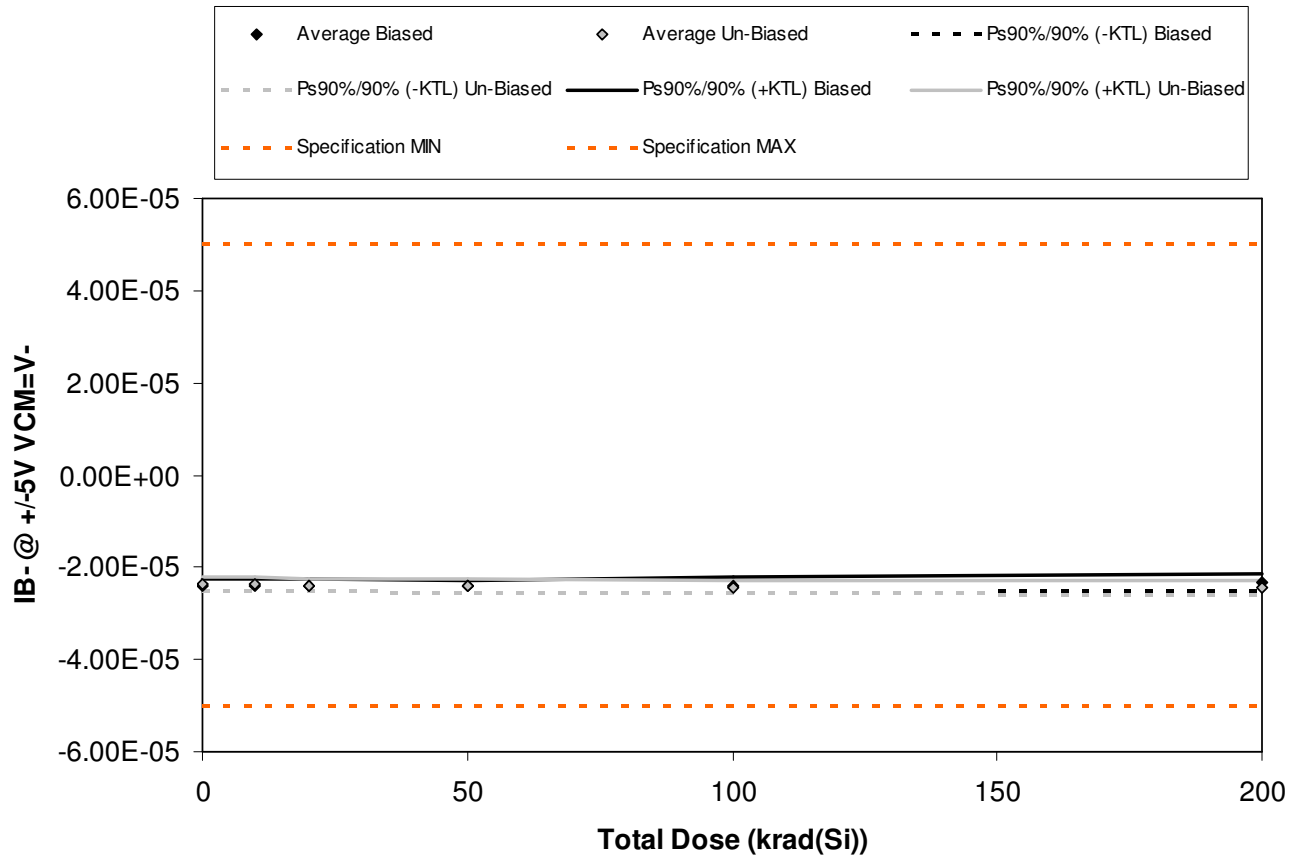


Figure 5.45. Plot of IB- @ +/-5V VCM=V- versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.45. Raw data for IB- @ +/-5V VCM=V- versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB- @ +/-5V VCM=V- Device	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	-2.41E-05	-2.41E-05	-2.42E-05	-2.44E-05	-2.39E-05	-2.33E-05
62	-2.38E-05	-2.38E-05	-2.38E-05	-2.43E-05	-2.41E-05	-2.42E-05
63	-2.44E-05	-2.44E-05	-2.44E-05	-2.46E-05	-2.45E-05	-2.34E-05
64	-2.41E-05	-2.41E-05	-2.41E-05	-2.44E-05	-2.43E-05	-2.30E-05
65	-2.31E-05	-2.30E-05	-2.31E-05	-2.33E-05	-2.29E-05	-2.23E-05
66	-2.44E-05	-2.44E-05	-2.45E-05	-2.46E-05	-2.47E-05	-2.49E-05
67	-2.29E-05	-2.29E-05	-2.30E-05	-2.31E-05	-2.34E-05	-2.38E-05
68	-2.38E-05	-2.38E-05	-2.39E-05	-2.42E-05	-2.43E-05	-2.44E-05
69	-2.41E-05	-2.41E-05	-2.41E-05	-2.43E-05	-2.46E-05	-2.52E-05
70	-2.37E-05	-2.37E-05	-2.38E-05	-2.41E-05	-2.42E-05	-2.44E-05
71	-2.35E-05	-2.35E-05	-2.35E-05	-2.35E-05	-2.35E-05	-2.35E-05
72	-2.31E-05	-2.30E-05	-2.30E-05	-2.30E-05	-2.30E-05	-2.30E-05
Biased Statistics						
Average Biased	-2.39E-05	-2.39E-05	-2.39E-05	-2.42E-05	-2.39E-05	-2.32E-05
Std Dev Biased	5.16E-07	5.20E-07	5.07E-07	5.17E-07	6.21E-07	6.72E-07
Ps90%/90% (+KTL) Biased	-2.25E-05	-2.25E-05	-2.25E-05	-2.27E-05	-2.22E-05	-2.14E-05
Ps90%/90% (-KTL) Biased	-2.53E-05	-2.53E-05	-2.53E-05	-2.56E-05	-2.56E-05	-2.51E-05
Un-Biased Statistics						
Average Un-Biased	-2.38E-05	-2.38E-05	-2.39E-05	-2.40E-05	-2.42E-05	-2.45E-05
Std Dev Un-Biased	5.55E-07	5.53E-07	5.46E-07	5.41E-07	5.15E-07	5.31E-07
Ps90%/90% (+KTL) Un-Biased	-2.23E-05	-2.23E-05	-2.24E-05	-2.26E-05	-2.28E-05	-2.31E-05
Ps90%/90% (-KTL) Un-Biased	-2.53E-05	-2.53E-05	-2.54E-05	-2.55E-05	-2.57E-05	-2.60E-05
Specification MIN	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05	-5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05	5.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

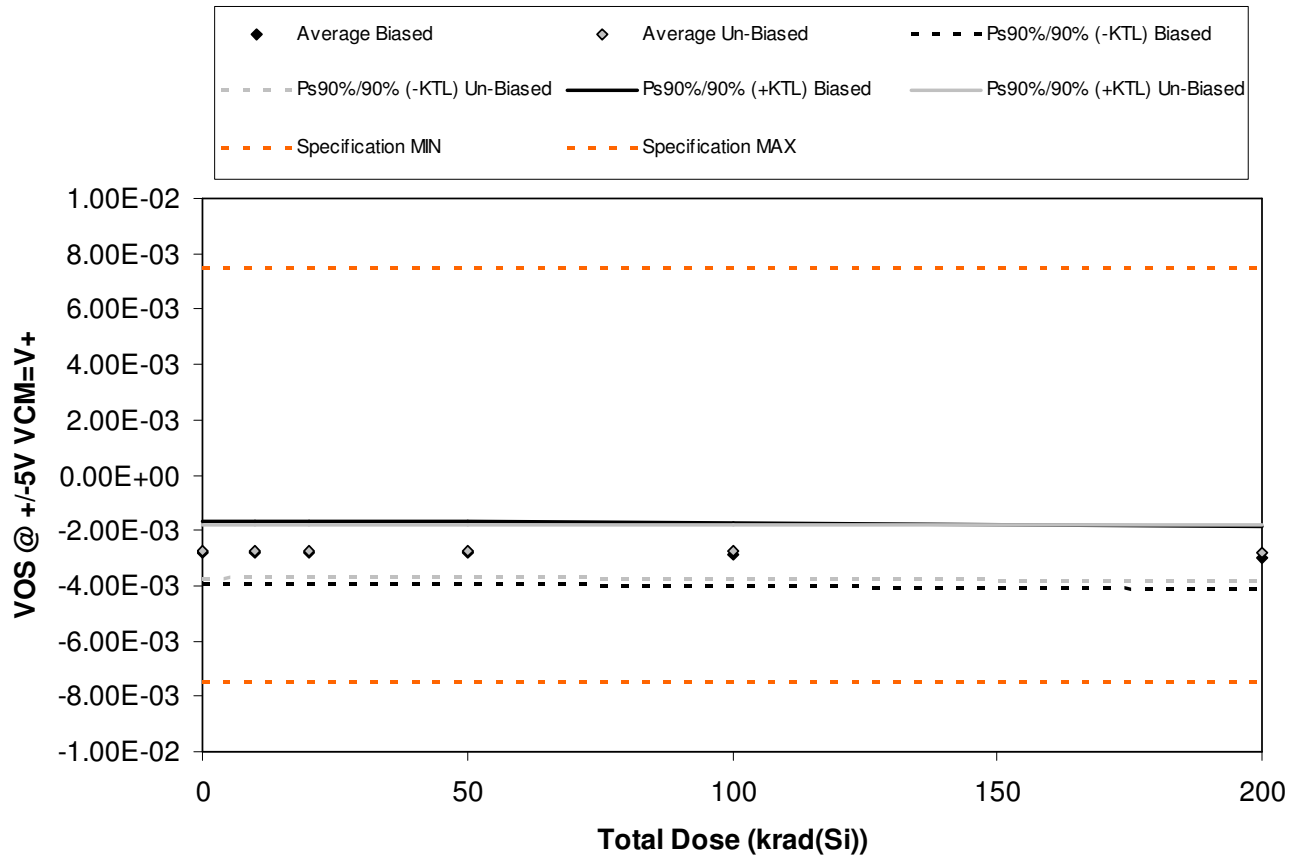


Figure 5.46. Plot of VOS @ +/-5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.46. Raw data for VOS @ +/-5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

VOS @ +/-5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	-2.44E-03	-2.45E-03	-2.45E-03	-2.46E-03	-2.52E-03	-2.60E-03
62	-3.00E-03	-2.97E-03	-2.97E-03	-3.00E-03	-3.07E-03	-3.13E-03
63	-3.19E-03	-3.16E-03	-3.17E-03	-3.17E-03	-3.19E-03	-3.36E-03
64	-2.32E-03	-2.29E-03	-2.31E-03	-2.30E-03	-2.33E-03	-2.50E-03
65	-3.17E-03	-3.14E-03	-3.16E-03	-3.14E-03	-3.22E-03	-3.35E-03
66	-3.21E-03	-3.17E-03	-3.18E-03	-3.18E-03	-3.19E-03	-3.24E-03
67	-2.55E-03	-2.52E-03	-2.53E-03	-2.52E-03	-2.55E-03	-2.58E-03
68	-2.62E-03	-2.60E-03	-2.60E-03	-2.63E-03	-2.62E-03	-2.68E-03
69	-3.07E-03	-3.04E-03	-3.04E-03	-3.04E-03	-3.06E-03	-3.12E-03
70	-2.38E-03	-2.36E-03	-2.36E-03	-2.35E-03	-2.36E-03	-2.39E-03
71	-3.03E-03	-2.99E-03	-2.99E-03	-3.00E-03	-3.00E-03	-3.00E-03
72	-2.48E-03	-2.44E-03	-2.44E-03	-2.44E-03	-2.45E-03	-2.46E-03
Biased Statistics						
Average Biased	-2.82E-03	-2.80E-03	-2.81E-03	-2.81E-03	-2.87E-03	-2.99E-03
Std Dev Biased	4.15E-04	4.04E-04	4.06E-04	4.07E-04	4.12E-04	4.13E-04
Ps90%/90% (+KTL) Biased	-1.68E-03	-1.70E-03	-1.70E-03	-1.70E-03	-1.74E-03	-1.85E-03
Ps90%/90% (-KTL) Biased	-3.96E-03	-3.91E-03	-3.92E-03	-3.93E-03	-3.99E-03	-4.12E-03
Un-Biased Statistics						
Average Un-Biased	-2.77E-03	-2.74E-03	-2.74E-03	-2.75E-03	-2.76E-03	-2.80E-03
Std Dev Un-Biased	3.55E-04	3.49E-04	3.51E-04	3.49E-04	3.56E-04	3.62E-04
Ps90%/90% (+KTL) Un-Biased	-1.79E-03	-1.78E-03	-1.78E-03	-1.79E-03	-1.78E-03	-1.81E-03
Ps90%/90% (-KTL) Un-Biased	-3.74E-03	-3.70E-03	-3.70E-03	-3.70E-03	-3.73E-03	-3.79E-03
Specification MIN	-7.50E-03	-7.50E-03	-7.50E-03	-7.50E-03	-7.50E-03	-7.50E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	7.50E-03	7.50E-03	7.50E-03	7.50E-03	7.50E-03	7.50E-03
Status	PASS	PASS	PASS	PASS	PASS	PASS

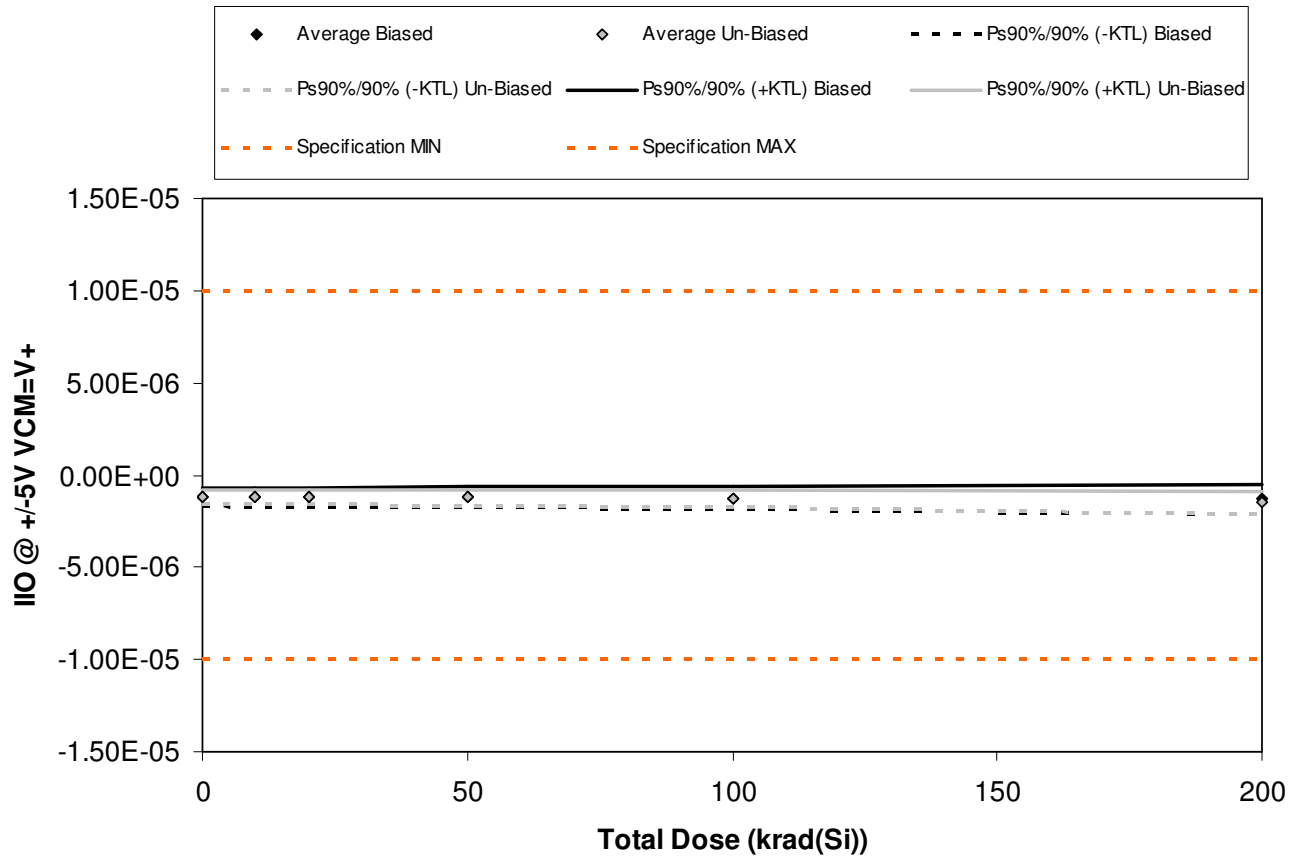


Figure 5.47. Plot of IIO @ +/-5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.47. Raw data for IIO @ +/-5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IIO @ +/-5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	-1.02E-06	-1.02E-06	-1.02E-06	-1.03E-06	-1.04E-06	-1.05E-06
62	-1.32E-06	-1.34E-06	-1.35E-06	-1.39E-06	-1.45E-06	-1.54E-06
63	-1.36E-06	-1.36E-06	-1.37E-06	-1.40E-06	-1.47E-06	-1.62E-06
64	-9.74E-07	-9.71E-07	-9.73E-07	-9.68E-07	-9.72E-07	-9.87E-07
65	-1.31E-06	-1.31E-06	-1.31E-06	-1.32E-06	-1.34E-06	-1.36E-06
66	-1.29E-06	-1.29E-06	-1.30E-06	-1.32E-06	-1.36E-06	-1.44E-06
67	-1.11E-06	-1.12E-06	-1.14E-06	-1.20E-06	-1.30E-06	-1.52E-06
68	-1.10E-06	-1.10E-06	-1.12E-06	-1.15E-06	-1.26E-06	-1.49E-06
69	-1.32E-06	-1.33E-06	-1.35E-06	-1.42E-06	-1.52E-06	-1.77E-06
70	-9.93E-07	-9.94E-07	-1.00E-06	-1.02E-06	-1.06E-06	-1.14E-06
71	-1.30E-06	-1.30E-06	-1.30E-06	-1.30E-06	-1.30E-06	-1.30E-06
72	-1.05E-06	-1.04E-06	-1.04E-06	-1.04E-06	-1.04E-06	-1.05E-06
Biased Statistics						
Average Biased	-1.20E-06	-1.20E-06	-1.21E-06	-1.22E-06	-1.25E-06	-1.31E-06
Std Dev Biased	1.84E-07	1.87E-07	1.91E-07	2.08E-07	2.33E-07	2.86E-07
Ps90%/90% (+KTL) Biased	-6.91E-07	-6.86E-07	-6.82E-07	-6.51E-07	-6.13E-07	-5.27E-07
Ps90%/90% (-KTL) Biased	-1.70E-06	-1.71E-06	-1.73E-06	-1.79E-06	-1.89E-06	-2.10E-06
Un-Biased Statistics						
Average Un-Biased	-1.16E-06	-1.17E-06	-1.18E-06	-1.22E-06	-1.30E-06	-1.47E-06
Std Dev Un-Biased	1.38E-07	1.39E-07	1.41E-07	1.51E-07	1.67E-07	2.24E-07
Ps90%/90% (+KTL) Un-Biased	-7.84E-07	-7.86E-07	-7.94E-07	-8.04E-07	-8.42E-07	-8.60E-07
Ps90%/90% (-KTL) Un-Biased	-1.54E-06	-1.55E-06	-1.57E-06	-1.63E-06	-1.76E-06	-2.09E-06
Specification MIN	-1.00E-05	-1.00E-05	-1.00E-05	-1.00E-05	-1.00E-05	-1.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	1.00E-05	1.00E-05	1.00E-05	1.00E-05	1.00E-05	1.00E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

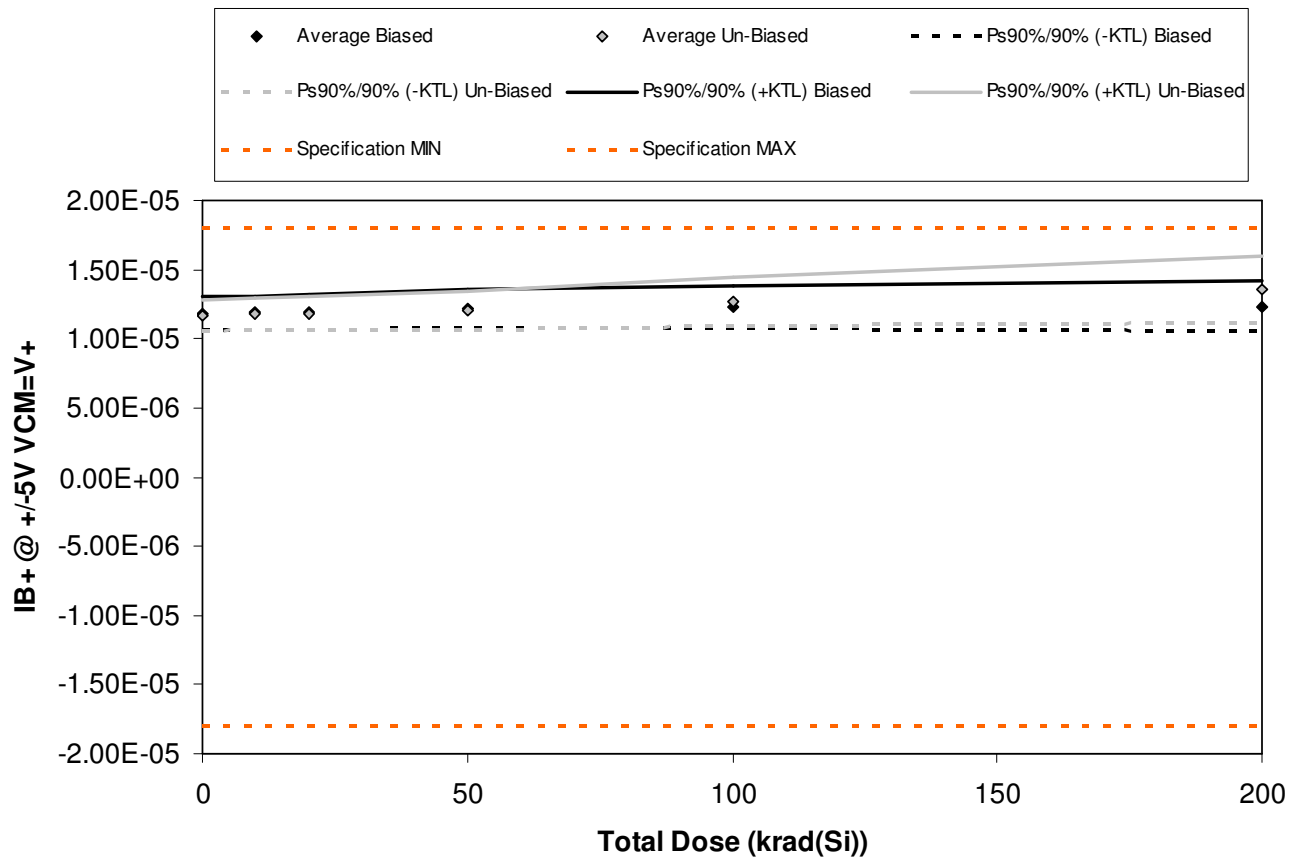


Figure 5.48. Plot of IB+ @ +/-5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.48. Raw data for IB+ @ +/-5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB+ @ +/-5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
Device						
61	1.19E-05	1.20E-05	1.20E-05	1.22E-05	1.22E-05	1.22E-05
62	1.20E-05	1.21E-05	1.22E-05	1.26E-05	1.27E-05	1.32E-05
63	1.18E-05	1.18E-05	1.19E-05	1.21E-05	1.23E-05	1.22E-05
64	1.23E-05	1.24E-05	1.24E-05	1.27E-05	1.28E-05	1.26E-05
65	1.12E-05	1.12E-05	1.12E-05	1.14E-05	1.14E-05	1.14E-05
66	1.10E-05	1.10E-05	1.11E-05	1.12E-05	1.15E-05	1.22E-05
67	1.19E-05	1.20E-05	1.21E-05	1.24E-05	1.31E-05	1.43E-05
68	1.18E-05	1.19E-05	1.20E-05	1.22E-05	1.27E-05	1.38E-05
69	1.19E-05	1.20E-05	1.21E-05	1.25E-05	1.31E-05	1.43E-05
70	1.18E-05	1.19E-05	1.20E-05	1.22E-05	1.27E-05	1.36E-05
71	1.15E-05	1.16E-05	1.16E-05	1.16E-05	1.16E-05	1.16E-05
72	1.21E-05	1.21E-05	1.21E-05	1.22E-05	1.21E-05	1.21E-05
Biased Statistics						
Average Biased	1.18E-05	1.19E-05	1.20E-05	1.22E-05	1.23E-05	1.23E-05
Std Dev Biased	4.28E-07	4.43E-07	4.58E-07	4.95E-07	5.57E-07	6.71E-07
Ps90%/90% (+KTL) Biased	1.30E-05	1.31E-05	1.32E-05	1.35E-05	1.38E-05	1.42E-05
Ps90%/90% (-KTL) Biased	1.07E-05	1.07E-05	1.07E-05	1.08E-05	1.08E-05	1.05E-05
Un-Biased Statistics						
Average Un-Biased	1.17E-05	1.18E-05	1.18E-05	1.21E-05	1.26E-05	1.36E-05
Std Dev Un-Biased	3.95E-07	4.12E-07	4.32E-07	5.04E-07	6.40E-07	8.76E-07
Ps90%/90% (+KTL) Un-Biased	1.28E-05	1.29E-05	1.30E-05	1.35E-05	1.44E-05	1.60E-05
Ps90%/90% (-KTL) Un-Biased	1.06E-05	1.06E-05	1.06E-05	1.07E-05	1.09E-05	1.12E-05
Specification MIN	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS

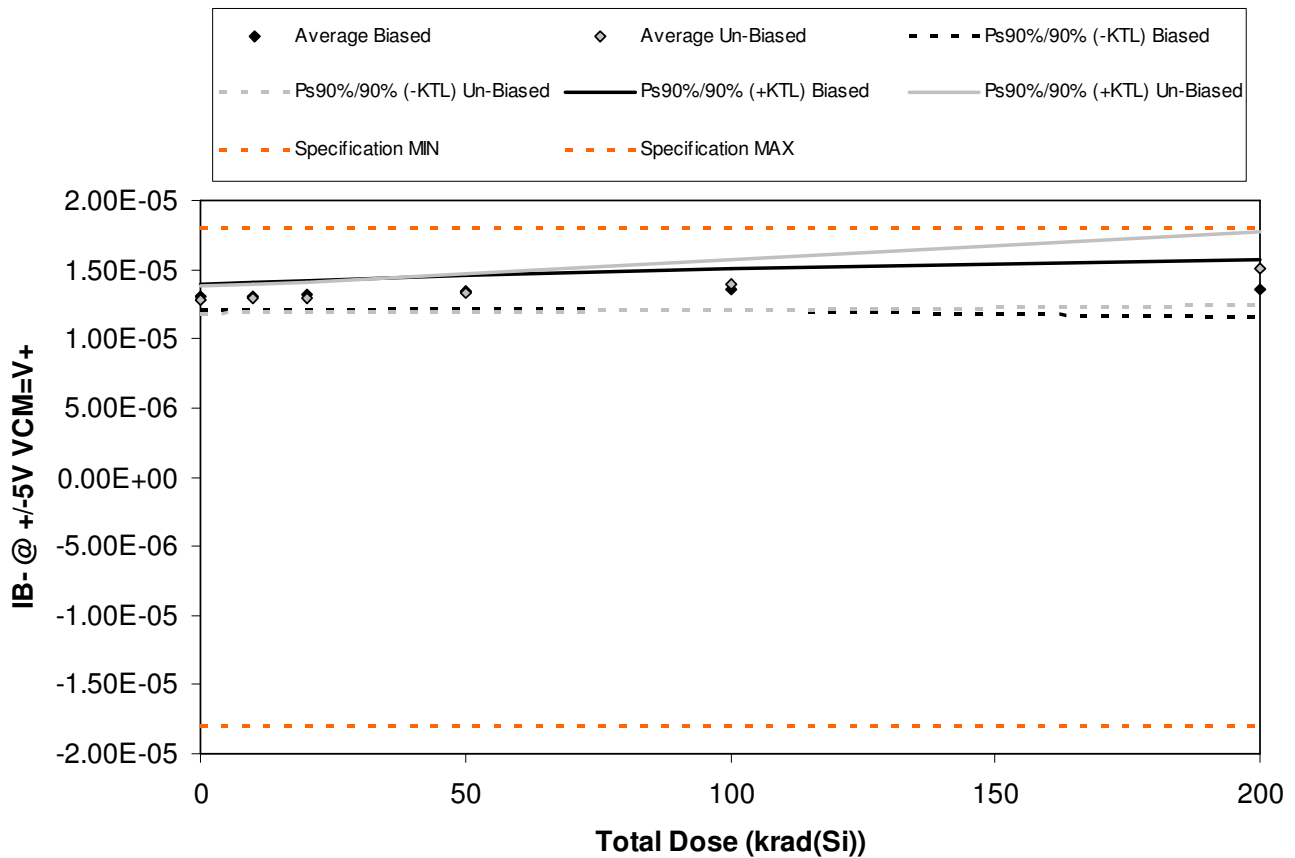


Figure 5.49. Plot of IB- @ +/-5V VCM=V+ versus total dose. The solid diamonds are the average of the measured data points for the samples irradiated under electrical bias and the black lines (solid and/or dashed) are the average of the data points after application of the KTL statistics on the samples irradiated under electrical bias. The red dotted line(s) are the pre- and/or post-irradiation minimum and/or maximum specification value as defined in the datasheet and/or test plan.



Table 5.49. Raw data for IB- @ +/-5V VCM=V+ versus total dose, including the statistical analysis, specification and the status of the testing (pass/fail).

IB- @ +/-5V VCM=V+	Total Dose (krad(Si))					
	0	10	20	50	100	200
61	1.30E-05	1.30E-05	1.30E-05	1.32E-05	1.32E-05	1.32E-05
62	1.33E-05	1.35E-05	1.36E-05	1.39E-05	1.41E-05	1.47E-05
63	1.31E-05	1.32E-05	1.32E-05	1.34E-05	1.37E-05	1.38E-05
64	1.33E-05	1.33E-05	1.34E-05	1.36E-05	1.38E-05	1.36E-05
65	1.24E-05	1.25E-05	1.25E-05	1.27E-05	1.27E-05	1.27E-05
66	1.22E-05	1.23E-05	1.23E-05	1.25E-05	1.29E-05	1.36E-05
67	1.30E-05	1.31E-05	1.32E-05	1.36E-05	1.44E-05	1.57E-05
68	1.29E-05	1.30E-05	1.31E-05	1.33E-05	1.40E-05	1.52E-05
69	1.32E-05	1.33E-05	1.34E-05	1.38E-05	1.46E-05	1.60E-05
70	1.28E-05	1.29E-05	1.29E-05	1.32E-05	1.37E-05	1.47E-05
71	1.28E-05	1.28E-05	1.28E-05	1.28E-05	1.28E-05	1.28E-05
72	1.32E-05	1.32E-05	1.32E-05	1.32E-05	1.32E-05	1.32E-05
Biased Statistics						
Average Biased	1.30E-05	1.31E-05	1.31E-05	1.34E-05	1.35E-05	1.36E-05
Std Dev Biased	3.57E-07	3.80E-07	3.99E-07	4.54E-07	5.53E-07	7.45E-07
Ps90%/90% (+KTL) Biased	1.40E-05	1.41E-05	1.42E-05	1.46E-05	1.50E-05	1.56E-05
Ps90%/90% (-KTL) Biased	1.20E-05	1.20E-05	1.20E-05	1.21E-05	1.20E-05	1.16E-05
Un-Biased Statistics						
Average Un-Biased	1.28E-05	1.29E-05	1.30E-05	1.33E-05	1.39E-05	1.51E-05
Std Dev Un-Biased	3.50E-07	3.73E-07	4.04E-07	5.03E-07	6.64E-07	9.75E-07
Ps90%/90% (+KTL) Un-Biased	1.38E-05	1.39E-05	1.41E-05	1.47E-05	1.57E-05	1.77E-05
Ps90%/90% (-KTL) Un-Biased	1.19E-05	1.19E-05	1.19E-05	1.19E-05	1.21E-05	1.24E-05
Specification MIN	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05	-1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS
Specification MAX	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05	1.80E-05
Status	PASS	PASS	PASS	PASS	PASS	PASS



6.0. Summary / Conclusions

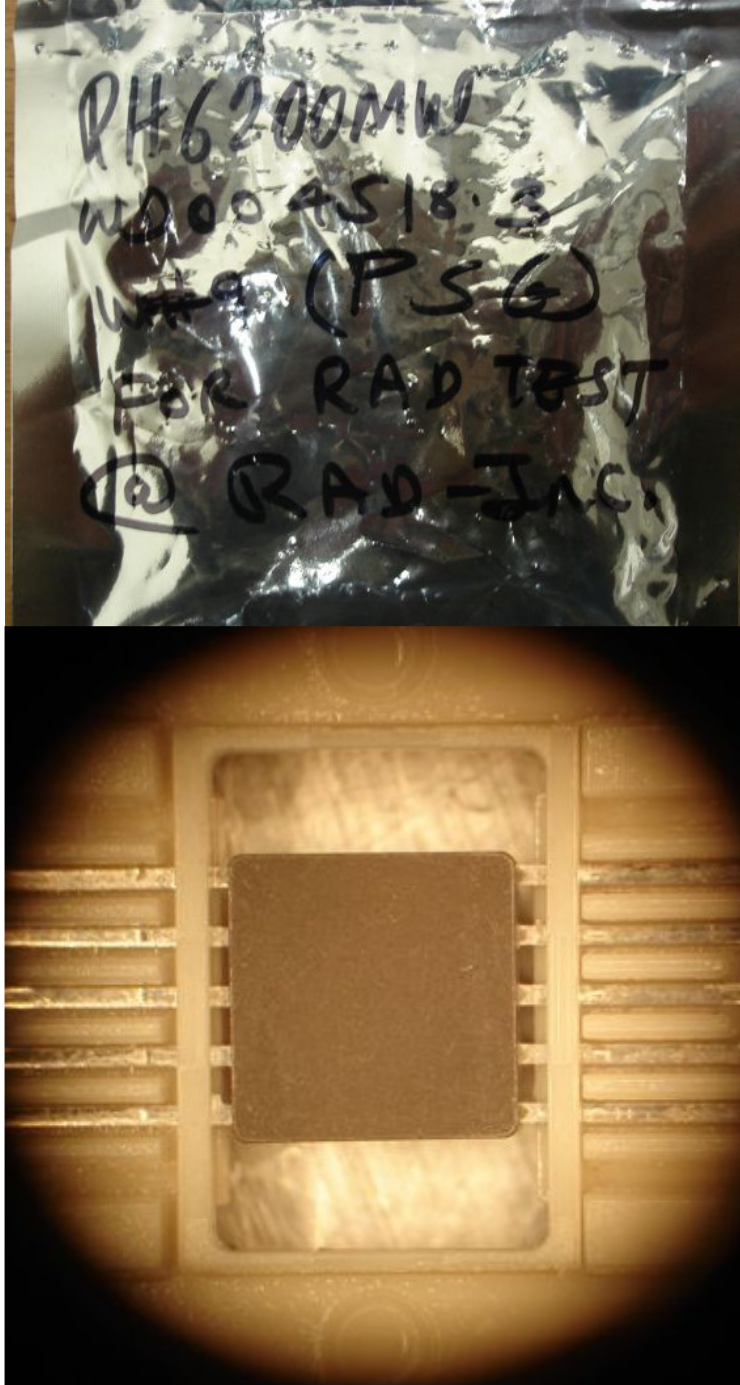
The total ionizing dose testing described in this final report was performed using the facilities at Radiation Assured Devices' Longmire Laboratories in Colorado Springs, CO. The high dose rate total ionizing dose (TID) source is a JLSA 81-24 irradiator modified to provide a panoramic exposure. The Co-60 rods are held in the base of the irradiator heavily shielded by lead, during the radiation exposures the rod is raised by an electronic timer/controller and the exposure is performed in air. The dose rate for this irradiator in this configuration ranges from $<1\text{rad}(\text{Si})/\text{s}$ to a maximum of approximately $120\text{rad}(\text{Si})/\text{s}$, determined by the distance from the source.

The parametric data was obtained as "read and record" and all the raw data plus an attributes summary are contained in this report as well as in a separate Excel file. The attributes data contains the average, standard deviation and the average with the KTL values applied. The KTL value used in this work is 2.742 per MIL-HDBK-814 using one sided tolerance limits of 90/90 and a 5-piece sample size. The 90/90 KTL values were selected to match the statistical levels specified in the MIL-PRF-38535 sampling plan for the qualification of a radiation hardness assured (RHA) component. Note that the following criteria must be met for a device to pass the total ionizing dose test: following the radiation exposure each of the 5 pieces irradiated under electrical bias shall pass the specification value. The units irradiated without electrical bias and the KTL statistics are included in this report for reference only. If any of the 5 pieces irradiated under electrical bias exceed the datasheet specifications, then the lot could be logged as a failure.

Based on this criterion the RH6200 Low Noise Rail-to-Rail Input and Output Op Amp (from the lot date code identified on the first page of this test report) PASSED the total ionizing dose test to the maximum tested dose level of $200\text{krad}(\text{Si})$ with all parameters remaining within their datasheet specifications.



Appendix A: Photograph of a Sample Unit-Under-Test. Note that units are unmarked.





Appendix B: Radiation Bias Connections

TID Radiation Biased Conditions:

Pin	Function	Connection / Bias
1	SHDN	NC
2	NC	NC
3	-IN	To Pin 7 via 10k Ω
4	+IN	To 0V via 10k Ω Resistor
5	V-	To -5V using 0.1 μ F Decoupling
6	NC	NC
7	OUT	To Pin 3 via 10k Ω
8	V+	To +5V using 0.1 μ F Decoupling
9	NC	NC
10	NC	NC

TID Radiation Unbiased Conditions: All pins are connected to GND.

Pin	Function	Connection / Bias
1	SHDN	GND
2	NC	GND
3	-IN	GND
4	+IN	GND
5	V-	GND
6	NC	GND
7	OUT	GND
8	V+	GND
9	NC	GND
10	NC	GND

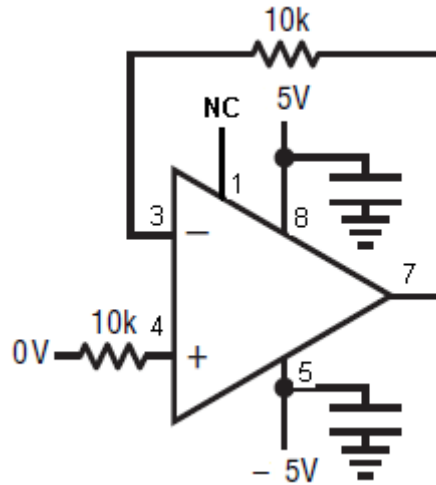


Figure B.1. Irradiation bias drawing for the units to be irradiated under electrical bias.

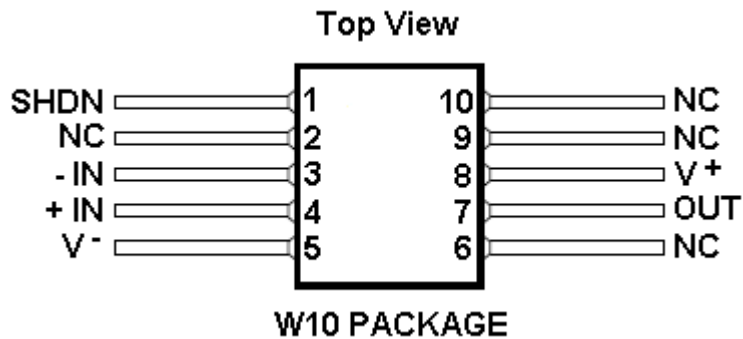


Fig B.2. W package drawing (for reference only).



Appendix C: Electrical Test Parameters and Conditions

The expected ranges of values as well as the measurement conditions are taken from Linear Technology LT6200 Datasheet. All electrical tests for this device are performed on one of Radiation Assured Device's LTS2020 Test Systems. The LTS2020 Test System is a programmable parametric tester that provides parameter measurements for a variety of digital, analog and mixed signal products including voltage regulators, voltage comparators, D to A and A to D converters. The LTS2020 Test System achieves accuracy and sensitivity through the use of software self-calibration and an internal relay matrix with separate family boards and custom personality adapter boards. The tester uses this relay matrix to connect the required test circuits, select the appropriate voltage / current sources and establish the needed measurement loops for all the tests performed. The measured parameters and test conditions are shown in Table C.1.

A listing of the measurement precision/resolution for each parameter is shown in Table C.2. The precision/resolution values were obtained from test data or from the DAC resolution of the LTS-2020 for the particular test shown, whichever is greater. To generate the precision/resolution shown in Table C.2, one of the units-under-test was tested repetitively (a total of 10-times with re-insertion between tests) to obtain the average test value and standard deviation. Using this test data MIL-HDBK-814 90/90 KTL statistics were applied to the measured standard deviation to generate the final measurement range. This value encompasses the precision/resolution of all aspects of the test system, including the LTS2020 mainframe, family board, socket assembly and DUT board as well as insertion error. In some cases, the measurement resolution is limited by the internal DACs, which results in a measured standard deviation of zero. In these instances the precision/resolution will be reported back as the LSB of the DAC.

Note that the testing and statistics used in this document are based on an “analysis of variables” technique, which relies on small sample sizes to qualify much larger lot sizes (see MIL-HDBK-814, p. 91 for a discussion of statistical treatments). Not all measured parameters are well suited to this approach due to inherent large variations. If necessary, larger samples sizes could be used to qualify these parameters using an “attributes” approach.



Table C.1. Measured parameters, test conditions, and acceptance criteria for the RH6200 Low Noise Rail-to-Rail Input and Output Op Amp.

Parameter	Test Conditions
+ SUPPLY CURRENT @ +/-2.5V	+/-2.5V
- SUPPLY CURRENT @ +/-2.5V	+/-2.5V
+ S/D SUPPLY CURRENT @ +/-2.5V	+/-2.5V, V _{SHDN} =0.3V
S/D PIN CURRENT @ +/-2.5V	+/-2.5V, V _{SHDN} =0.3V
CMRR @ +/-2.5V VCM=+/-1V	+/-2.5V VCM=+/-1V
CMRR @ +/-2.5V VCM=+/-2.5V	+/-2.5V VCM=+/-2.5V
AVOL @ +/-2.5V RL=1K VO=+/-2V	+/-2.5V RL=1K VO=+/-2V
AVOL @ +/-2.5V RL=100 VO=+/-1.5V	+/-2.5V RL=100 VO=+/-1.5V
VOH @ +/-2.5V IL=0	+/-2.5V IL=0
VOH @ +/-2.5V IL=5MA	+/-2.5V IL=5MA
VOH @ +/-2.5V IL=20MA	+/-2.5V IL=20MA
VOL @ +/-2.5V IL=0	+/-2.5V IL=0
VOL @ +/-2.5V IL=5MA	+/-2.5V IL=5MA
VOL @ +/-2.5V IL=20MA	+/-2.5V IL=20MA
ISC SOURCE @ +/-2.5V	+/-2.5V
ISC SINK @ +/-2.5V	+/-2.5V
+ SUPPLY CURRENT @ +/-5V	+/-5V
- SUPPLY CURRENT @ +/-5V	+/-5V
+ S/D SUPPLY CURRENT @ +/-5V	+/-5V, V _{SHDN} =0.3V
S/D PIN CURRENT @ +/-5V	+/-5V, V _{SHDN} =0.3V
CMRR @ +/-5V VCM=+/-2V	+/-5V VCM=+/-2V
CMRR @ +/-5V VCM=+/-5V	+/-5V VCM=+/-5V
PSRR @ +/-1.25V TO +/-5V	+/-1.25V TO +/-5V



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AVOL @ +/-5V RL=1K VO=+/-4.5V	+/-5V RL=1K VO=+/-4.5V
AVOL @ +/-5V RL=100 VO=+/-2V	+/-5V RL=100 VO=+/-2V
VOH @ +/-5V IL=0	+/-5V IL=0
VOH @ +/-5V IL=5MA	+/-5V IL=5MA
VOH @ +/-5V IL=20MA	+/-5V IL=20MA
VOL @ +/-5V IL=0	+/-5V IL=0
VOL @ +/-5V IL=5MA	+/-5V IL=5MA
VOL @ +/-5V IL=20MA	+/-5V IL=20MA
ISC SOURCE @ +/-5V	+/-5V
ISC SINK @ +/-5V	+/-5V
VOS @ +/-2.5V VCM=V-	+/-2.5V VCM=V-
IIO @ +/-2.5V VCM=V-	+/-2.5V VCM=V-
IB+ @ +/-2.5V VCM=V-	+/-2.5V VCM=V-
IB- @ +/-2.5V VCM=V-	+/-2.5V VCM=V-
VOS @ +/-2.5V VCM=V+	+/-2.5V VCM=V+
IIO @ +/-2.5V VCM=V+	+/-2.5V VCM=V+
IB+ @ +/-2.5V VCM=V+	+/-2.5V VCM=V+
IB- @ +/-2.5V VCM=V+	+/-2.5V VCM=V+
VOS @ +/-5V VCM=V-	+/-5V VCM=V-
IIO @ +/-5V VCM=V-	+/-5V VCM=V-
IB+ @ +/-5V VCM=V-	+/-5V VCM=V-
IB- @ +/-5V VCM=V-	+/-5V VCM=V-
VOS @ +/-5V VCM=V+	+/-5V VCM=V+
IIO @ +/-5V VCM=V+	+/-5V VCM=V+
IB+ @ +/-5V VCM=V+	+/-5V VCM=V+
IB- @ +/-5V VCM=V+	+/-5V VCM=V+

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Table C.2. Measured parameters, pre-irradiation specifications and measurement precision for the RH6200 Low Noise Rail-to-Rail Input and Output Op Amp.

Parameter	Pre-Irradiation Specification		Measurement Precision/Resolution
	MIN	MAX	
+ SUPPLY CURRENT @ +/-2.5V		2.00E-02	±6.23E-04
- SUPPLY CURRENT @ +/-2.5V	-2.00E-02		±6.15E-04
+ S/D SUPPLY CURRENT @ +/-2.5V		1.80E-03	±1.07E-05
S/D PIN CURRENT @ +/-2.5V	-2.80E-04		±1.28E-06
CMRR @ +/-2.5V VCM=+/-1V	8.50E+01		±7.28E-01
CMRR @ +/-2.5V VCM=+/-2.5V	6.50E+01		±2.98E-01
AVOL @ +/-2.5V RL=1K VO=+/-2V	7.00E+01		±2.46E+00
AVOL @ +/-2.5V RL=100 VO=+/-1.5V	1.10E+01		±2.58E-01
VOH @ +/-2.5V IL=0	-1.10E-01		±2.20E-03
VOH @ +/-2.5V IL=5MA	-1.90E-01		±2.85E-03
VOH @ +/-2.5V IL=20MA	-4.00E-01		±3.94E-03
VOL @ +/-2.5V IL=0		5.00E-02	±3.75E-04
VOL @ +/-2.5V IL=5MA		1.00E-01	±7.37E-04
VOL @ +/-2.5V IL=20MA		2.90E-01	±1.87E-03
ISC SOURCE @ +/-2.5V		-6.00E-02	±6.98E-04
ISC SINK @ +/-2.5V	6.00E-02		±4.69E-04
+ SUPPLY CURRENT @ +/-5V		2.90E-02	±4.61E-04
- SUPPLY CURRENT @ +/-5V	-2.90E-02		±4.60E-04
+ S/D SUPPLY CURRENT @ +/-5V		2.10E-03	±4.47E-06
S/D PIN CURRENT @ +/-5V	-2.95E-04		±8.15E-07
CMRR @ +/-5V VCM=+/-2V	7.50E+01		±4.79E-01
CMRR @ +/-5V VCM=+/-5V	6.50E+01		±4.53E-02
PSRR @ +/-1.25V TO +/-5V	6.00E+01		±1.39E-01



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AVOL @ +/-5V RL=1K VO=+/-4.5V	4.60E+01		±1.38E+01
AVOL @ +/-5V RL=100 VO=+/-2V	7.50E+00		±1.70E-01
VOH @ +/-5V IL=0	-1.50E-01		±1.60E-03
VOH @ +/-5V IL=5MA	-2.30E-01		±1.95E-03
VOH @ +/-5V IL=20MA	-4.80E-01		±2.77E-03
VOL @ +/-5V IL=0		7.00E-02	±4.61E-04
VOL @ +/-5V IL=5MA		1.20E-01	±5.25E-04
VOL @ +/-5V IL=20MA		3.10E-01	±1.17E-03
ISC SOURCE @ +/-5V		-6.00E-02	±5.05E-04
ISC SINK @ +/-5V	6.00E-02		±2.61E-04
VOS @ +/-2.5V VCM=V-	-2.00E-03	2.00E-03	±8.77E-06
IIO @ +/-2.5V VCM=V-	-5.00E-06	5.00E-06	±1.52E-09
IB+ @ +/-2.5V VCM=V-	-5.00E-05	5.00E-05	±5.75E-08
IB- @ +/-2.5V VCM=V-	-5.00E-05	5.00E-05	±5.96E-08
VOS @ +/-2.5V VCM=V+	-2.00E-03	2.00E-03	±9.88E-06
IIO @ +/-2.5V VCM=V+	-4.00E-06	4.00E-06	±2.99E-09
IB+ @ +/-2.5V VCM=V+	-1.80E-05	1.80E-05	±2.79E-08
IB- @ +/-2.5V VCM=V+	-1.80E-05	1.80E-05	±3.24E-08
VOS @ +/-5V VCM=V-	-7.50E-03	7.50E-03	±4.05E-05
IIO @ +/-5V VCM=V-	-1.50E-05	1.50E-05	±1.78E-08
IB+ @ +/-5V VCM=V-	-5.00E-05	5.00E-05	±4.34E-08
IB- @ +/-5V VCM=V-	-5.00E-05	5.00E-05	±5.93E-08
VOS @ +/-5V VCM=V+	-7.50E-03	7.50E-03	±4.24E-05
IIO @ +/-5V VCM=V+	-1.00E-05	1.00E-05	±5.19E-09
IB+ @ +/-5V VCM=V+	-1.80E-05	1.80E-05	±2.25E-08
IB- @ +/-5V VCM=V+	-1.80E-05	1.80E-05	±2.02E-08

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Appendix D: List of Figures Used in the Results Section (Section 5)

16. + SUPPLY CURRENT @ +/-2.5V
17. - SUPPLY CURRENT @ +/-2.5V
18. + S/D SUPPLY CURRENT @ +/-2.5V
19. S/D PIN CURRENT @ +/-2.5V
20. CMRR @ +/-2.5V VCM=+/-1V
21. CMRR @ +/-2.5V VCM=+/-2.5V
22. AVOL @ +/-2.5V RL=1K VO=+/-2V
23. AVOL @ +/-2.5V RL=100 VO=+/-1.5V
24. VOH @ +/-2.5V IL=0
25. VOH @ +/-2.5V IL=5MA
26. VOH @ +/-2.5V IL=20MA
27. VOL @ +/-2.5V IL=0
28. VOL @ +/-2.5V IL=5MA
29. VOL @ +/-2.5V IL=20MA
30. ISC SOURCE @ +/-2.5V
31. ISC SINK @ +/-2.5V
32. + SUPPLY CURRENT @ +/-5V
33. - SUPPLY CURRENT @ +/-5V
34. + S/D SUPPLY CURRENT @ +/-5V
35. S/D PIN CURRENT @ +/-5V
36. CMRR @ +/-5V VCM=+/-2V
37. CMRR @ +/-5V VCM=+/-5V
38. PSRR @ +/-1.25V TO +/-5V
39. AVOL @ +/-5V RL=1K VO=+/-4.5V
40. AVOL @ +/-5V RL=100 VO=+/-2V
41. VOH @ +/-5V IL=0
42. VOH @ +/-5V IL=5MA
43. VOH @ +/-5V IL=20MA
44. VOL @ +/-5V IL=0
45. VOL @ +/-5V IL=5MA
46. VOL @ +/-5V IL=20MA
47. ISC SOURCE @ +/-5V
48. ISC SINK @ +/-5V
49. VOS @ +/-2.5V VCM=V-
50. IIO @ +/-2.5V VCM=V-
51. IB+ @ +/-2.5V VCM=V-
52. IB- @ +/-2.5V VCM=V-
53. VOS @ +/-2.5V VCM=V+
54. IIO @ +/-2.5V VCM=V+
55. IB+ @ +/-2.5V VCM=V+



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- 56. IB- @ +/-2.5V VCM=V+
- 57. VOS @ +/-5V VCM=V-
- 58. IIO @ +/-5V VCM=V-
- 59. IB+ @ +/-5V VCM=V-
- 60. IB- @ +/-5V VCM=V-
- 61. VOS @ +/-5V VCM=V+
- 62. IIO @ +/-5V VCM=V+
- 63. IB+ @ +/-5V VCM=V+
- 64. IB- @ +/-5V VCM=V+